

Power Semiconductors for Power Electronics Applications

Munaf Rahimo, Corporate Executive Engineer

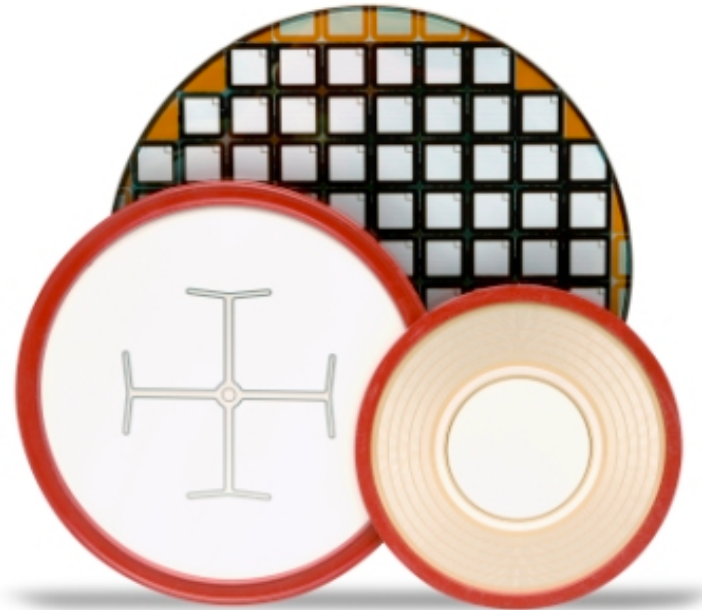
Grid Systems R&D, Power Systems

ABB Switzerland Ltd, Semiconductors

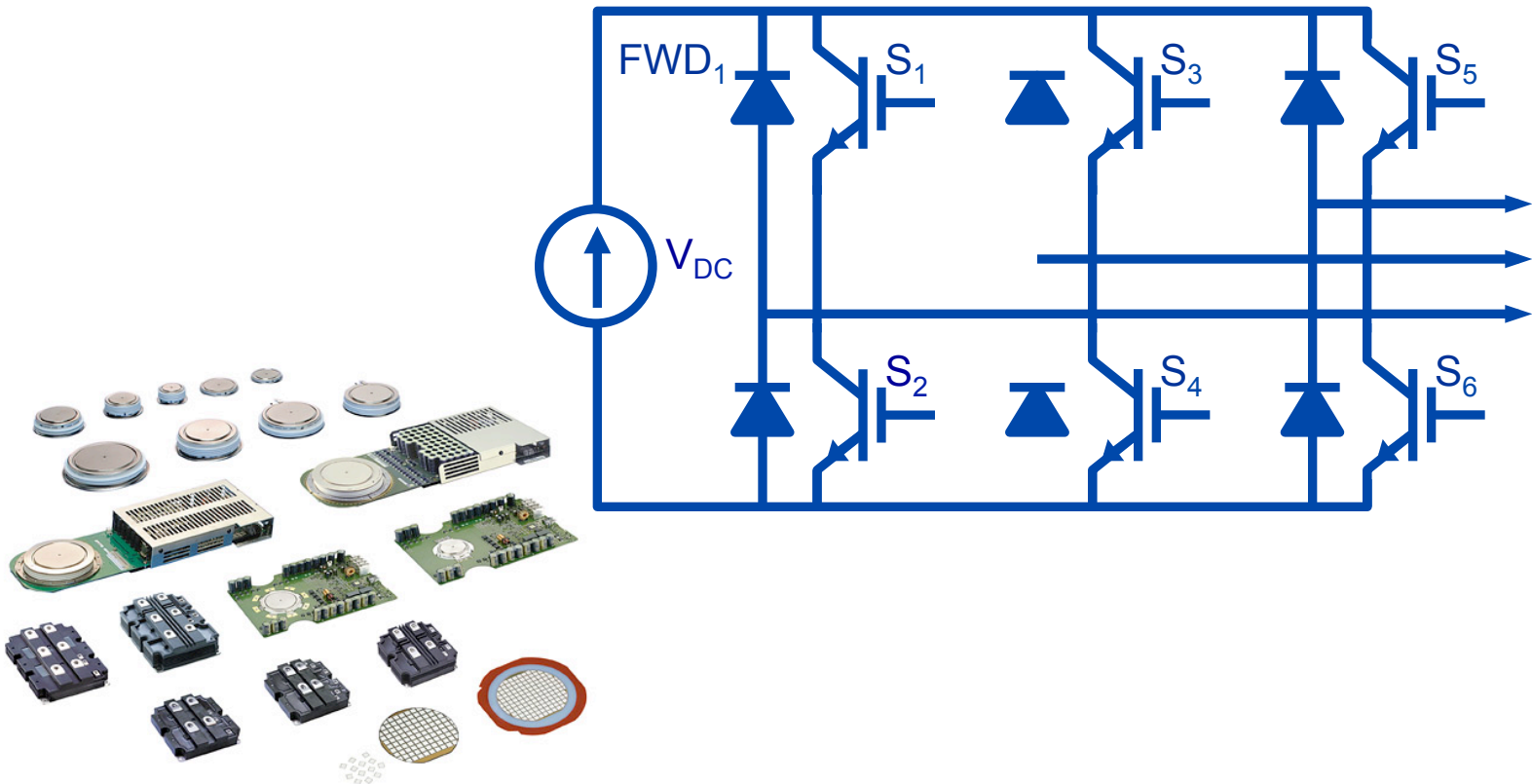
*CAS-PSI Special course
Power Converters, Baden
Switzerland, 8th May 2014*

Contents

- **Power Electronics and Power Semiconductors**
- **Understanding the Basics**
- **Technologies and Performance**
- **Packaging Concepts**
- **Technology Drivers and Trends**
- **Wide Band gap Technologies**
- **Conclusions**



Power Electronics and Power Semiconductors



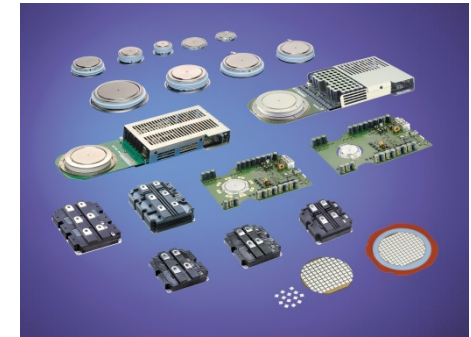
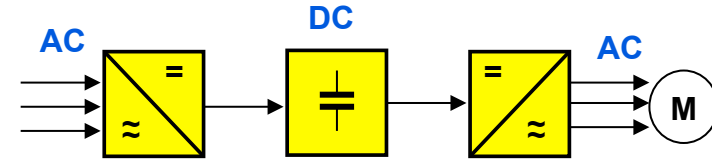
Power Electronics Applications are

.. an established technology that bridges the power industry with its needs for flexible and fast controllers

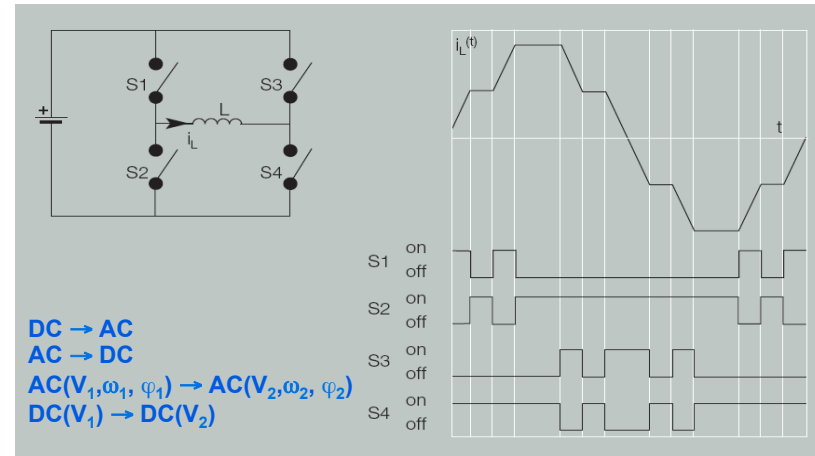
Transportation



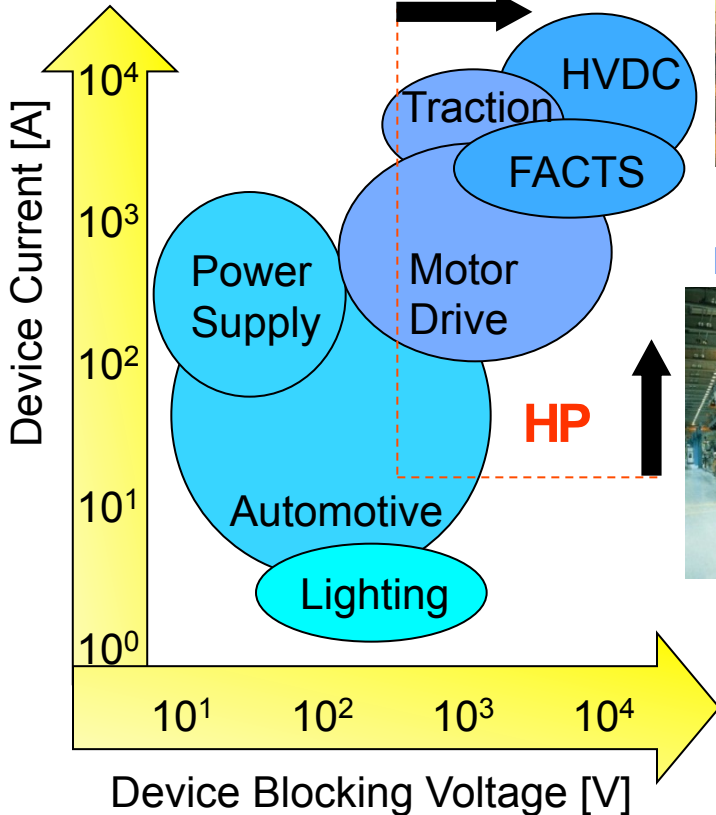
Grid Systems



Industrial Drives

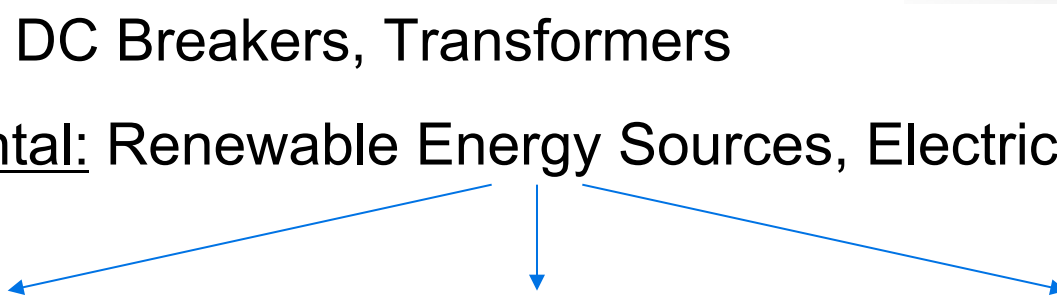


PE conversion employ controllable solid-state switches referred to as **Power Semiconductors**



Power Electronics Application Trends

- Traditional: More Compact and Powerful Systems
- Modern: Better Quality and Reliability
- Efficient: Lower Losses
- Custom: Niche and Special Applications
- Solid State: DC Breakers, Transformers
- Environmental: Renewable Energy Sources, Electric/Hybrid Cars



Economic

Environmental

Social

ABB

The Semiconductor Revolution

TRANSISTORS—first family of electronics

1948—Early "point contact" transistor.

1950—Early "junction" transistor.

"Grown junction", used to amplify received speech in special telephones.

"Alloy junction"; used in first completely transistorized carrier telephone system.

Phototransistor; provides electric "eye" for direct distance dialing.

Experimental "diffused base" transistor.

"Grown junction," tetraode type; high frequency amplifier.

"Alloy junction"; low frequency power amplifier.

"Diffused base"; high frequency broadband amplifier.

In 1948 Bell scientists announced their invention of the transistor—a tiny device able to amplify signals a hundred thousand times using a small fraction of the power of an electron tube.

From this original "point contact" transistor has grown a distinguished family of immense usefulness to electronics. Some of its leading members are shown here, in approximate actual size, with their scientific type names.

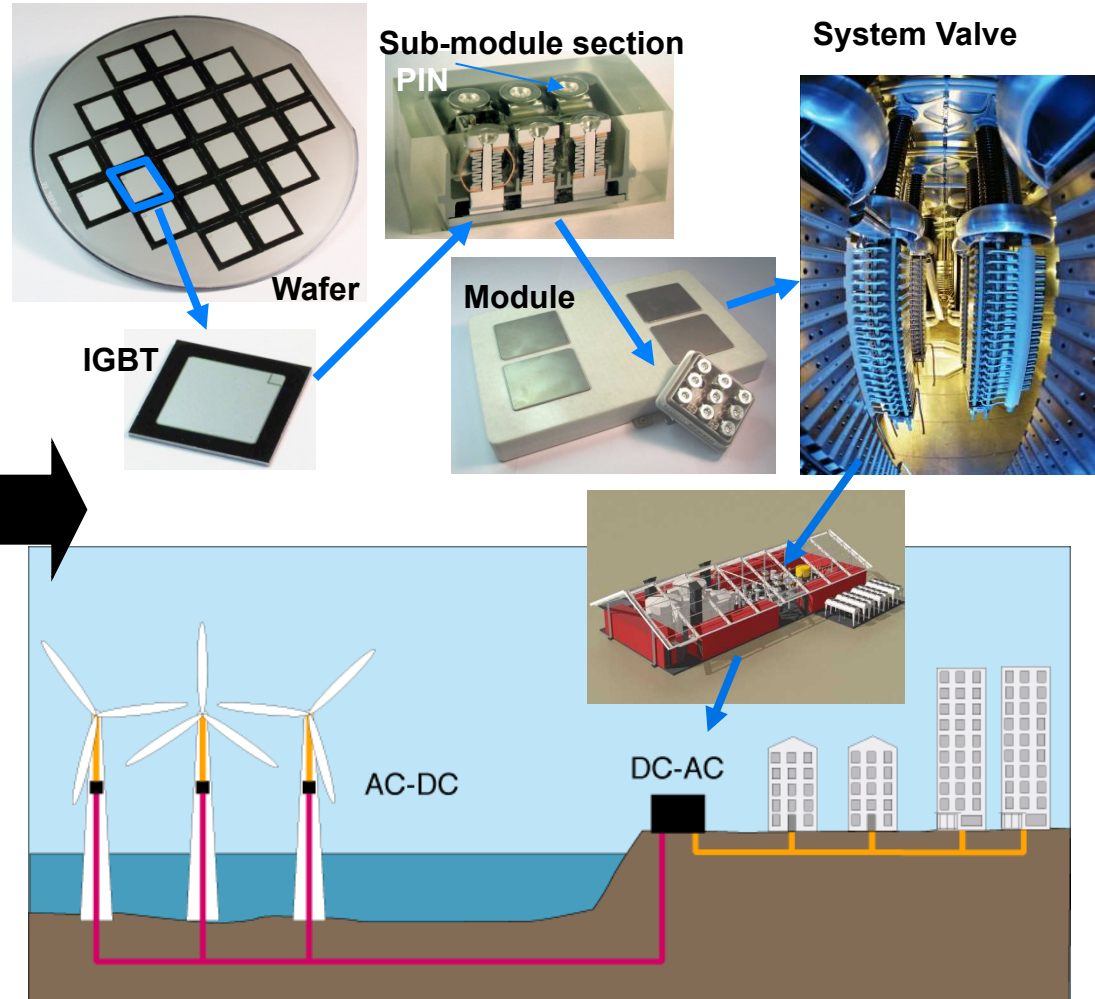
For telephony the transistor has opened the way for notable advances in instruments, transmission and switching. Elsewhere it has opened the way to advances in hearing aids, television, computers, portable radios and numerous military applications.

Bell's transistor family is typical of the Bell Laboratories research that helps keep your telephone service the world's best—and at the same time contributes importantly to other fields of technology.

BELL TELEPHONE LABORATORIES

WORLD CENTER OF COMMUNICATIONS RESEARCH AND DEVELOPMENT

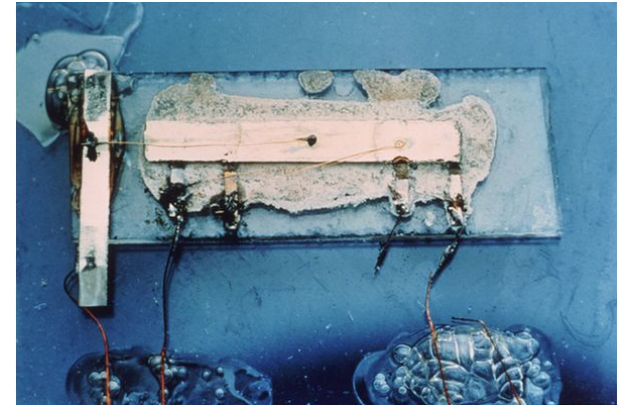
1947: Bell's Transistor



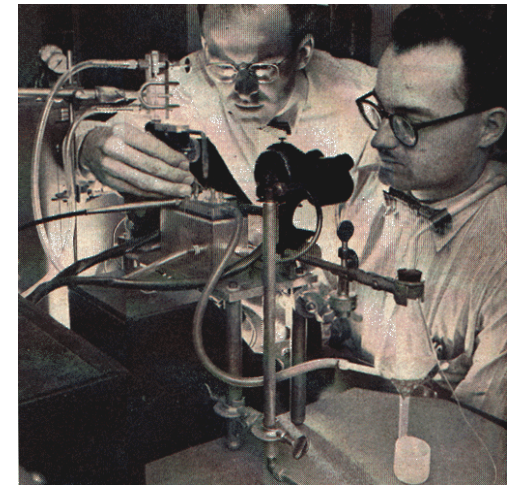
Today: GW IGBT based HVDC systems

Semiconductors, Towards Higher Speeds & Power

- It took close to two decades after the invention of the **solid-state bipolar transistor (1947)** for semiconductors to hit mainstream applications
- The beginnings of **power semiconductors** came at a similar time with the **integrated circuit** in the fifties
- **Both lead to the modern era of advanced DATA and POWER processing**
- While the main target for ICs is increasing the **speed** of data processing, for power devices it was the controlled **power** handling capability
- Since the **1970s**, power semiconductors have benefited from advanced Silicon material and technologies/ processes developed for the much larger and well funded IC applications and markets



Kilby's first IC in 1958

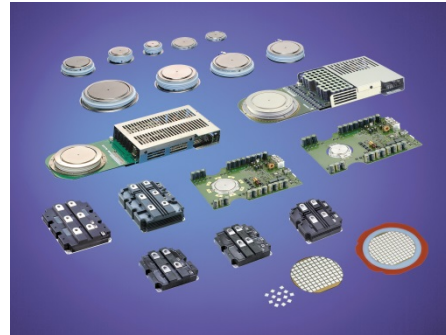


Robert N. Hall (left) at GE demonstrated the first 200V/35A Ge power diode in 1952

The Global Semiconductor Market and Producers



HITACHI
Inspire the Next



Never stop thinking



IR International Rectifier



FAIRCHILD
SEMICONDUCTOR



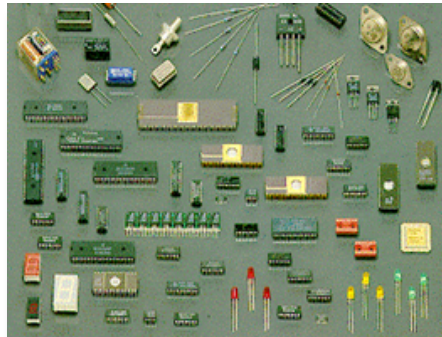
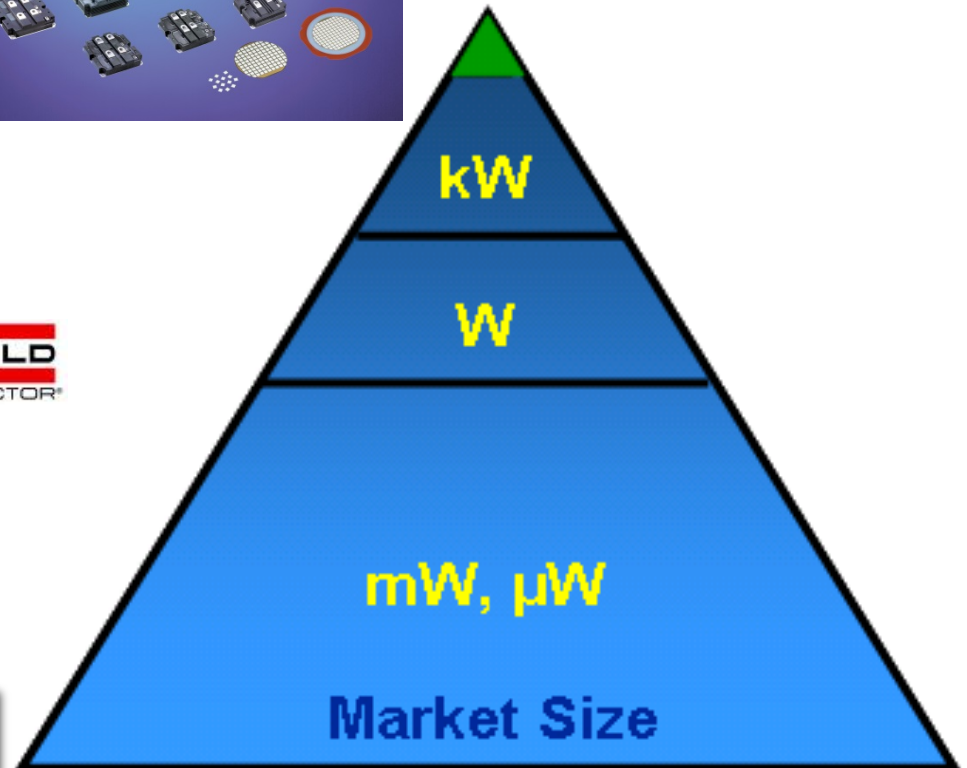
TEXAS INSTRUMENTS



NXP
founded by Philips

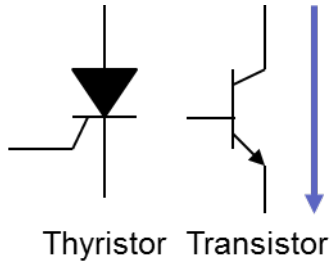


AMD
The future is fusion

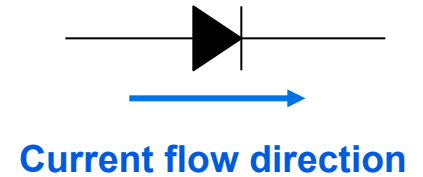


Power Semiconductors; the Principle

Power Semiconductor

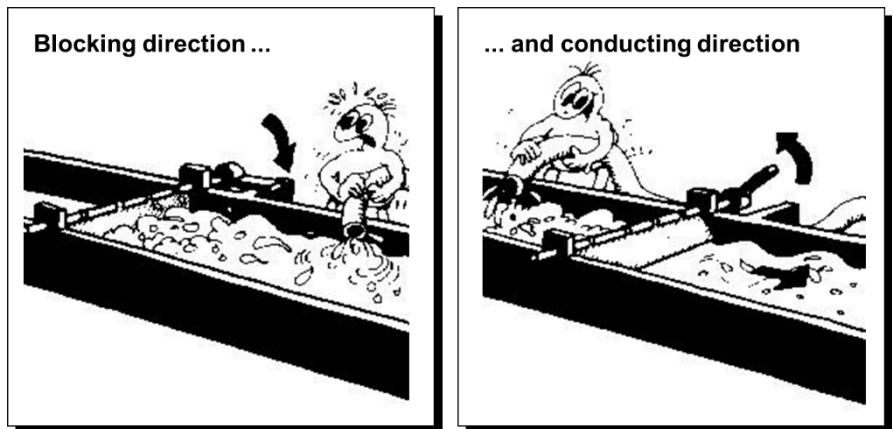
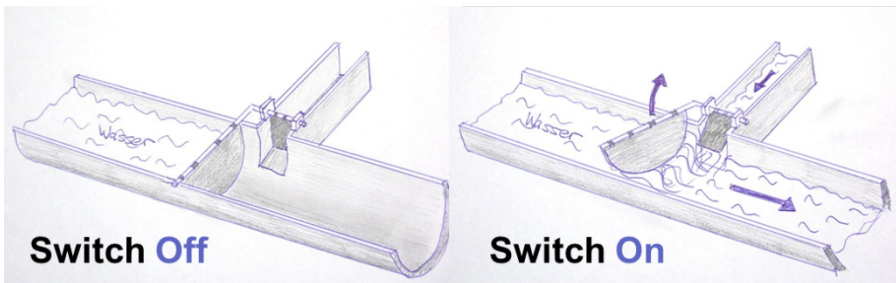


Current flow direction

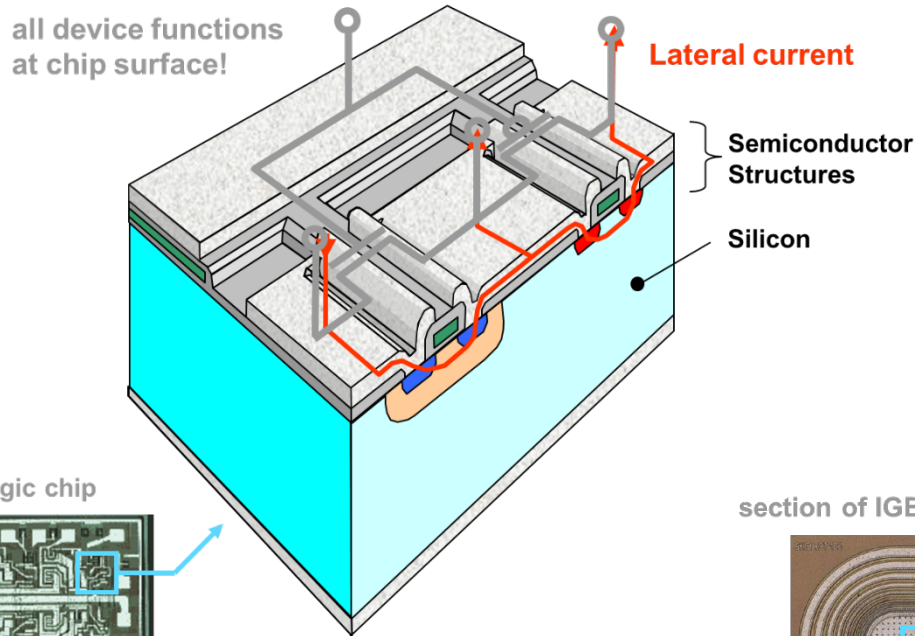


Switches
(MOSFET, IGBT, Thyristor)

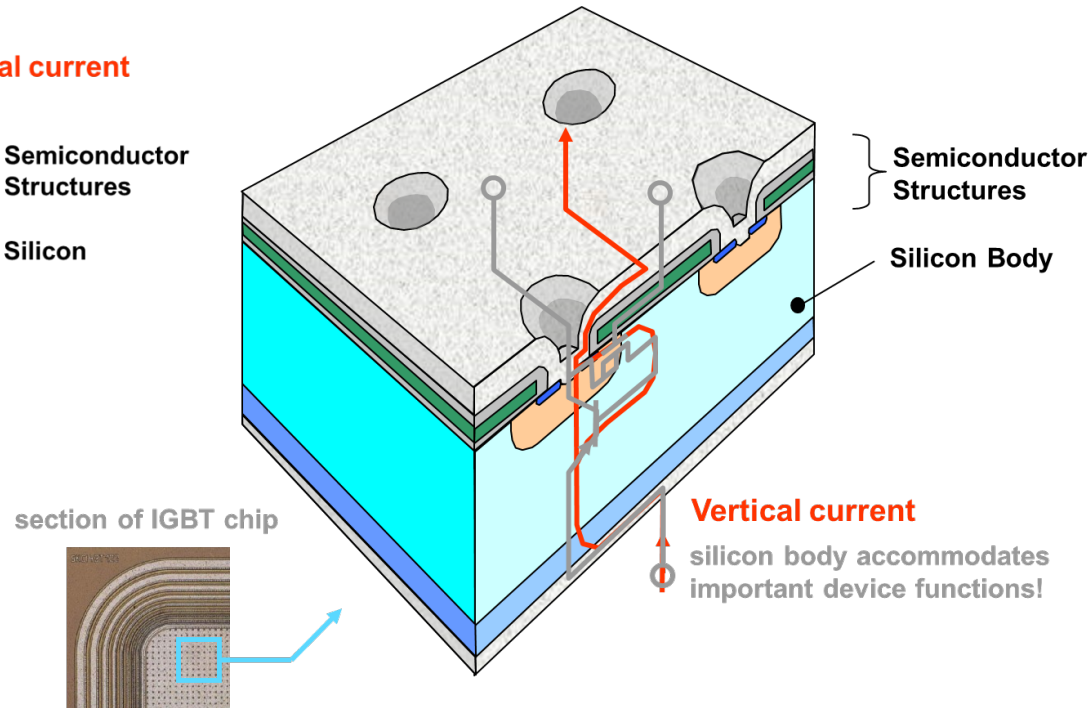
Rectifiers
(Diodes)



Power Semiconductor Device Main Functions



Logic Device



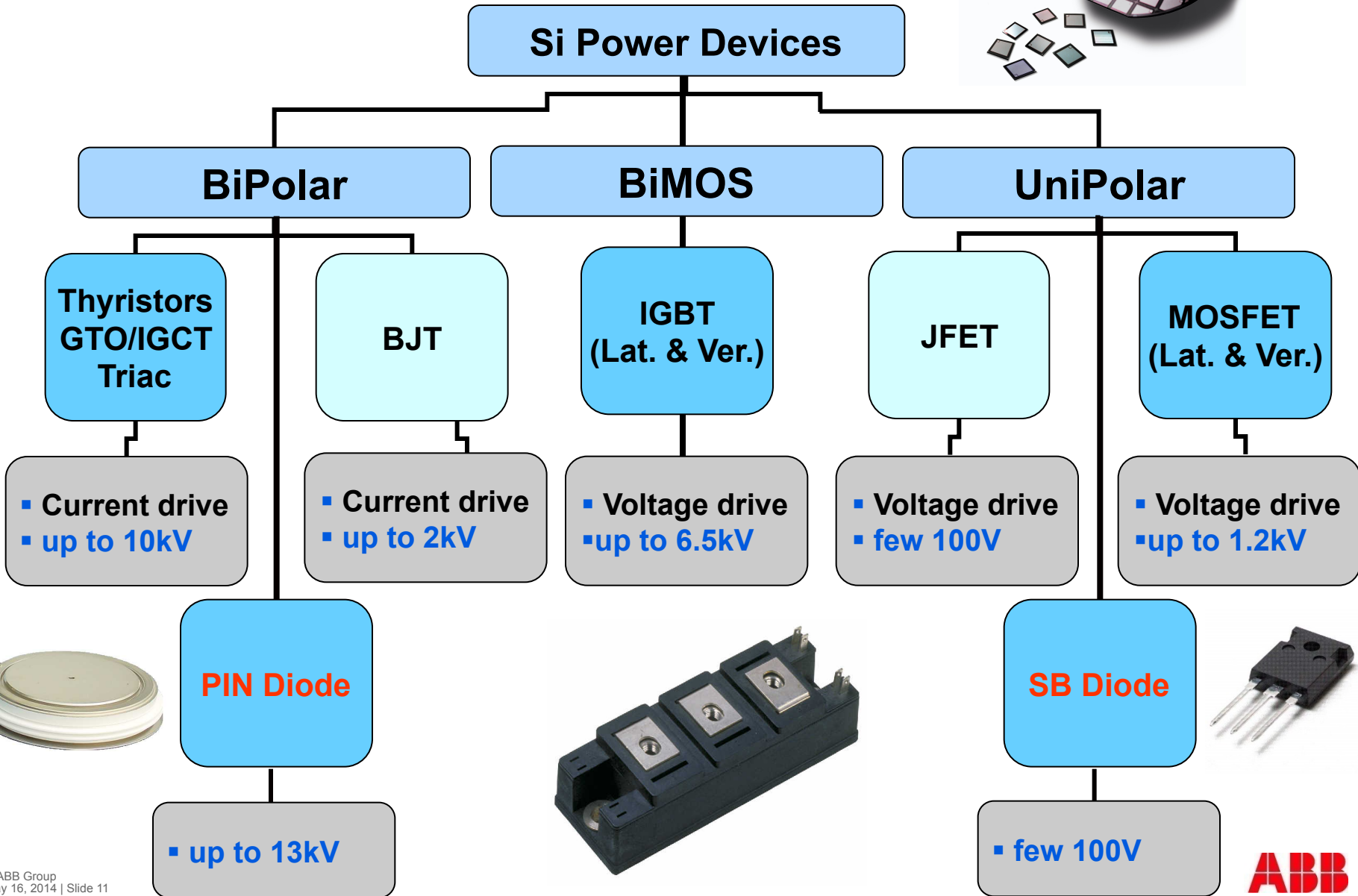
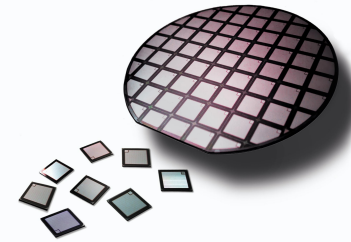
High Power Device

- **Main Functions of the power device:**

- **Support the off-voltage (Thousands of Volts)**
- **Conduct currents when switch is on (Hundreds of Amps per cm²)**

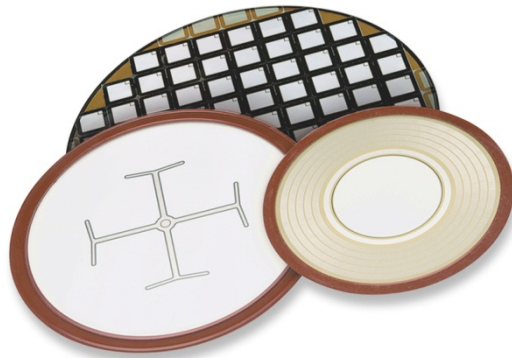


Silicon Switch/Diode Classification

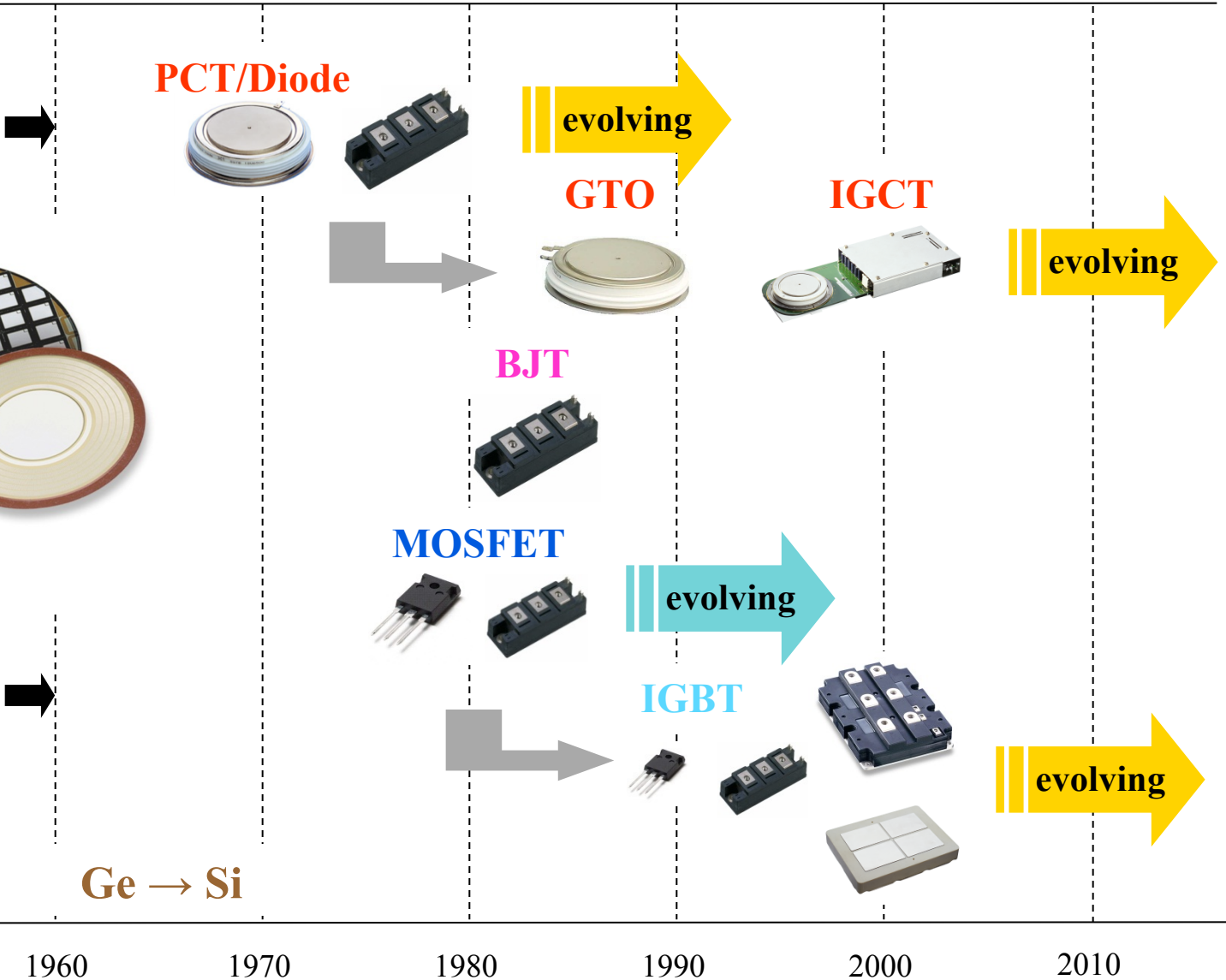


Evolution of Silicon Based Power Devices

Bipolar Technologies



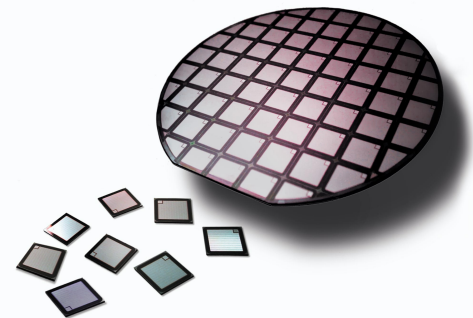
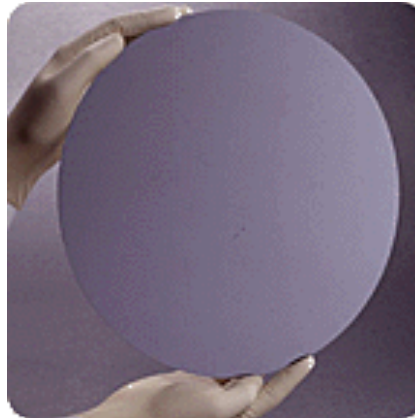
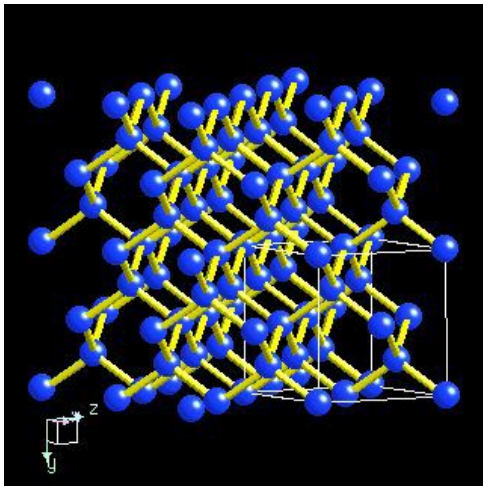
MOS Technologies



Silicon, the main power semiconductor material



- Silicon is the second most common chemical element in the crust of the earth (27.7% vs. 46.6% of Oxygen)
- Stones and sand are mostly consisting of Silicon and Oxygen (SiO_2)
- For Semiconductors, we need an almost perfect **Silicon crystal**
- Silicon crystals for semiconductor applications are probably the best organized structures on earth
- Before the fabrication of chips, the semiconductor wafer is doped with minute amounts of foreign atoms (p “B, Al” or n “P, As” type doping)



Power Semiconductor Processes



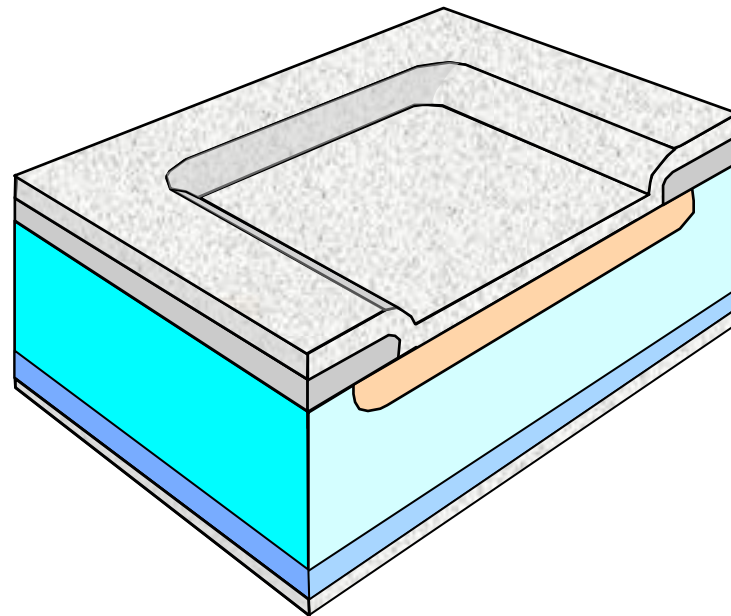
- It takes basically the same technologies to manufacture power semiconductors like modern logic devices like microprocessors
- But the challenges are different in terms of **Device Physics** and **Application**

Device	Critical Dimension	Min. doping concentration	Max. Process Temperature*
Logic Devices	0.1 - 0.2 μm	10^{15} cm^{-3}	1050 - 1100°C (minutes)
MOSFET, IGBT	1 - 2 μm	$10^{13} - 10^{14} \text{ cm}^{-3}$	1250°C (hours)
Thyristor, GTO, IGCT	10 -20 μm	$< 10^{13} \text{ cm}^{-3}$	1280-1300°C(days) melts at 1360°C

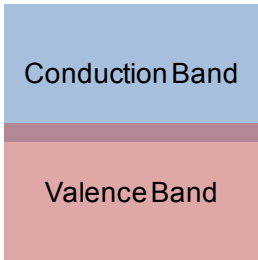
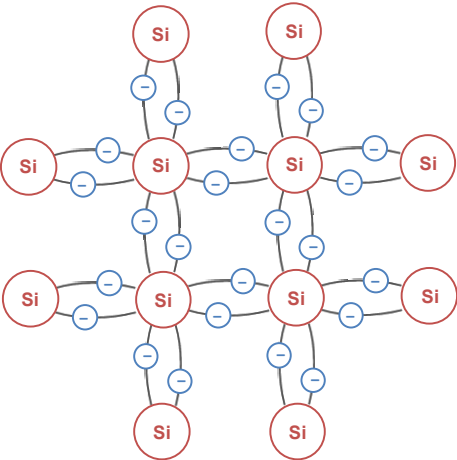
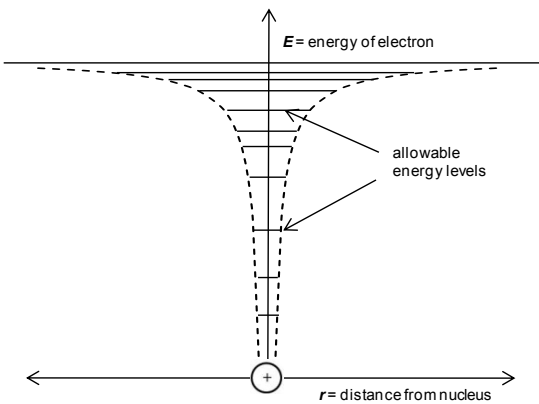
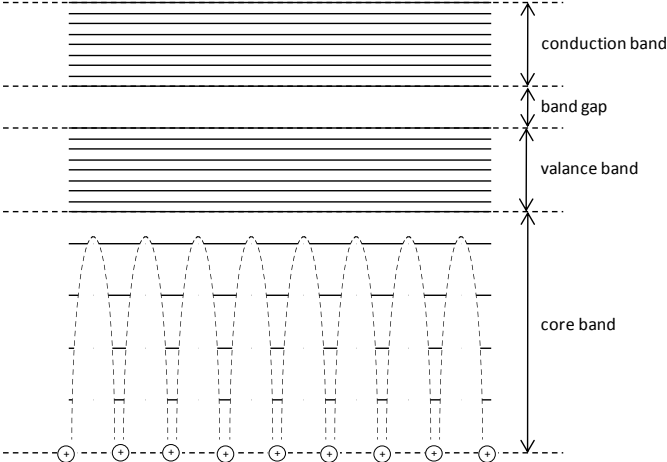
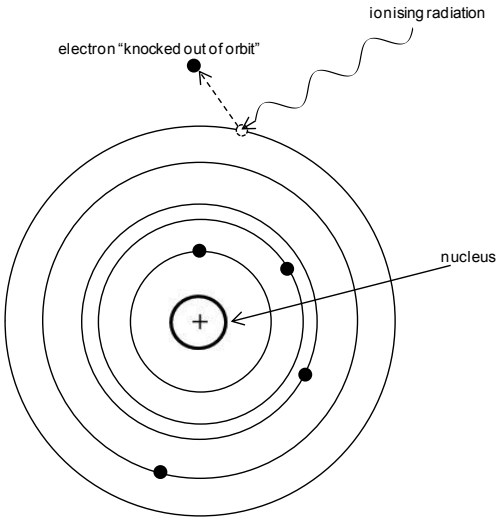
- Doping and thickness of the silicon must be tightly controlled (both in % range)
- Because silicon is a resistor, device thickness must be kept at absolute minimum
- Virtually no defects or contamination with foreign atoms are permitted

Power Semiconductors

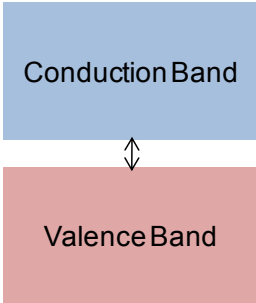
Understanding The Basics



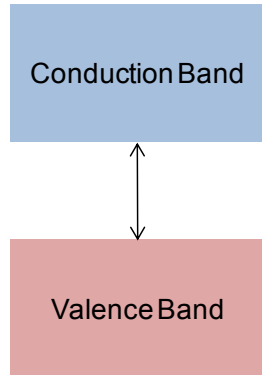
... without diving into semiconductor physics ...



Metal
($\rho \approx 10^{-6} \Omega\text{-cm}$)



Semiconductor
($\rho \approx 10^{2...6} \Omega\text{-cm}$)



Insulator
($\rho \approx 10^{16} \Omega\text{-cm}$)

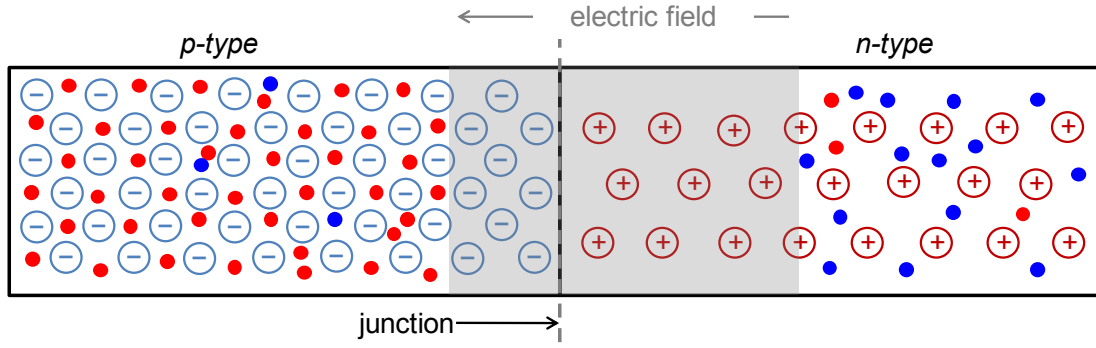
↕ Band Gap

Power Semiconductors, S. Linder, EPFL Press
ISBN 2-940222-09-6



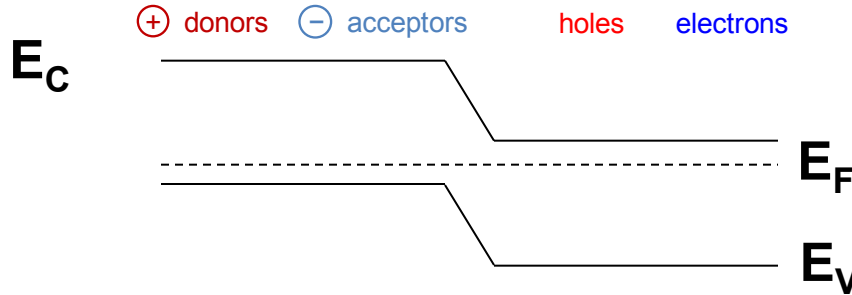
The Basic Building Block; The PN Junction

Anode



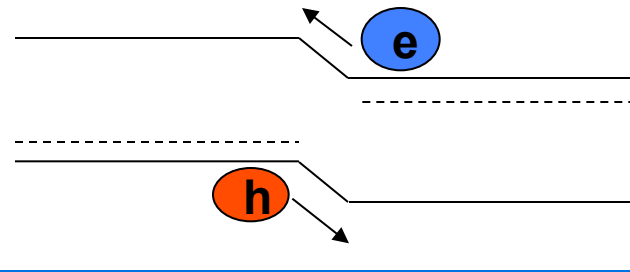
Cathode

No Bias



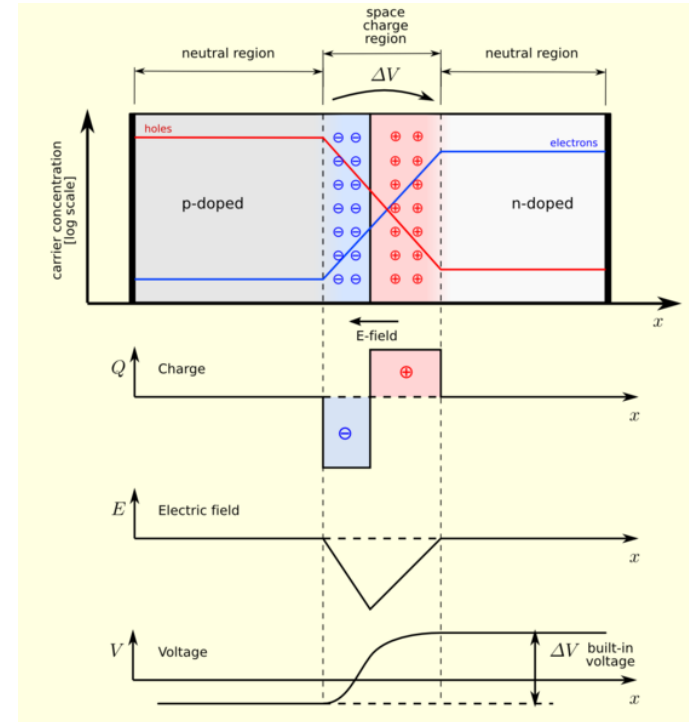
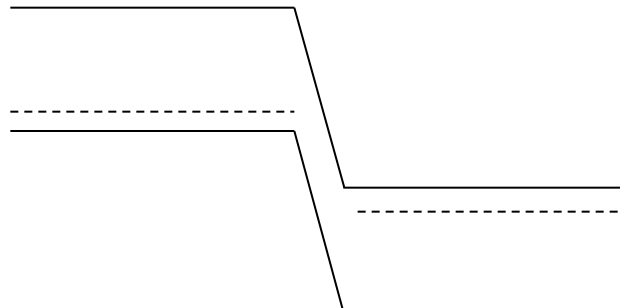
Forward Bias
P(+)
N(-)

Space-charge region abolished and a current starts to flow if the external voltage exceeds the "built-in" voltage ~ 0.7 V



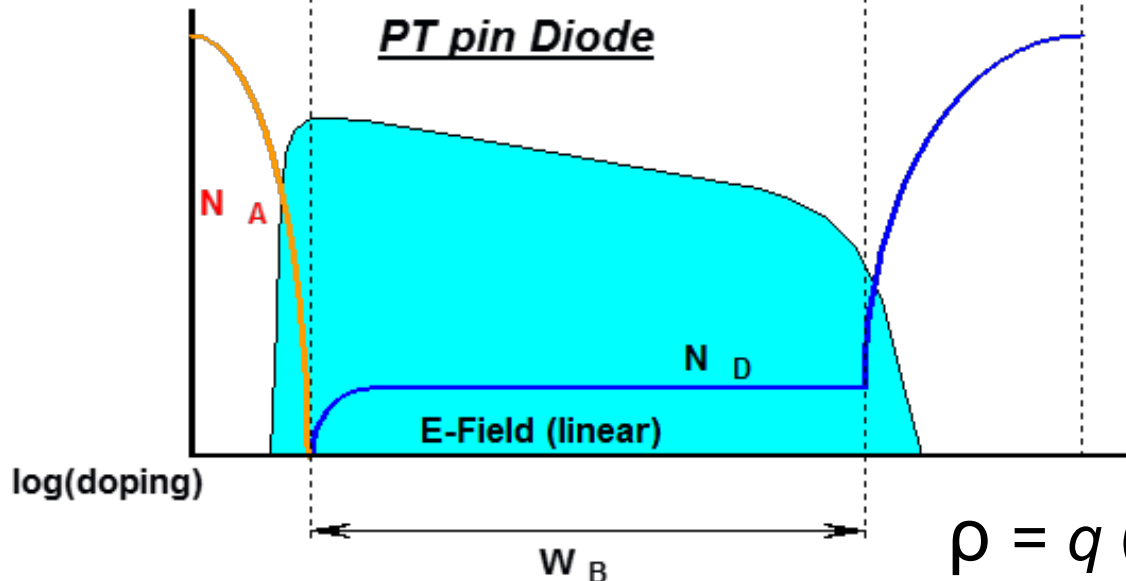
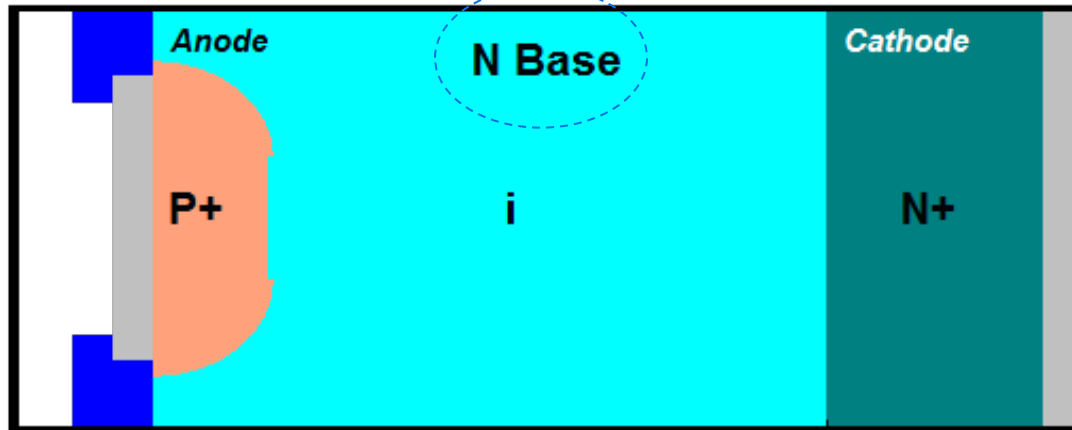
Reverse Bias
P(-)
N(+)

Space-charge region expands and avalanche break-down voltage is reached at critical electric field for Si (2×10^5 V/cm)



The PIN Bipolar Power Diode

The low doped drift (base) region is the main differentiator for power devices (normally n-type)



Poisson's Equation for Electric Field

$$\frac{d\mathcal{E}}{dx} = \frac{\rho}{\epsilon_s}$$

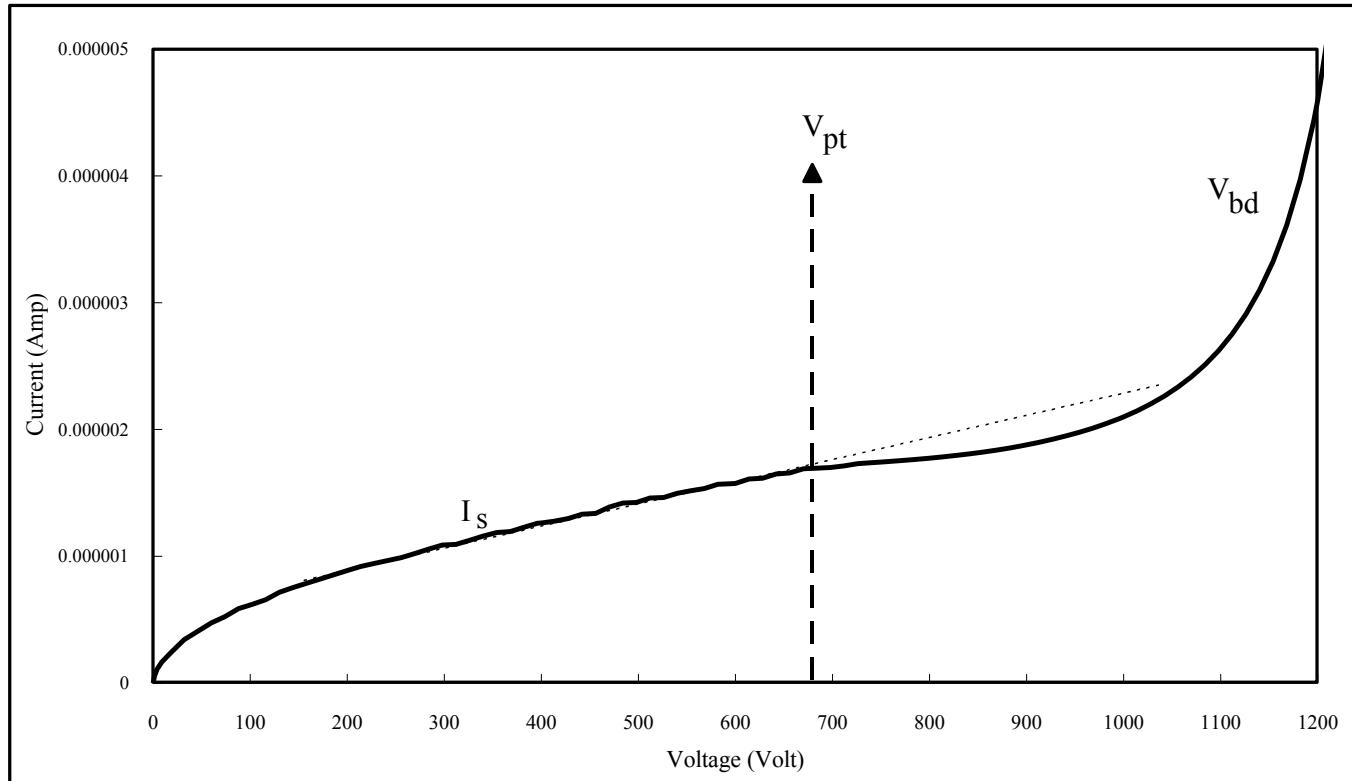
Charge Density
Permittivity

$$\rho = q(p - n + N_D - N_A)$$

Power Diode Structure and Doping Profile



The Power Diode in Reverse Blocking Mode

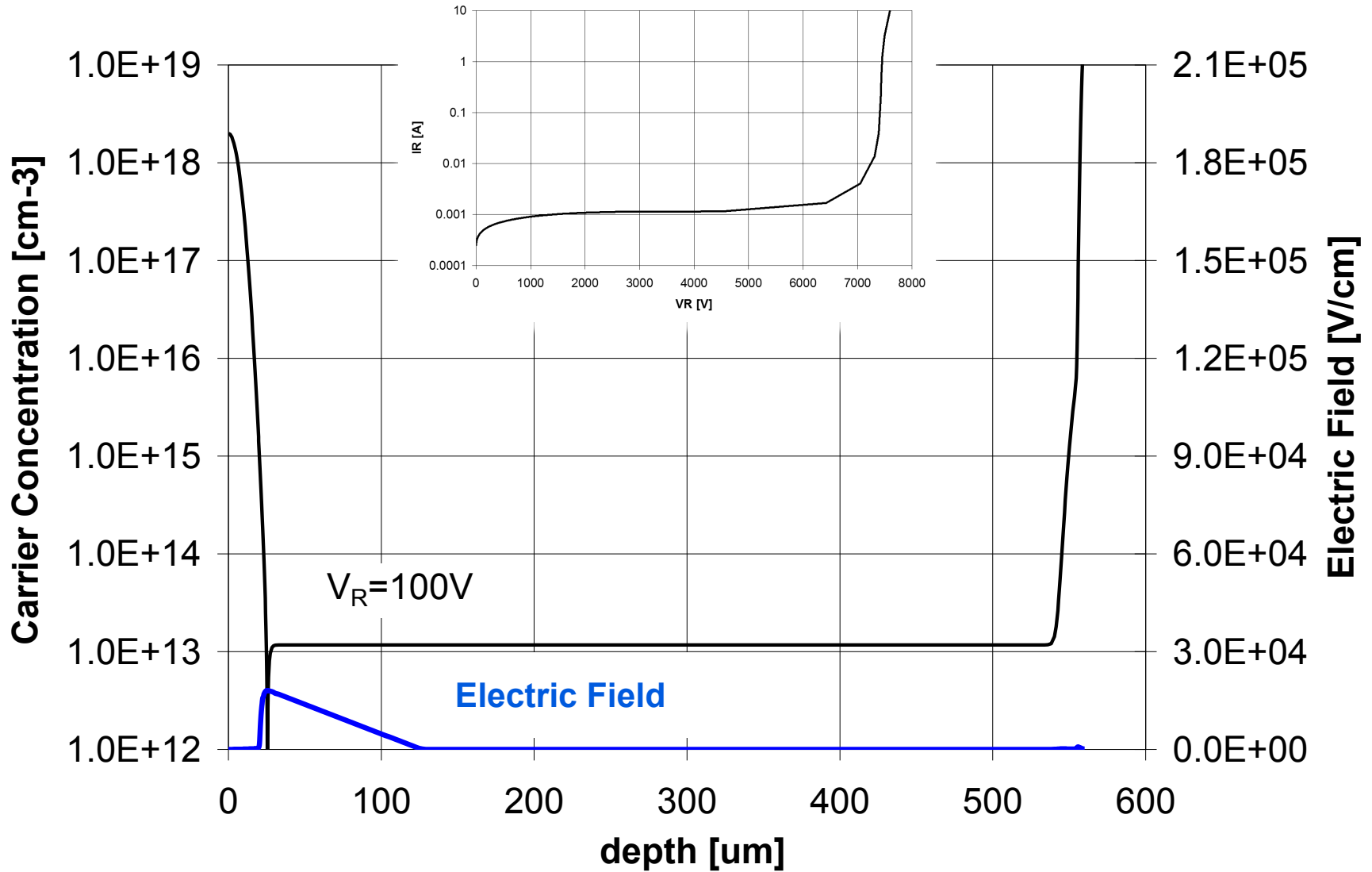


$$V_{bd} = 5.34 \times 10^{13} N_D^{-3/4} \quad \text{Non - Punch Through Breakdown Voltage}$$

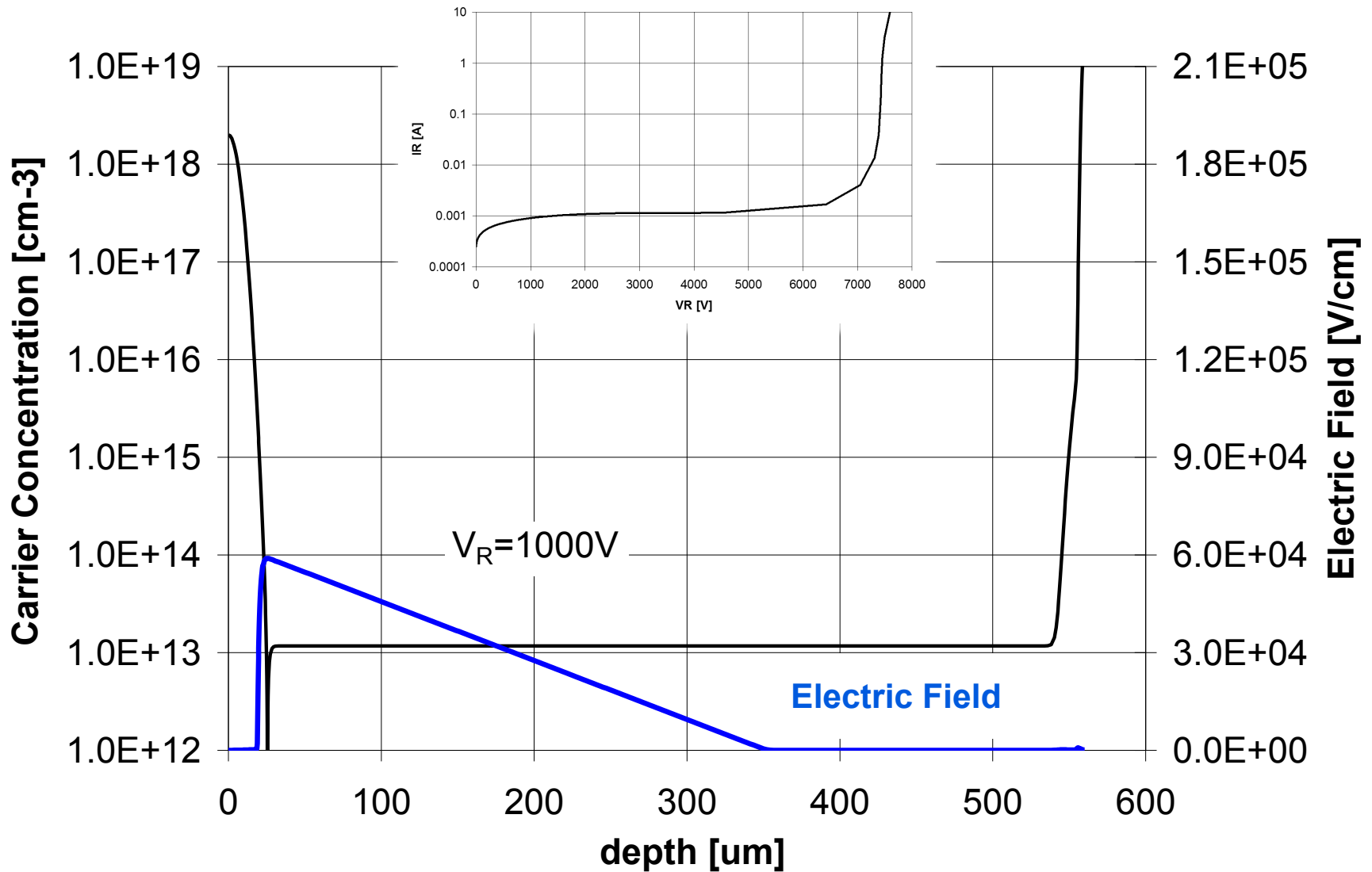
$$V_{pt} = 7.67 \times 10^{-12} N_D W_B \quad \text{Punch Through Voltage}$$

- All the constants on the right hand side of the above equations have units which will result in a final unit in (Volts).

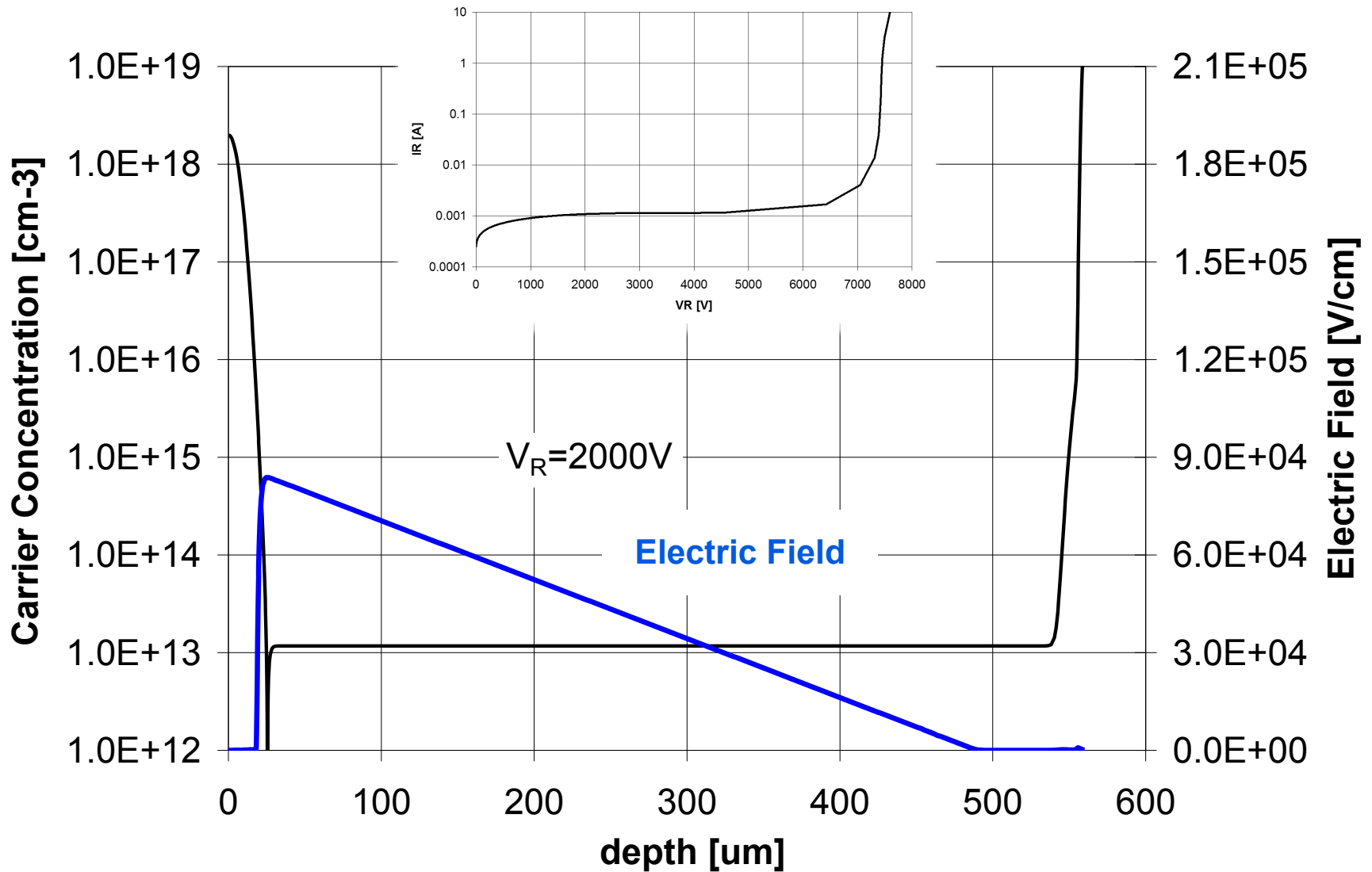
Power Diode Reverse Blocking Simulation (1/5)



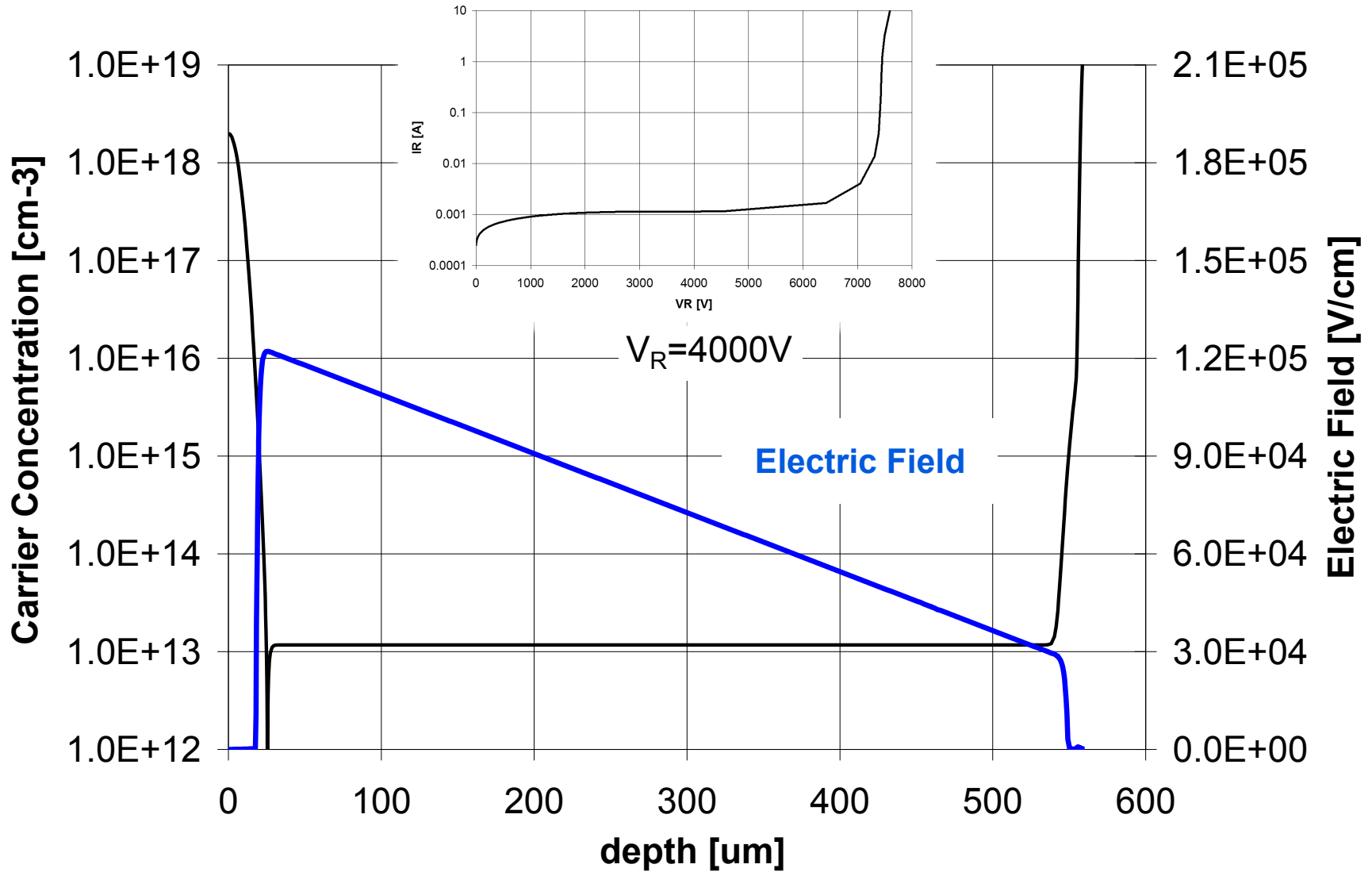
Power Diode Reverse Blocking Simulation (2/5)



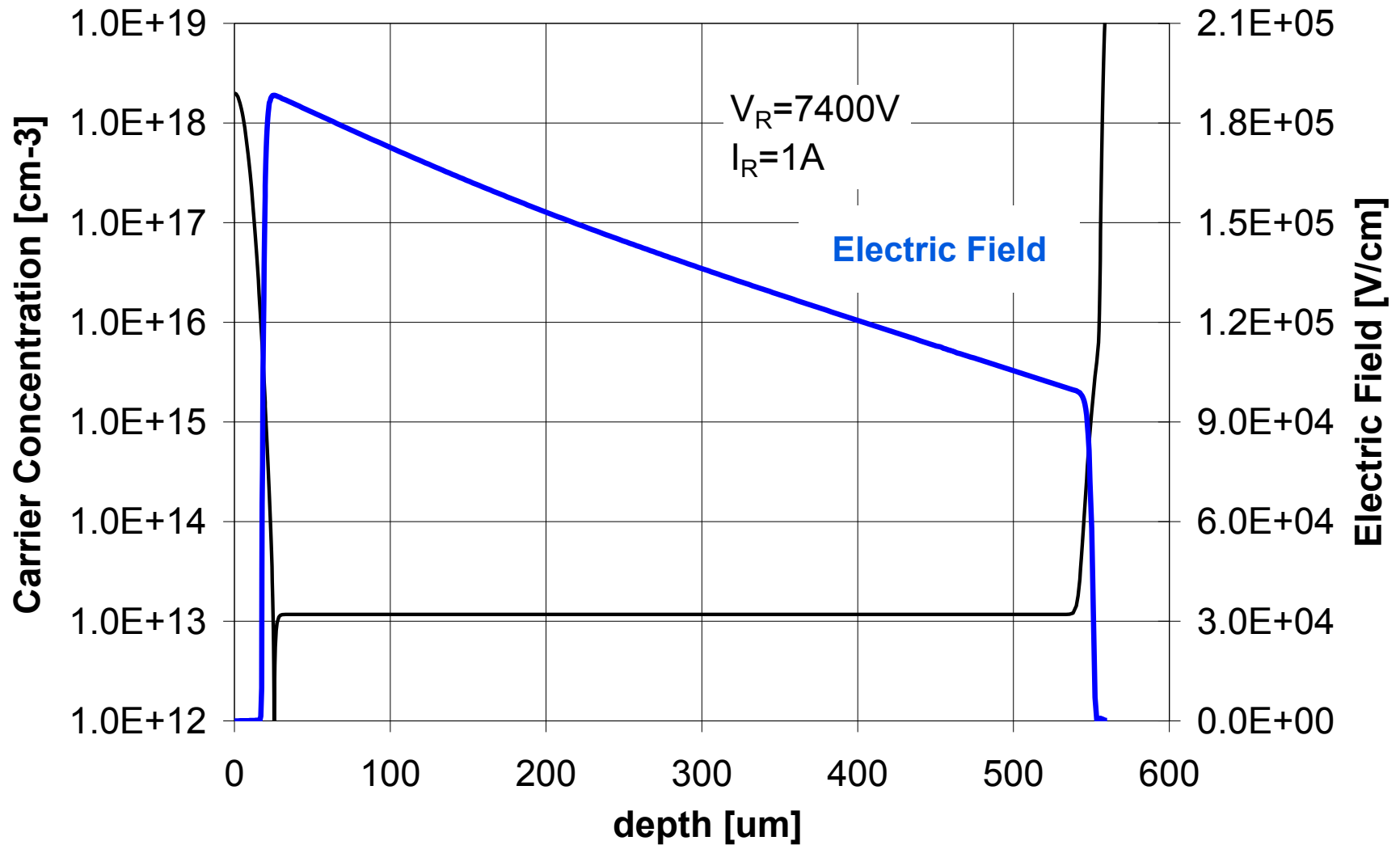
Power Diode Reverse Blocking Simulation (3/5)



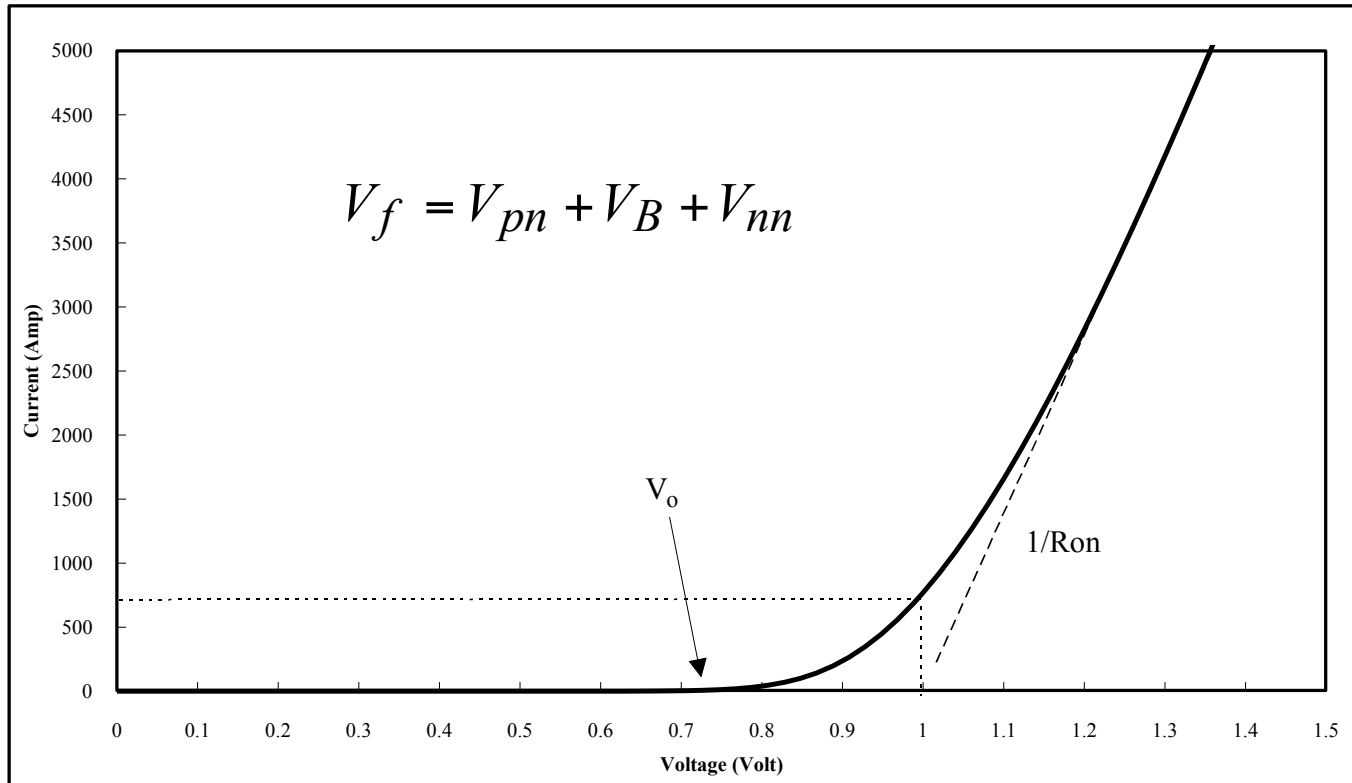
Power Diode Reverse Blocking Simulation (4/5)



Power Diode Reverse Blocking Simulation (5/5)

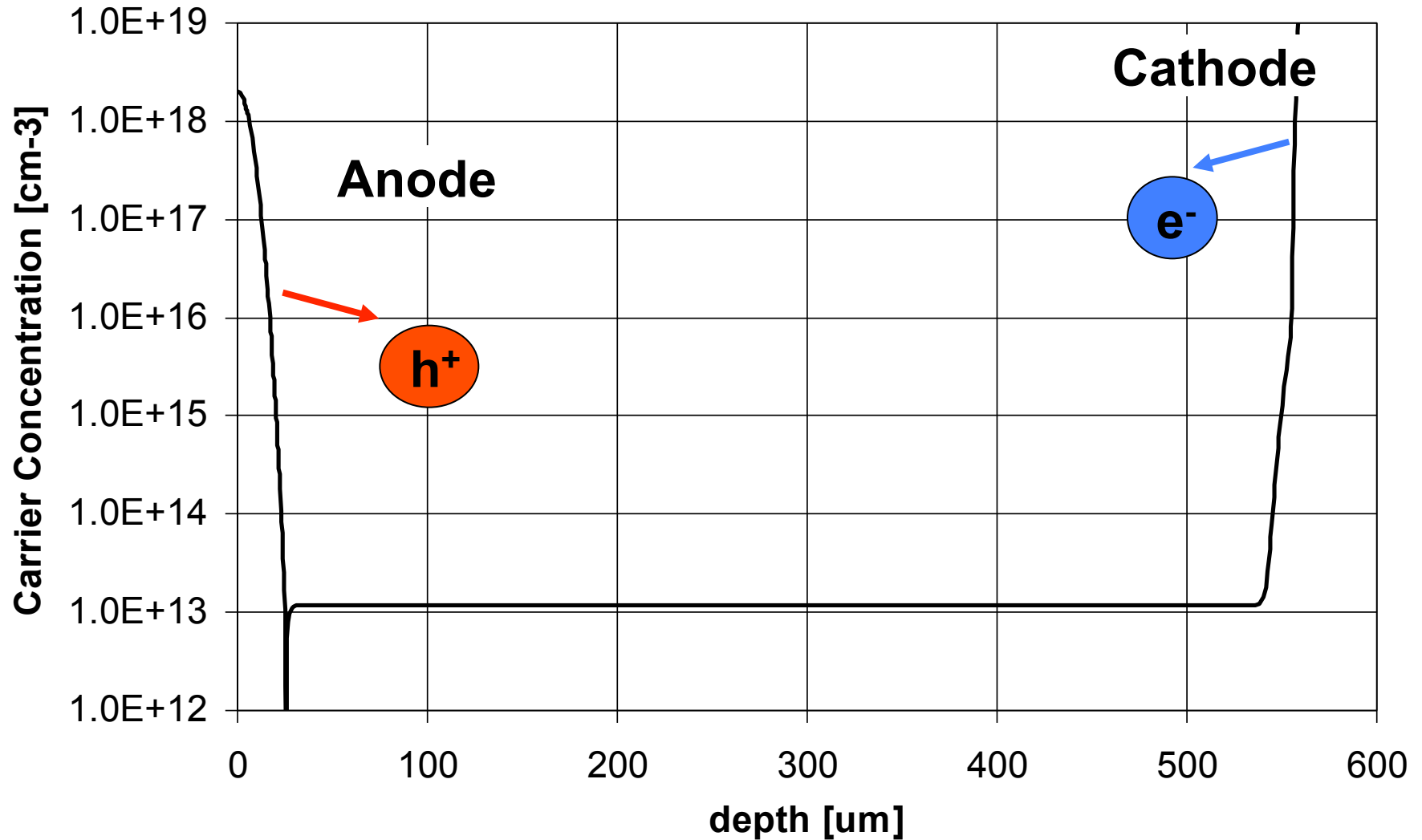


Power Diode in Forward Conduction Mode

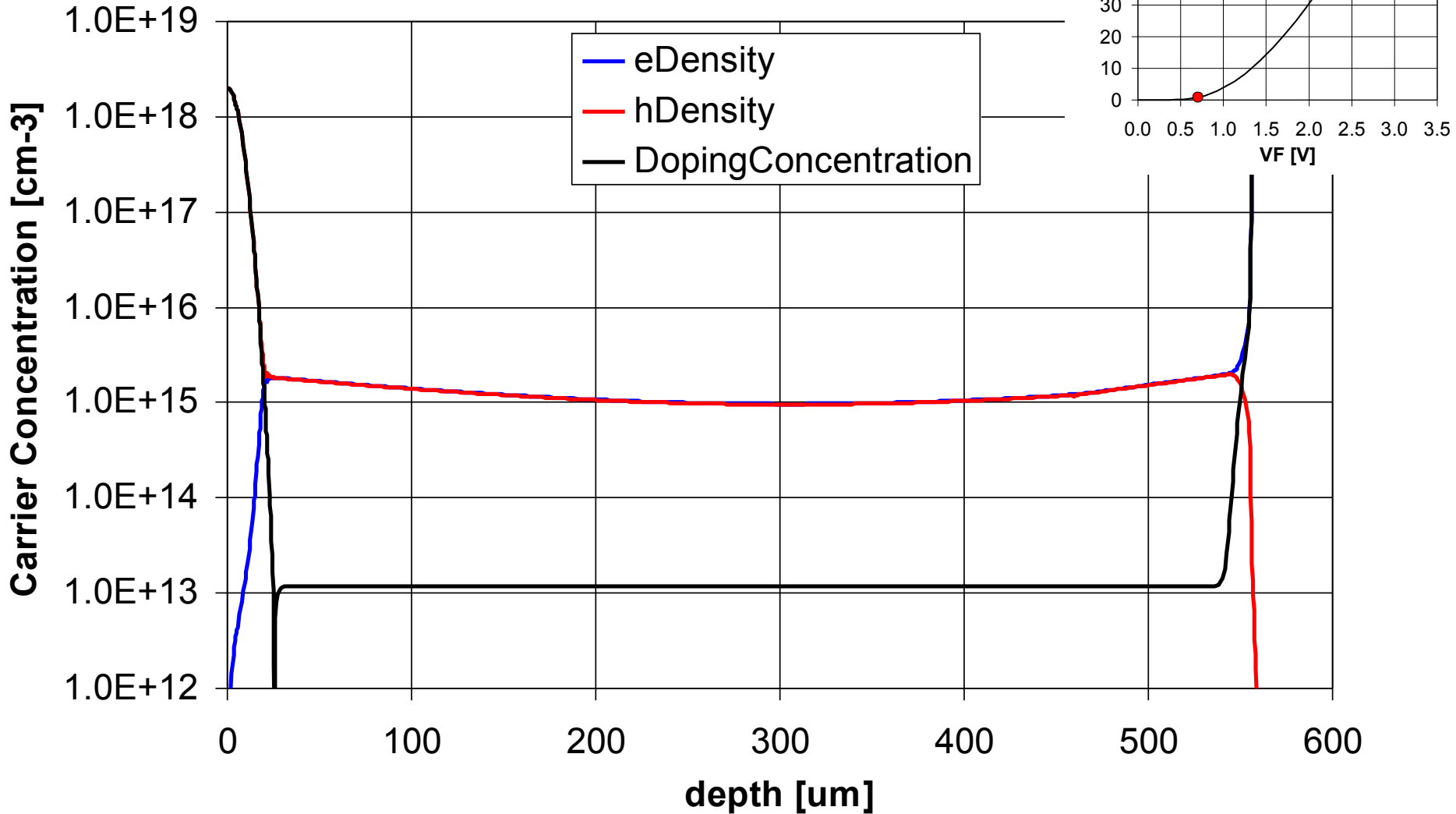


$$V_B = \frac{2kT}{q} \left(\frac{W_B}{2L_a} \right)^2 \quad \text{Base (Drift) Region Voltage Drop}$$

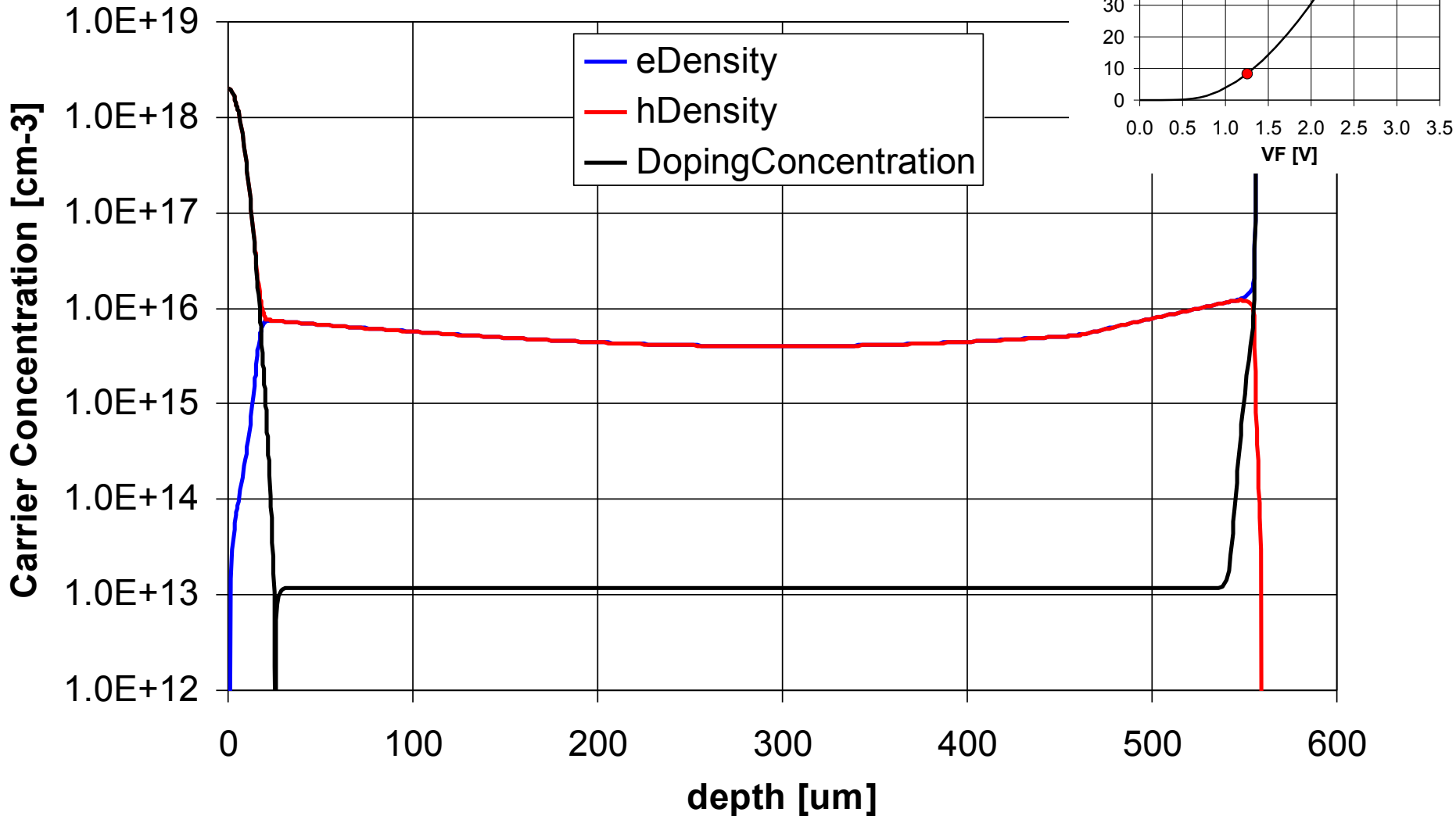
Power Diode Forward Conduction Simulation (1/5)



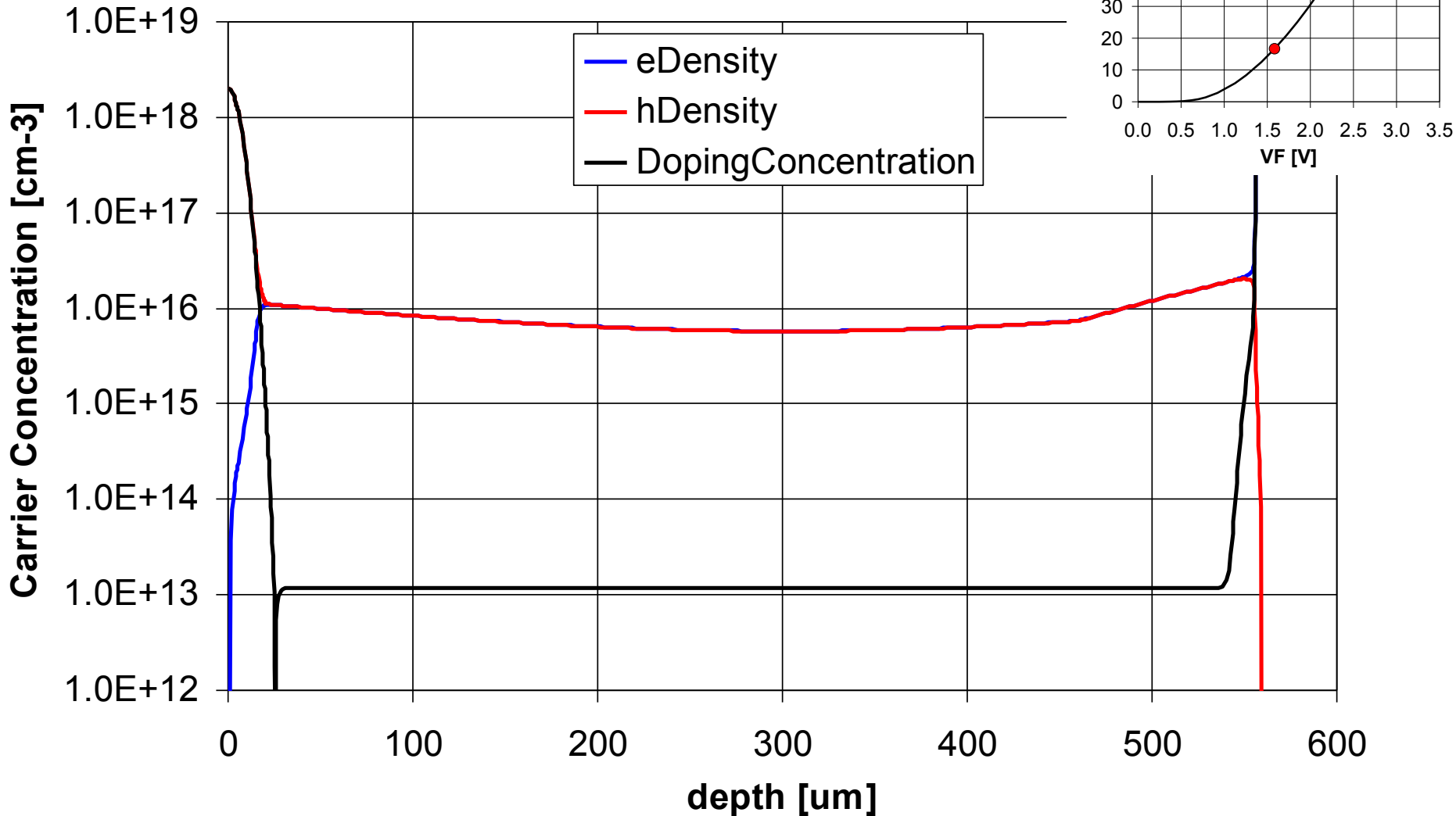
Forward Conduction Simulation (2/5)



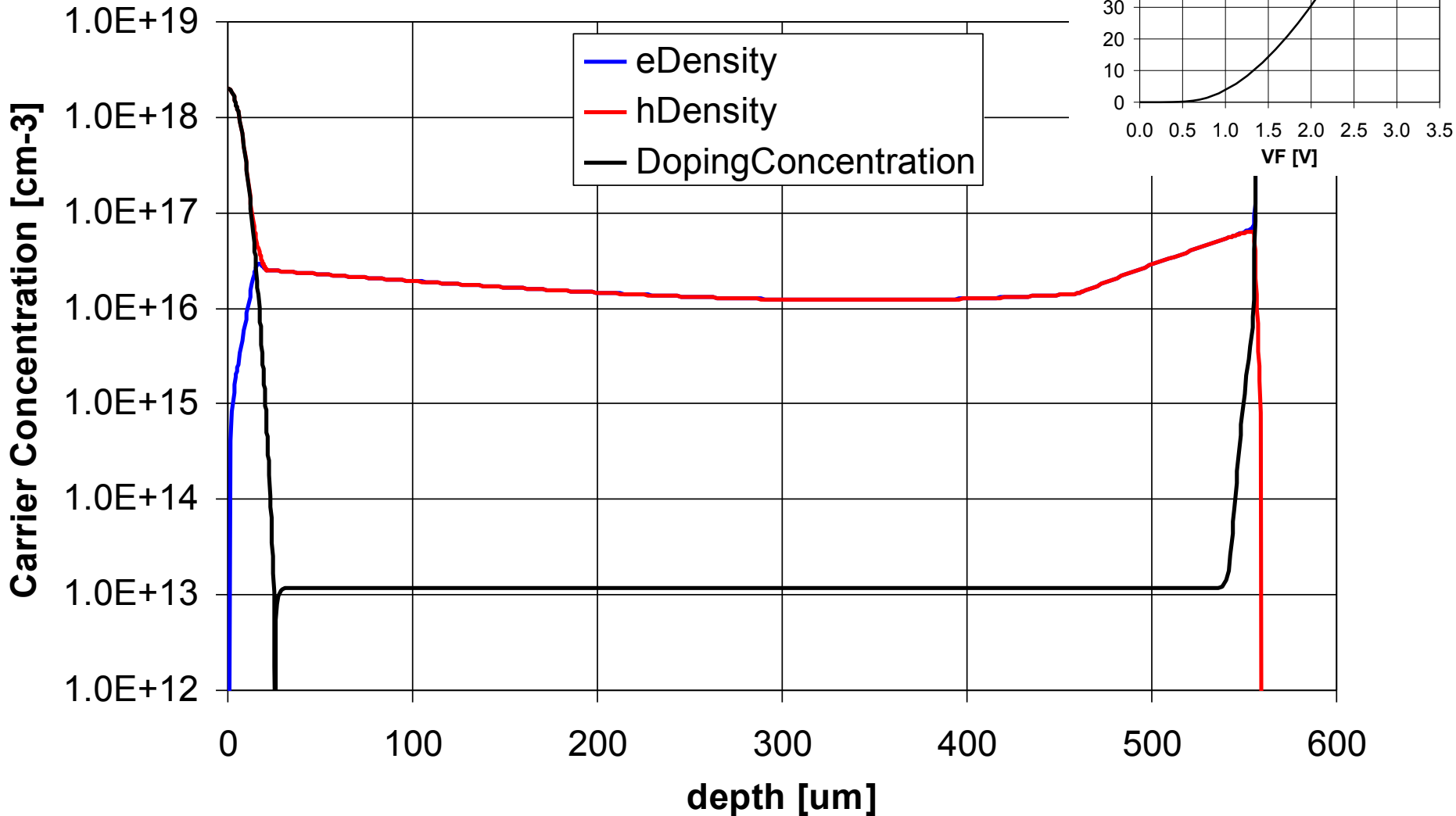
Forward Conduction Simulation (3/5)



Forward Conduction Simulation (4/5)

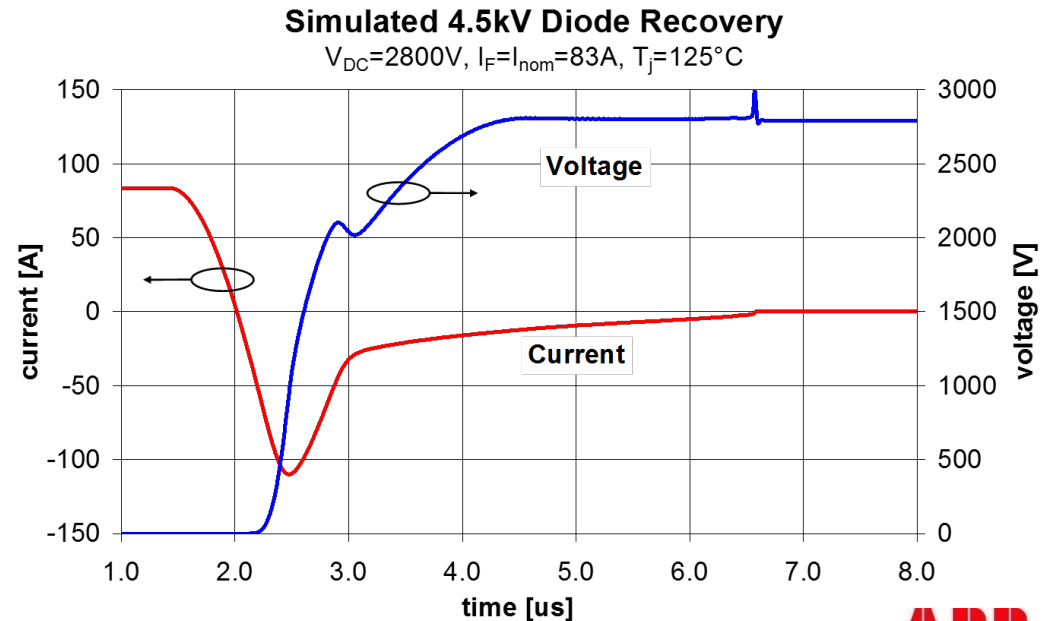
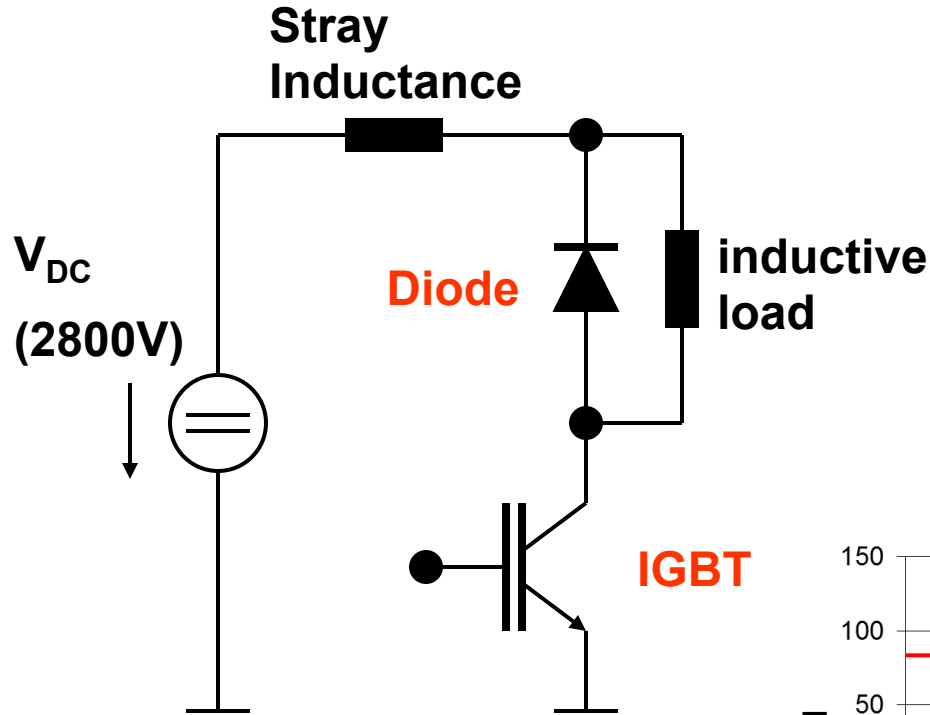


Forward Conduction Simulation (5/5)



Power Diode Reverse Recovery

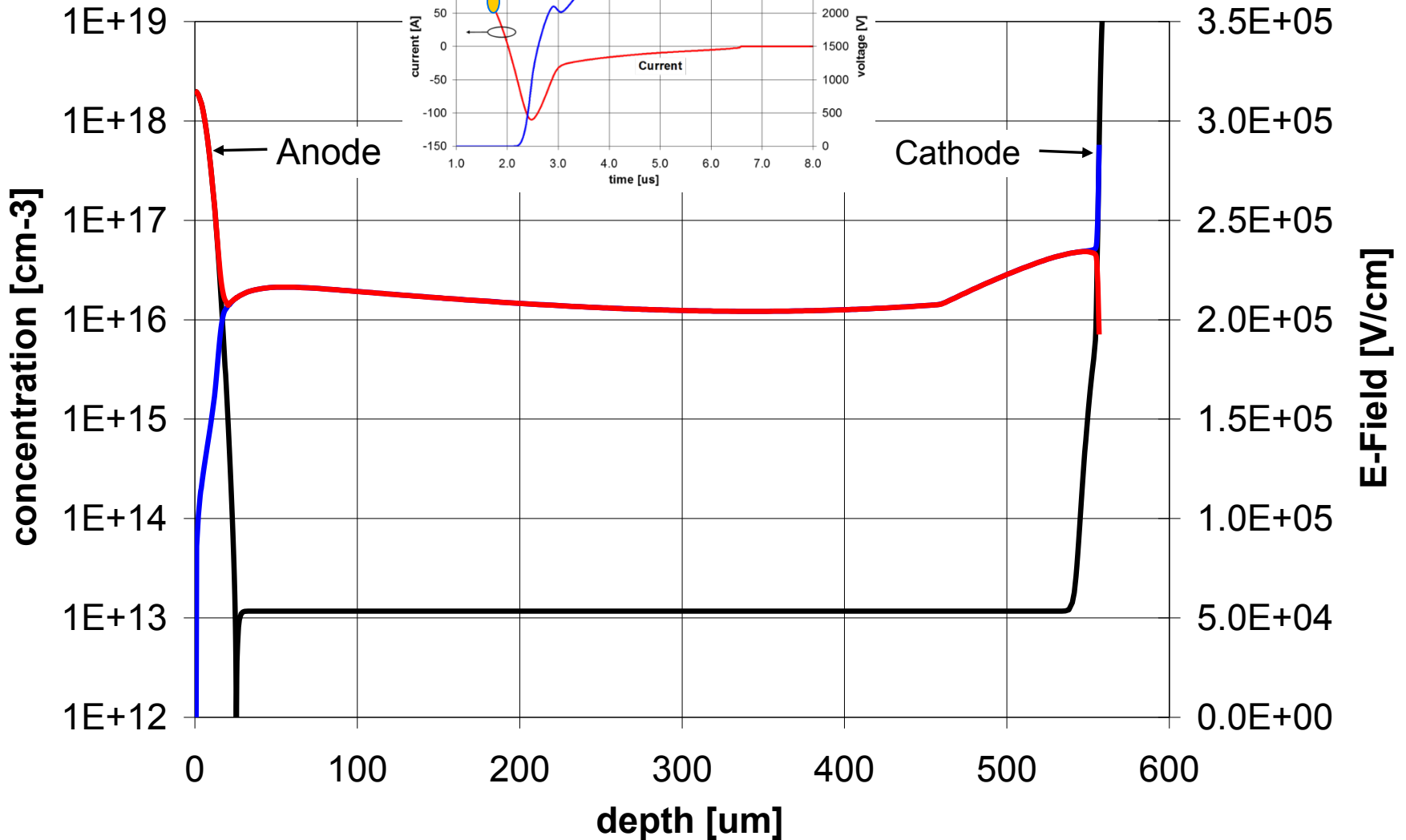
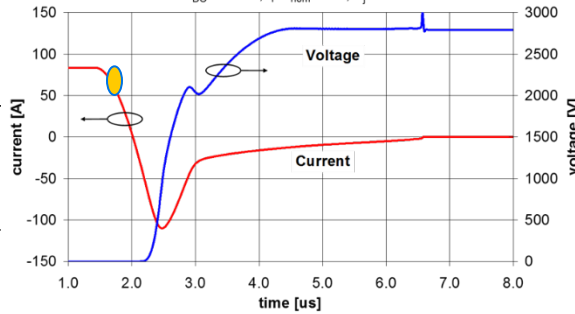
- Reverse Recovery: Transition from the conducting to the blocking state



Reverse Recovery Simulation (1/5)

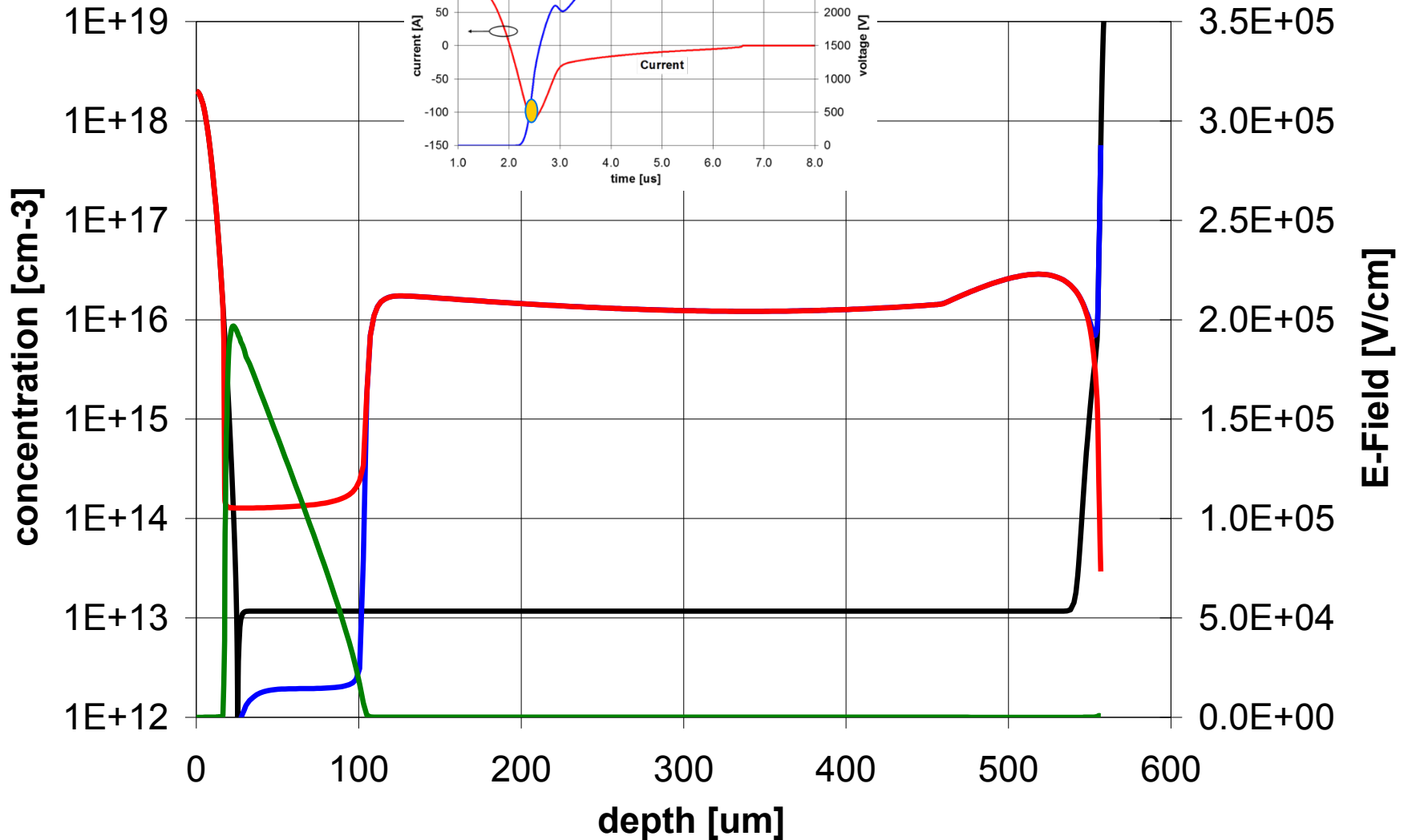
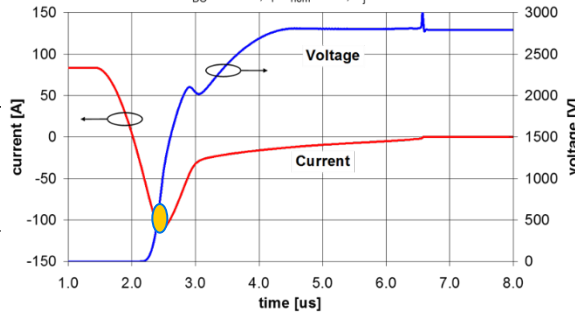
Simulated 4.5kV Diode Recovery

$V_{DC}=2800V$, $I_F=I_{nom}=83A$, $T_J=125^{\circ}C$



Reverse Recovery Simulation (2/5)

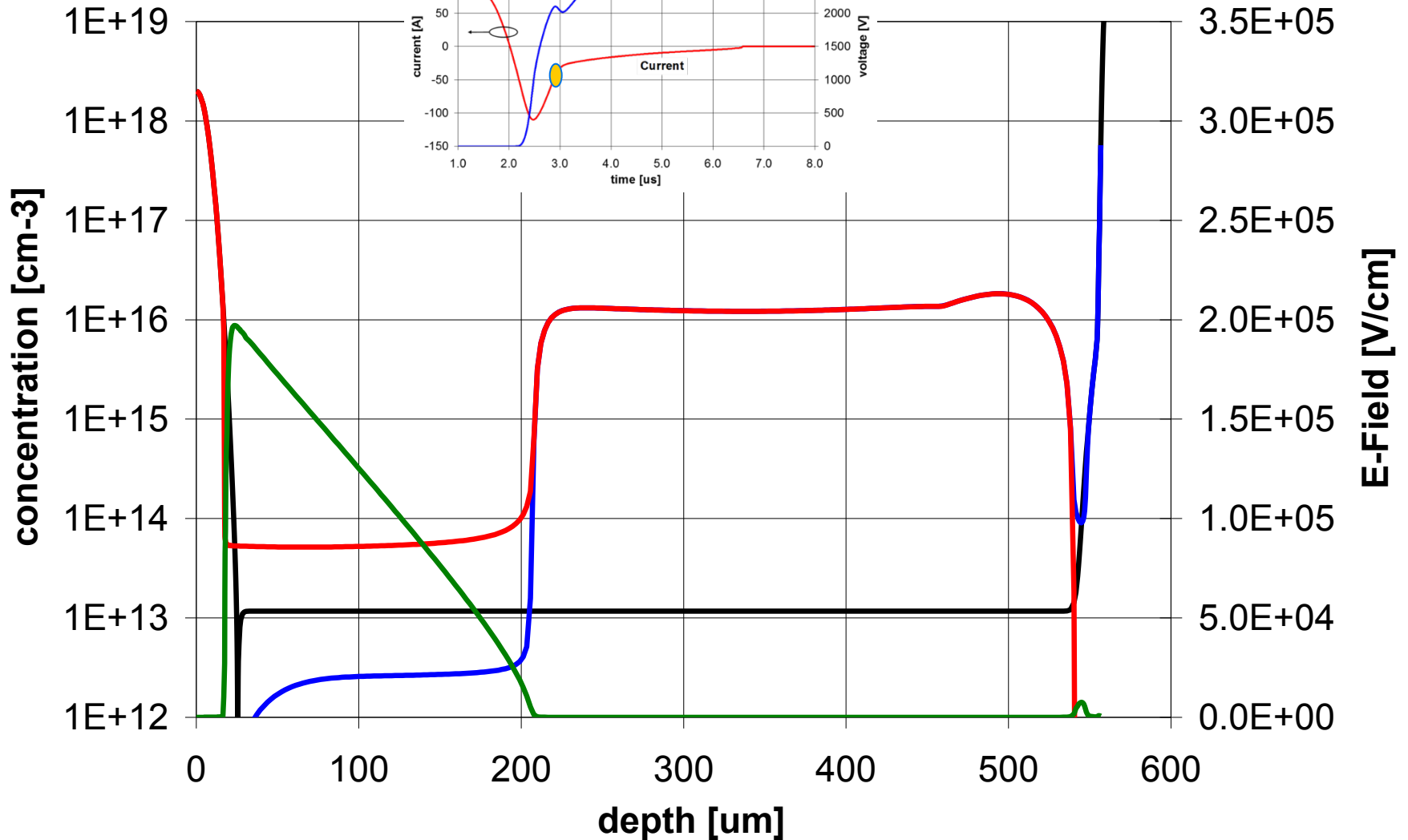
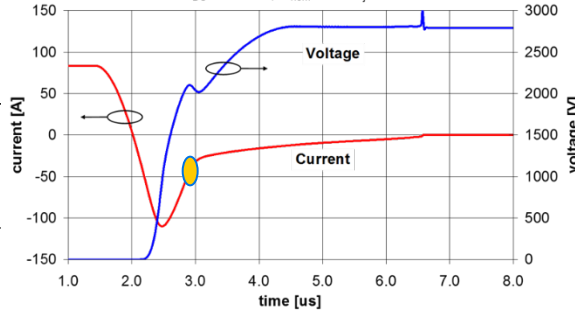
Simulated 4.5kV Diode Recovery
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Reverse Recovery Simulation (3/5)

Simulated 4.5kV Diode Recovery

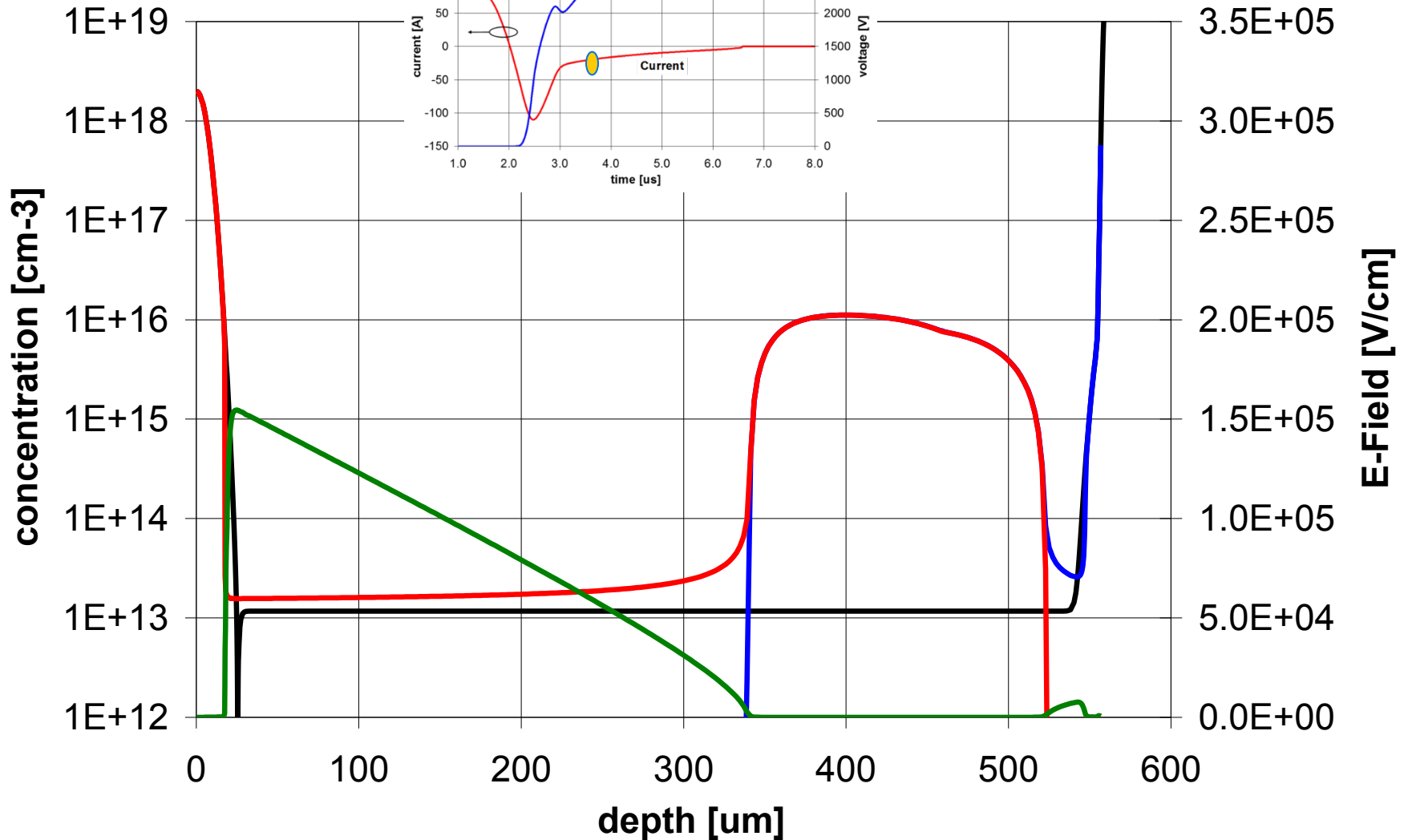
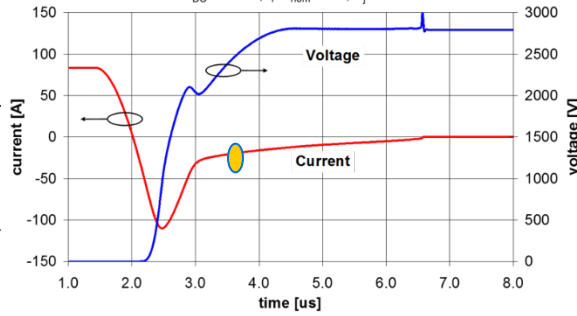
$V_{DC}=2800V$, $I_F=I_{nom}=83A$, $T_J=125^{\circ}C$



Reverse Recovery Simulation (4/5)

Simulated 4.5kV Diode Recovery

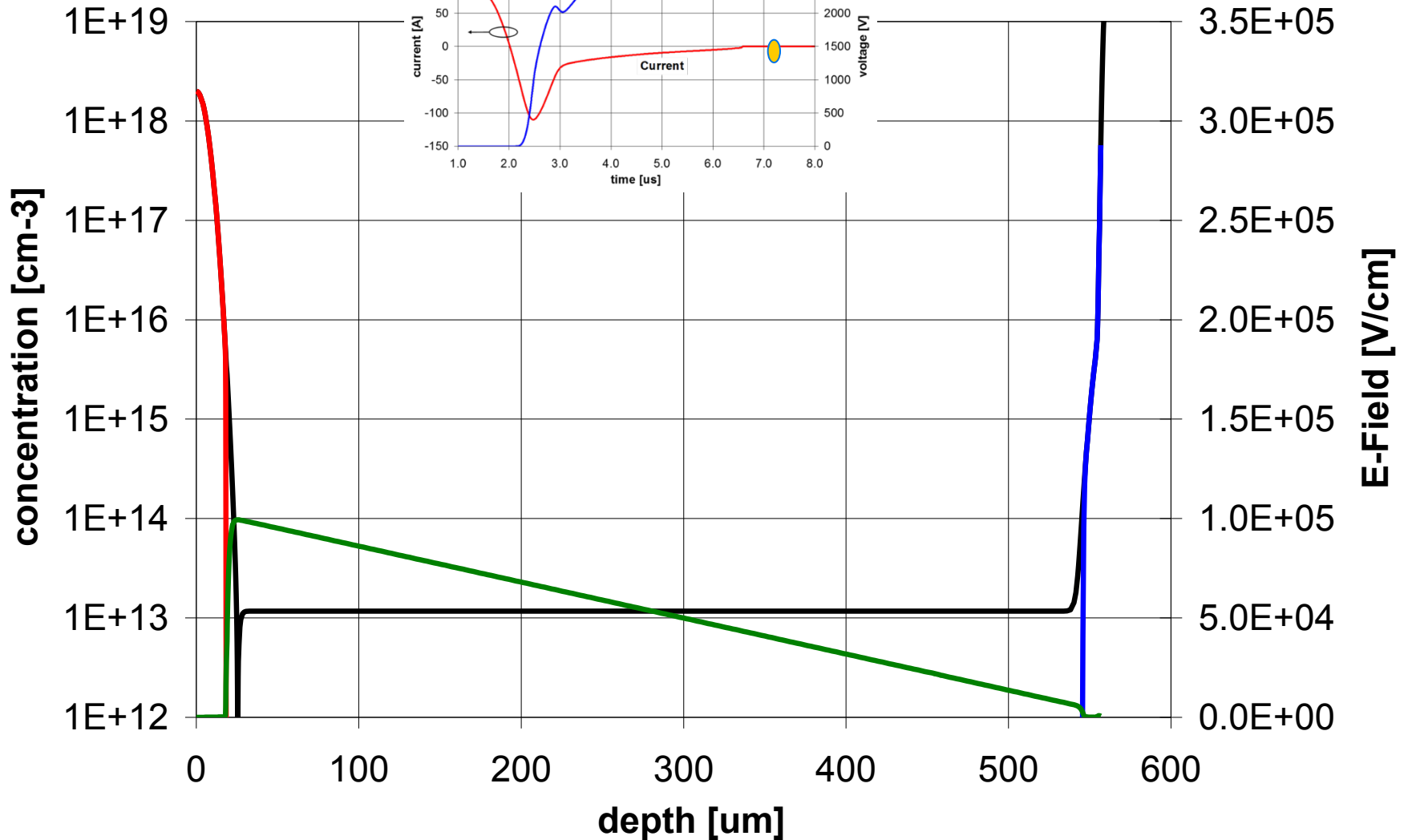
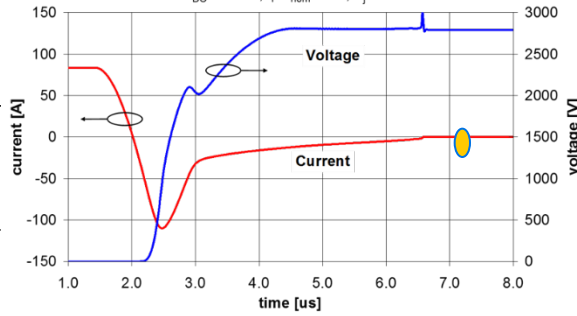
$V_{DC}=2800V$, $I_F=I_{nom}=83A$, $T_J=125^{\circ}C$



Reverse Recovery Simulation (5/5)

Simulated 4.5kV Diode Recovery

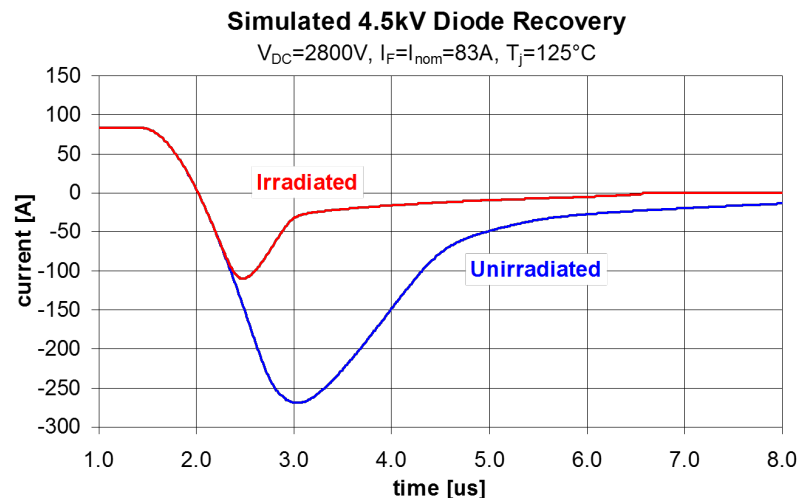
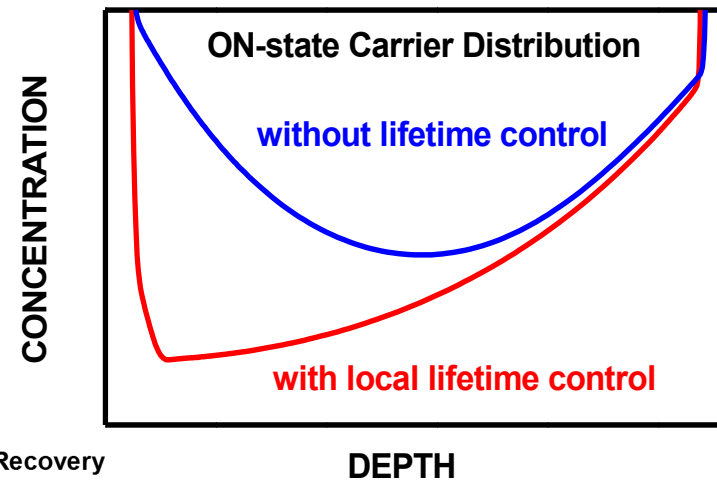
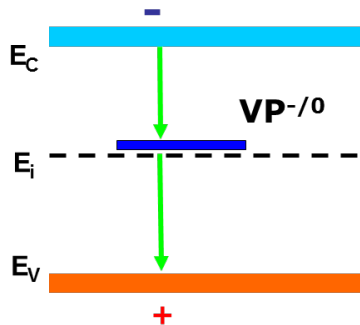
$V_{DC}=2800V$, $I_F=I_{nom}=83A$, $T_J=125^{\circ}C$



Lifetime Engineering of Power Diodes

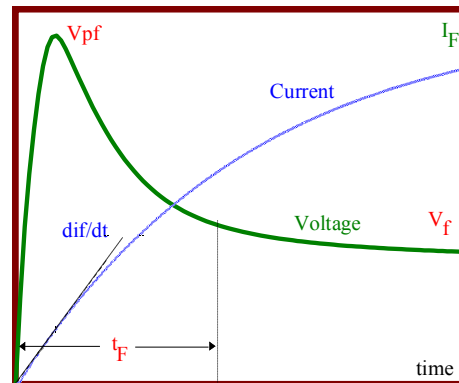
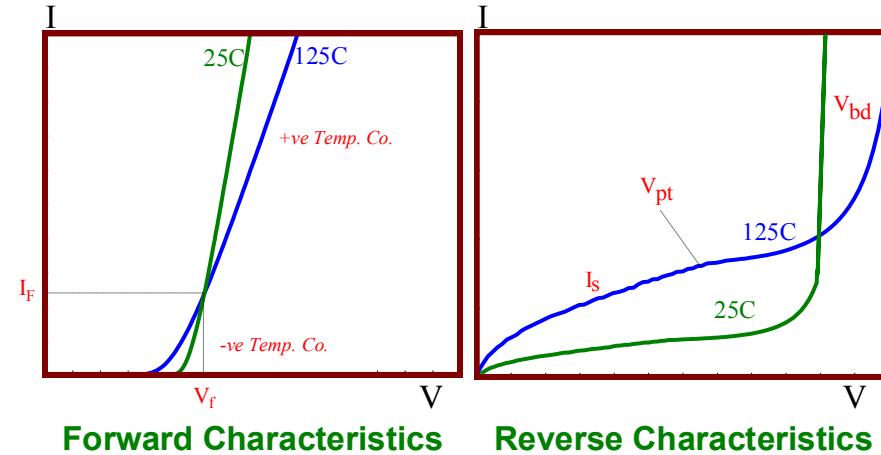
- Recombination Lifetime: Average value of time (ns - us) after which free carriers recombine (= disappear).
- Lifetime Control: Controlled introduction of lattice defects → enhanced carrier recombination → shaping of the carrier distribution

Example of carrier recombination in Silicon:

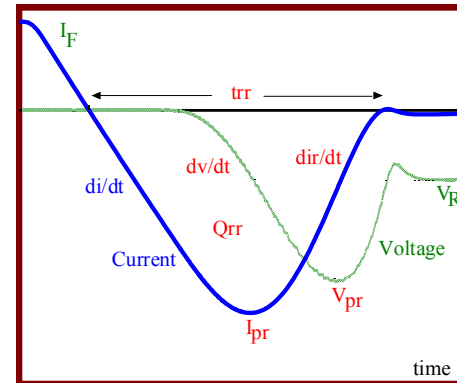


Power Diode Operational Modes

- Reverse Blocking State
 - Stable reverse blocking
 - Low leakage current
- Forward Conducting State
 - Low on-state losses
 - Positive temperature coefficient
- Turn-On (forward recovery)
 - Low turn-on losses
 - Short turn-on time
 - Good controllability
- Turn-Off (reverse recovery)
 - Low turn-off losses
 - Short turn-off time
 - Soft characteristics
 - Dynamic ruggedness



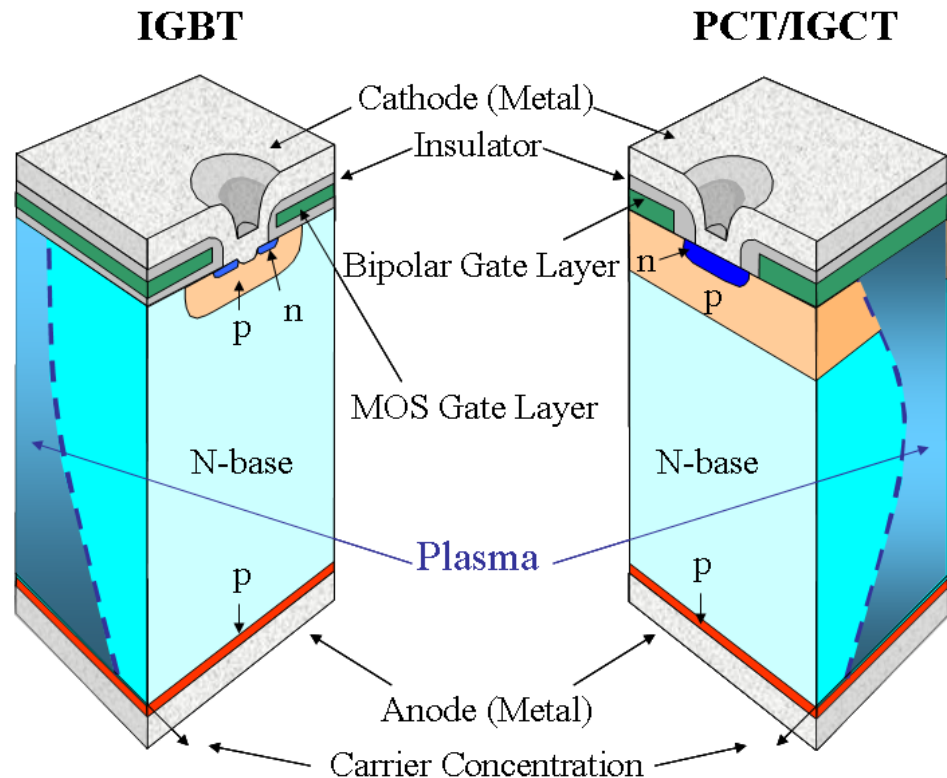
Forward Recovery



Reverse Recovery

Power Semiconductors

Technologies and Performance



Silicon Power Semiconductor Device Concepts



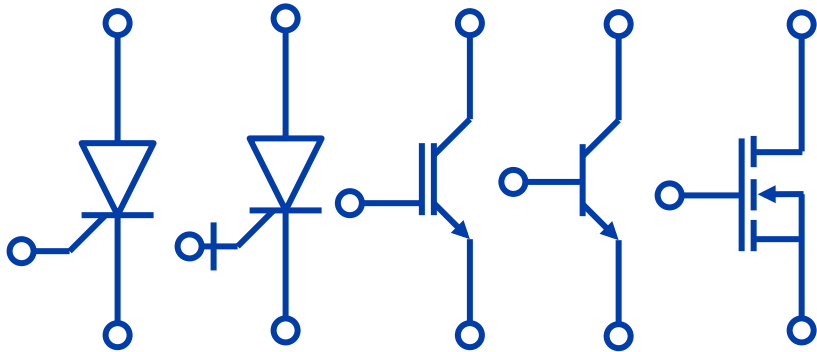
1000s of volts

PCT

IGBT

10s of volts

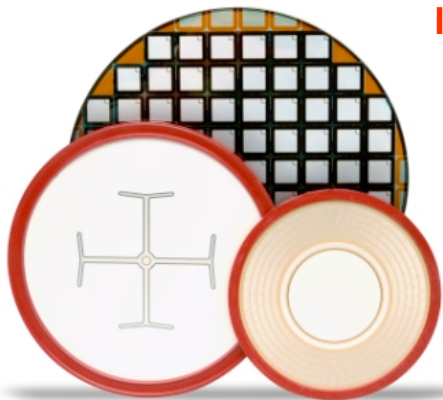
MOSFET



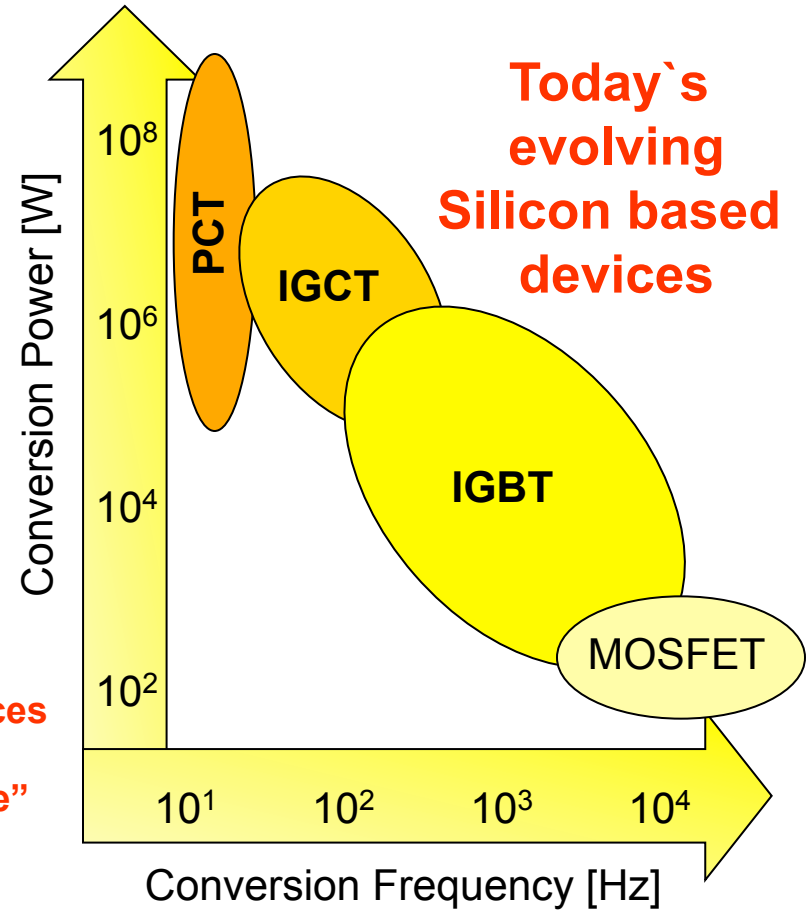
GTO / **GCT**

BJT

and the companion **Diode**

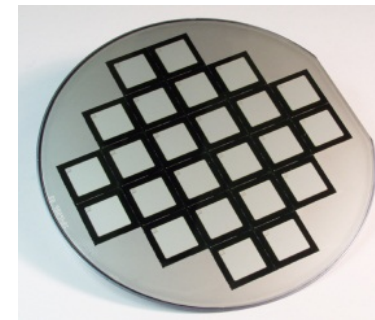
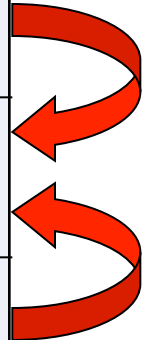


In red are devices that are in "design-in life"

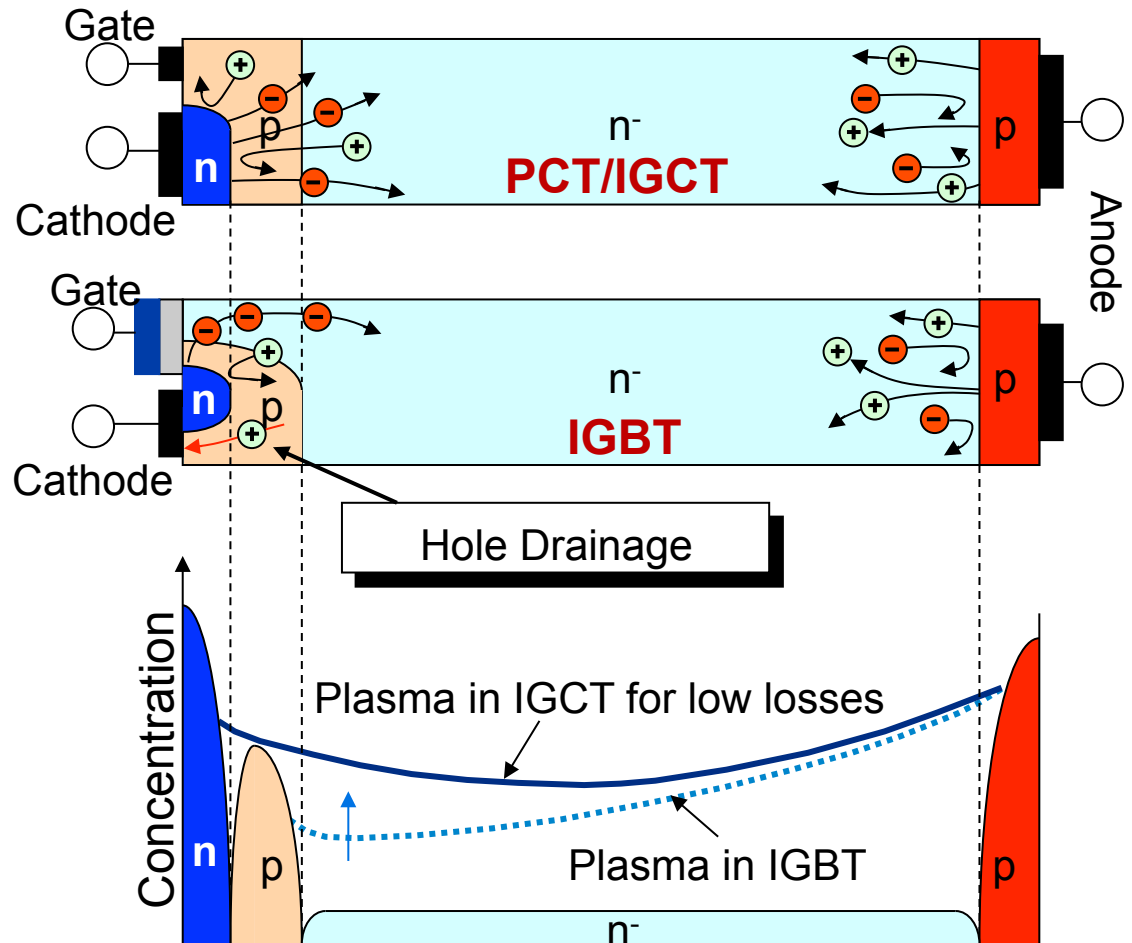
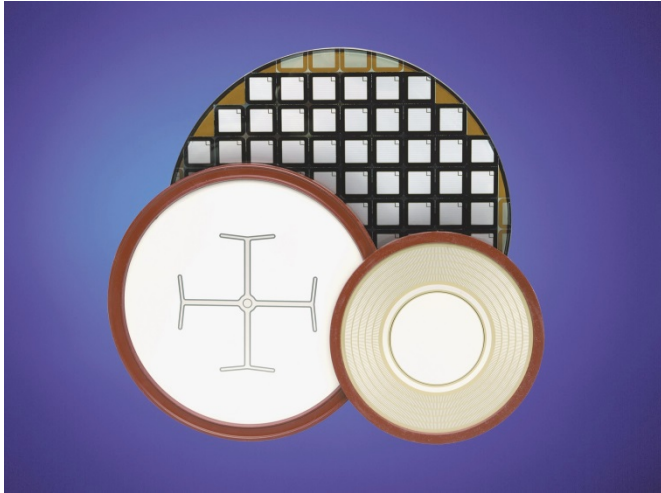


Silicon Power Semiconductor Switches

Technology	Device Character	Control Type
<u>Bipolar (Thyristor)</u> Thyristor, GTO, GCT	Low on-state losses High Turn-off losses	Current Controlled (“High” control power)
<u>Bipolar (Transistor)</u> BJT, Darlington	Medium on-state losses Medium Turn-off losses	Current Controlled (“High” control power)
<u>BiMOS (Transistor)</u> IGBT	Medium on-state losses Medium Turn-off losses	Voltage Controlled (Low control power)
<u>Unipolar (Transistor)</u> MOSFET, JFET	High on-state losses Low Turn-off losses	Voltage Controlled (Low control power)

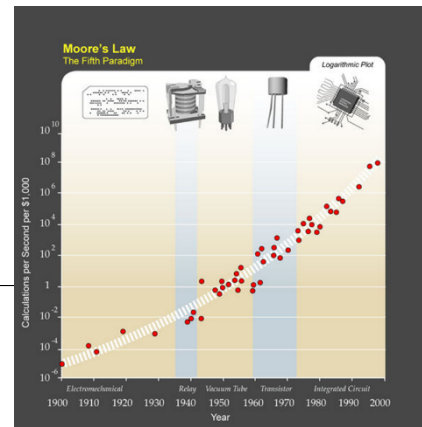


The main High Power MW Devices: LOW LOSSES

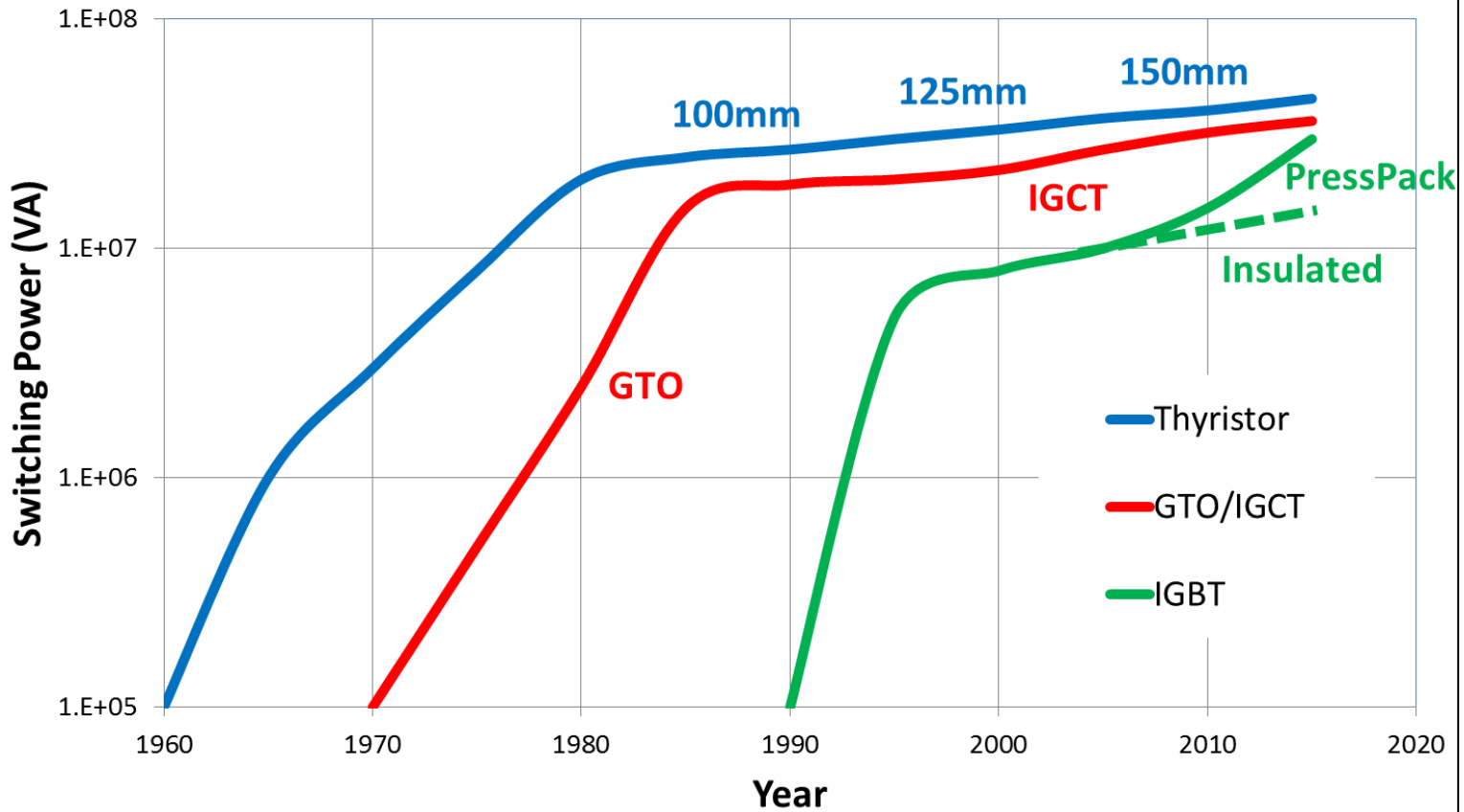


- **PCTs & IGCTs:** optimum carrier distribution for lowest losses
- **IGBTs:** continue to improve the carrier distribution for low losses

The High Power Devices Developments

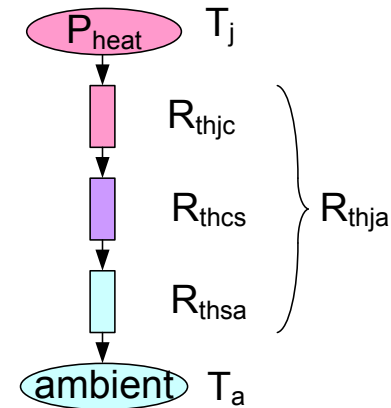
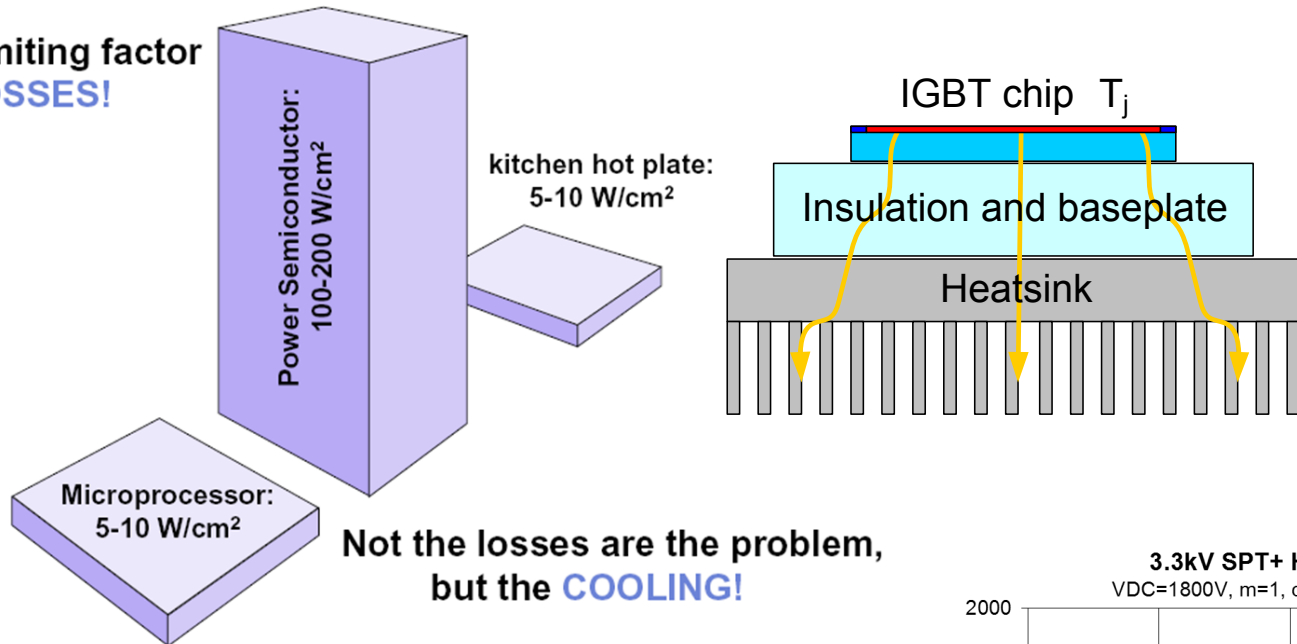


Historical Development of the Maximum Switching power of the Three Major High Power Semiconductors



Power Semiconductor Power Ratings

The limiting factor are **LOSSES!**



Not the losses are the problem, but the **COOLING!**

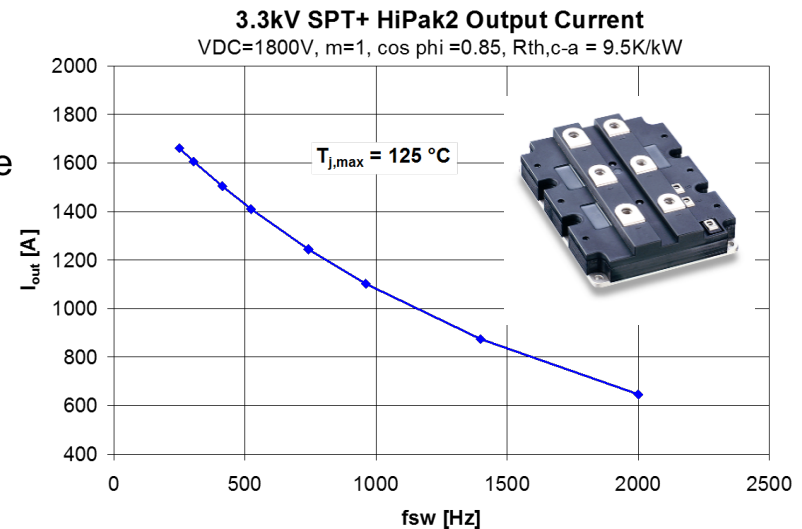
Example: Cont. Conduction 3.3kV/1.5kA IGBT Package

$$V_{CE,on} = 3.0V @ I_C = 1500A \rightarrow P_{heating} = 4.5kW$$

$$R_{th,j-a} = 18K / kW$$

$$P_{Cooling} = \frac{T_j - T_{amb}}{R_{th,j-a}} \quad T_{amb} = 40 \text{ } ^\circ C$$

$$P_{heating} = P_{cooling} \rightarrow T_j = R_{th,j-a} \cdot P_{heating} + T_{amb} = 4.5 \cdot 18 + 40 = 121 \text{ } ^\circ C$$



$$\text{Total IGBT Losses : } P_{tot} = P_{cond} + P_{turn-off} + P_{turn-on}$$

Performance Requirements for Power Devices

- **Power Density Handling Capability:**

- Low **on-state and switching losses**
- High **operating temperatures**
- Low **thermal resistance**

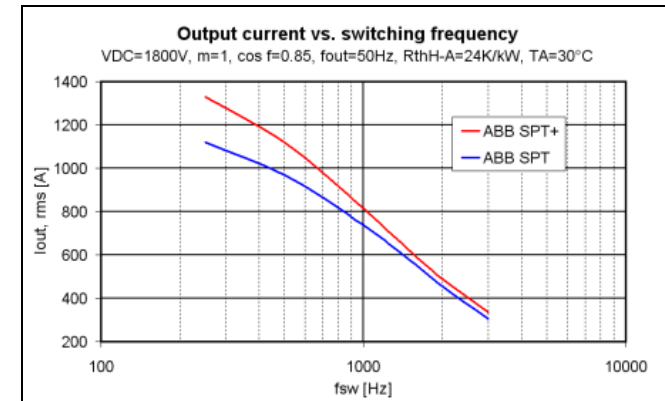
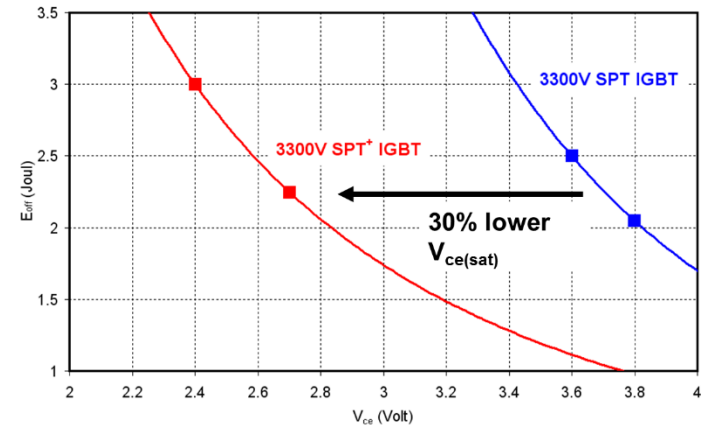
- **Controllable and Soft Switching:**

- Good **turn-on** controllability
- Soft and controllable **turn-off** and low EMI

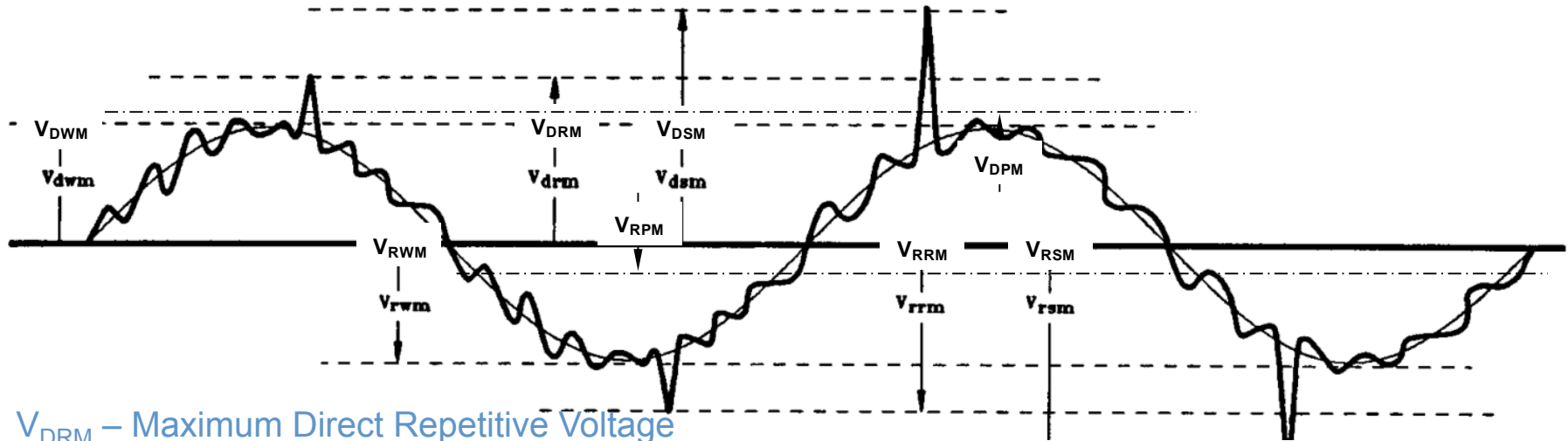
- **Ruggedness and Reliability:**

- High **turn-off current** capability
- Robust **short circuit** mode for IGBTs
- Good **surge current** capability
- Good **current / voltage sharing** for paralleled / series devices
- Stable **blocking behaviour** and low **leakage current**
- Low “Failure In Time” **FIT** rates
- Compact, powerful and reliable **packaging**

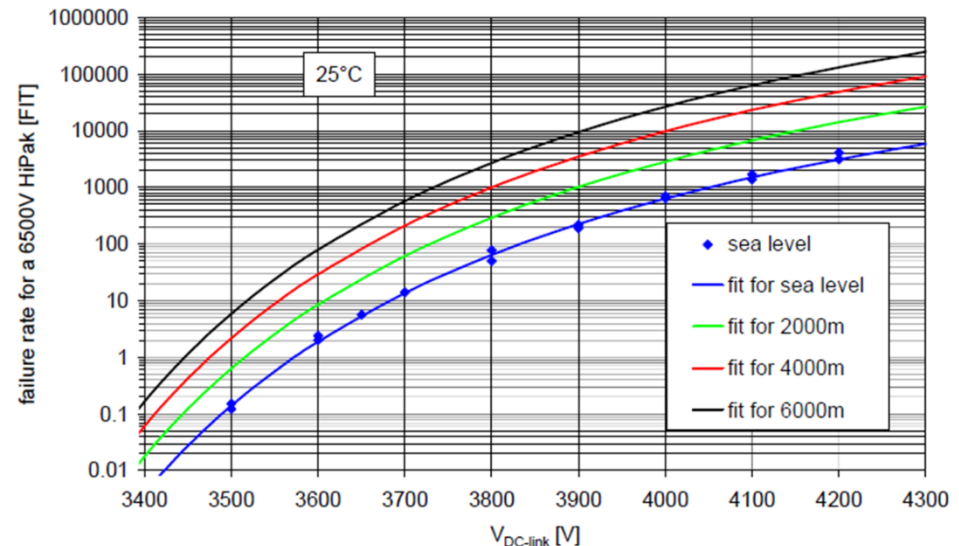
(technology curve: traditional focus)



Power Semiconductor Voltage Ratings



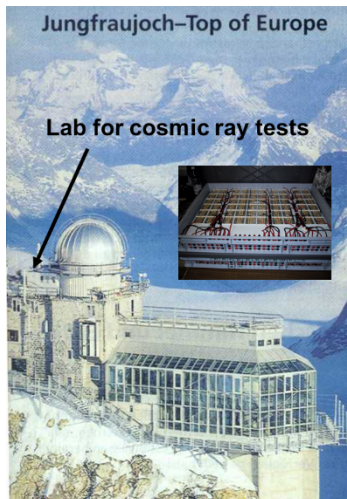
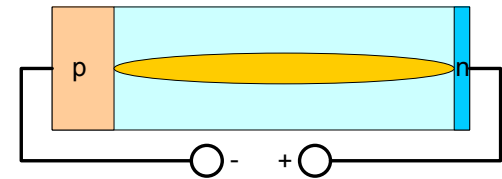
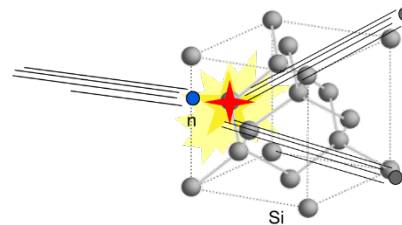
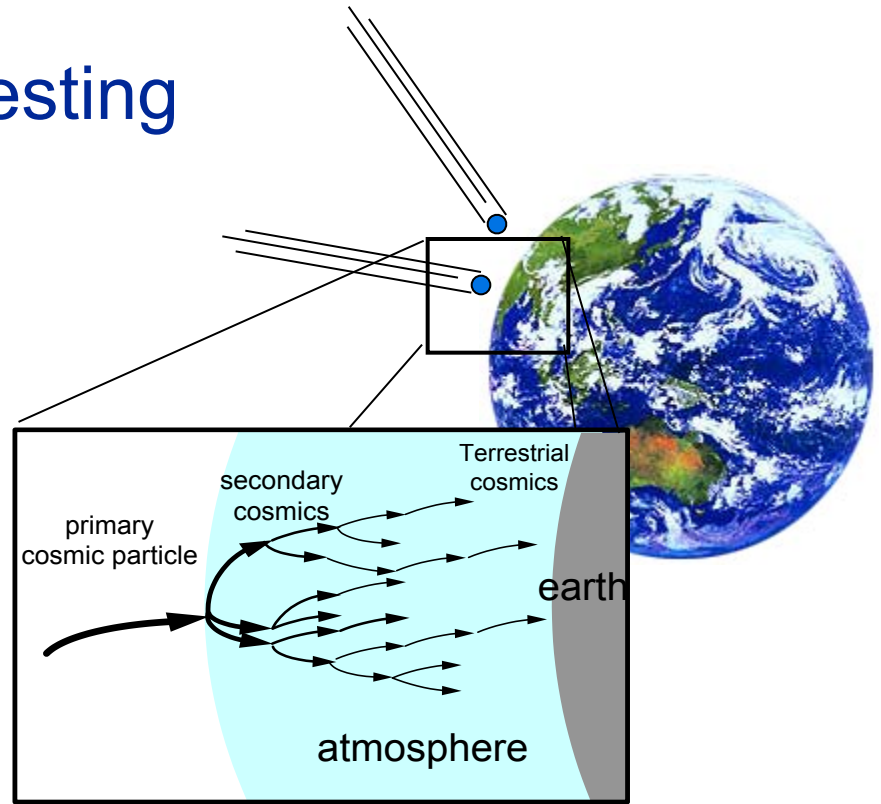
- V_{DRM} – Maximum Direct Repetitive Voltage
- V_{RRM} – Maximum Reverse Repetitive Voltage
- V_{DPM} – Maximum Direct Permanent Voltage
- V_{RPM} – Maximum Reverse Permanent Voltage
- V_{DSM} – Maximum Direct Surge Voltage
- V_{RSM} – Maximum Reverse Surge Voltage
- V_{DWM} – Maximum Direct Working Voltage



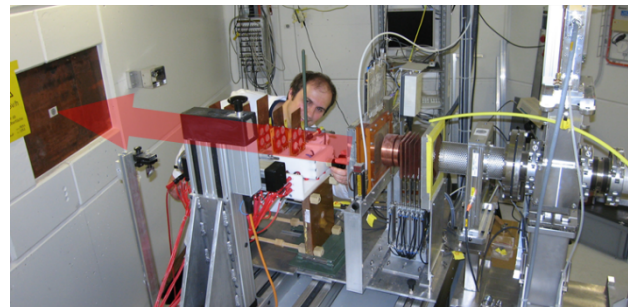
6.5kV IGBT FIT rates due to cosmic rays

Cosmic Ray Failures and Testing

- Interaction of primary cosmics with magnetic field of earth “Cosmics are more focused to the magnetic poles”
- Interaction with earth atmosphere:
 - Cascade of secondary, tertiary ... particles in the upper atmosphere
 - Increase of particle density
 - Cosmic flux dependence of altitude
- Terrestrial cosmic particle species:
 - muons, neutrons, protons, electrons, pions
- Typical terrestrial cosmic flux at sea level: 20 neutrons per cm^2 and h

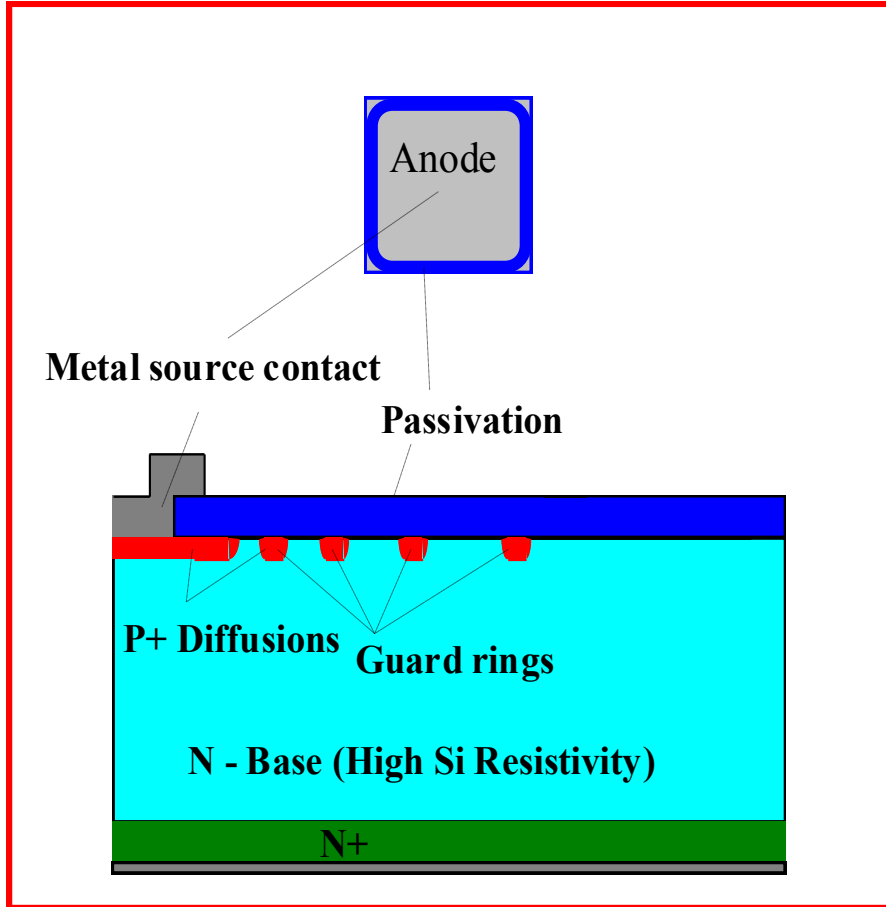


Proton beam at Paul Scherrer Institute, Switzerland

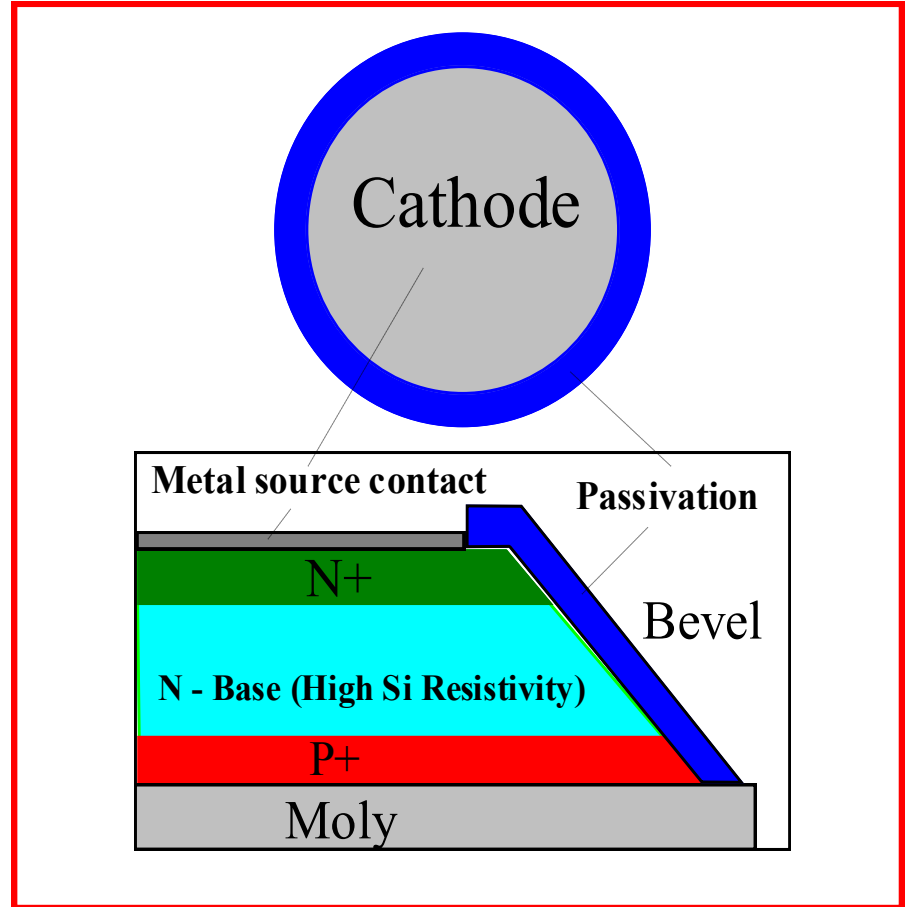


- Failures due to cosmic under blocking condition without precursor
- Statistical process and Sudden single event burnout

Power Semiconductor Junction Termination

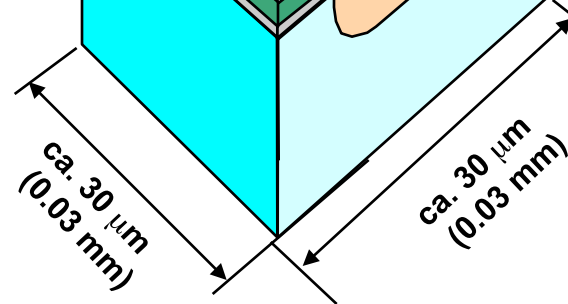
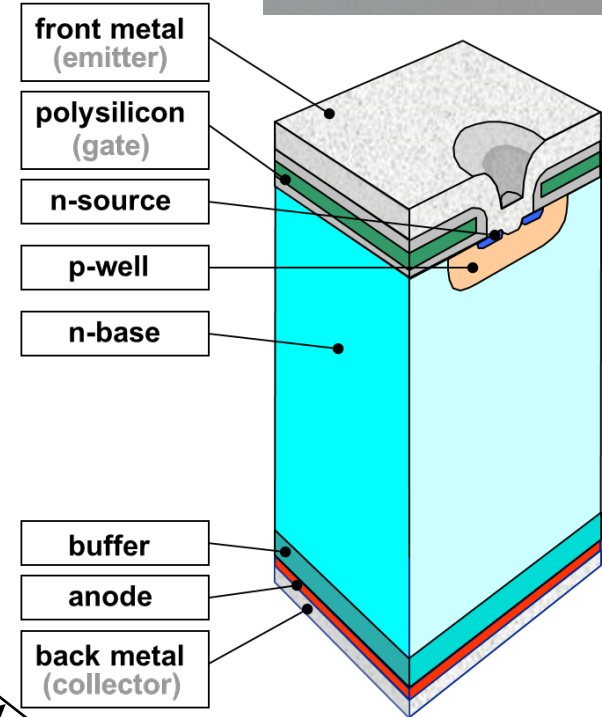
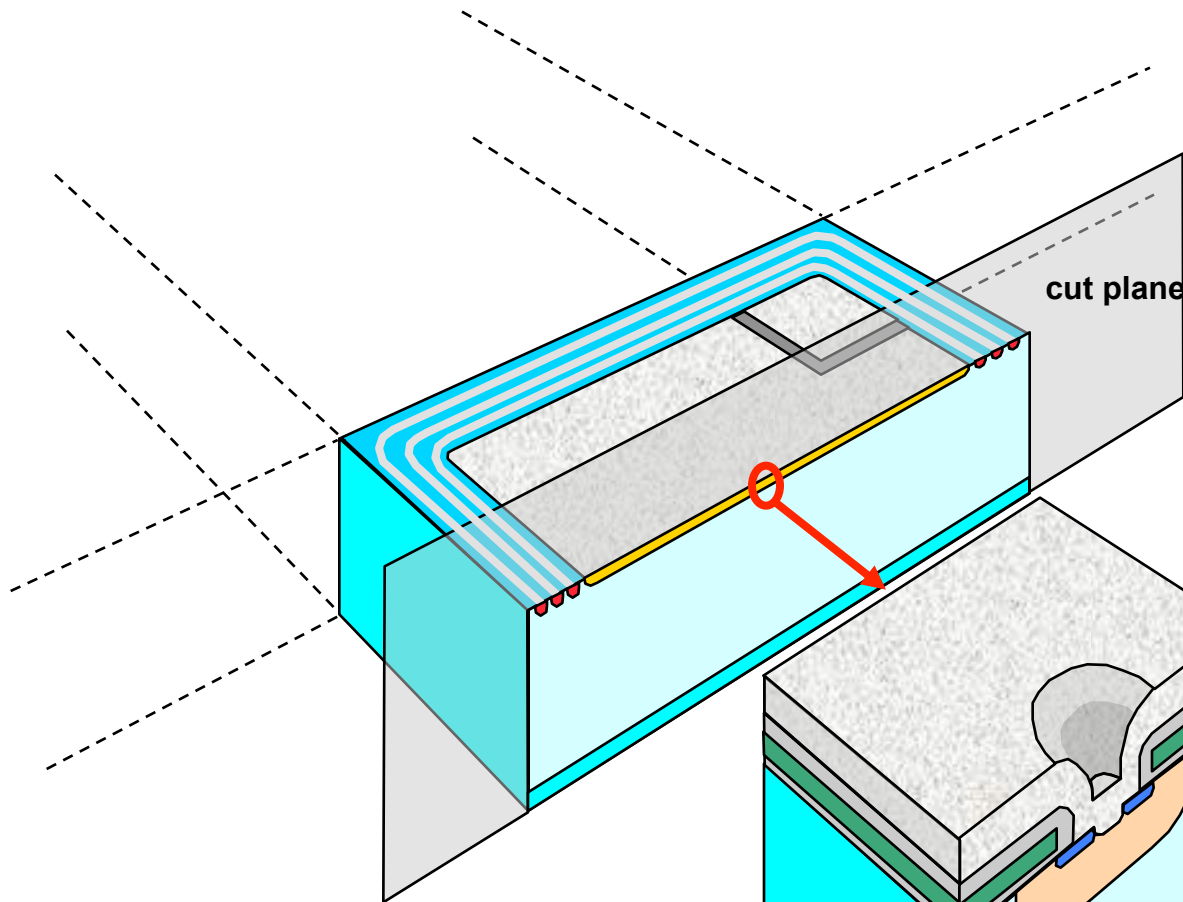
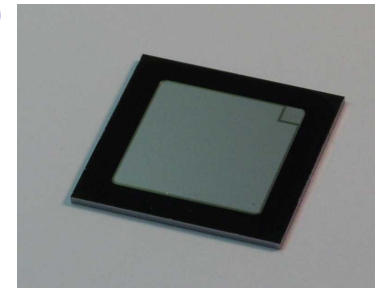


Planar technology

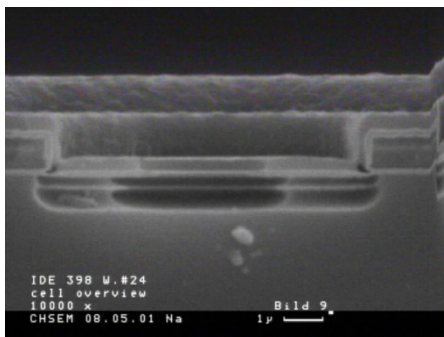


Conventional technology

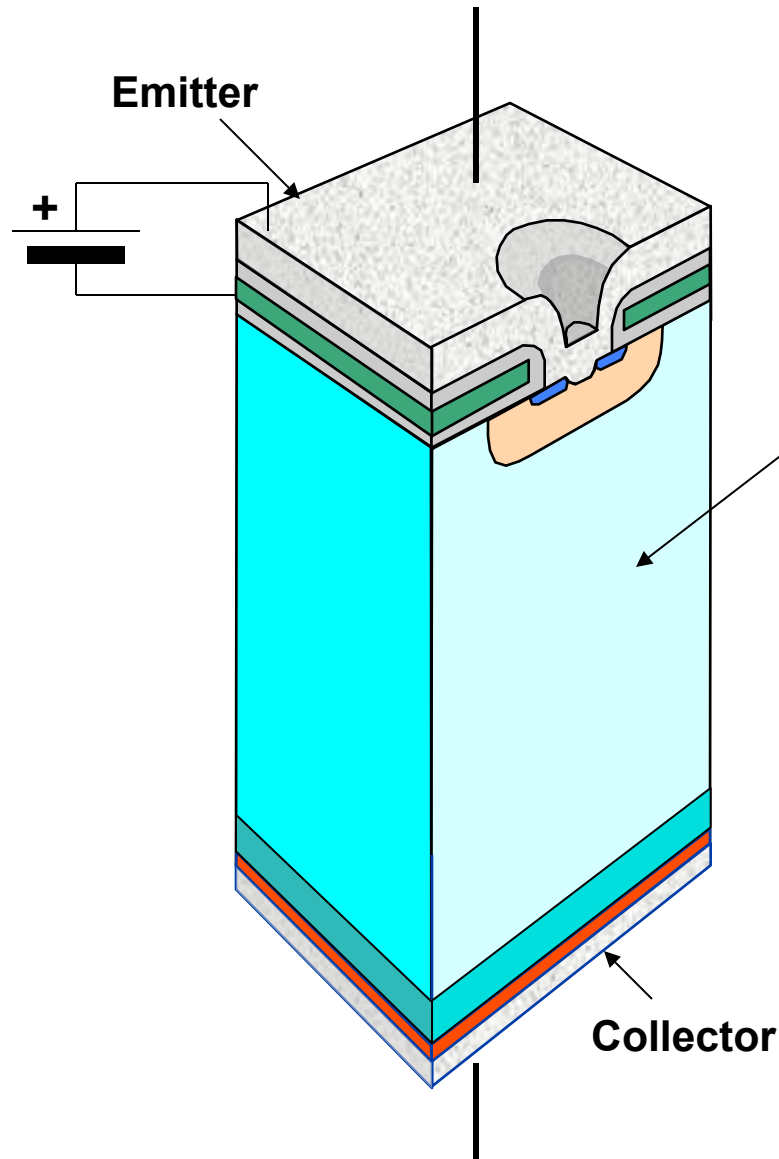
The Insulated Gate Bipolar Transistor (IGBT)



IGBT cell
approx. 100'000 per cm^2

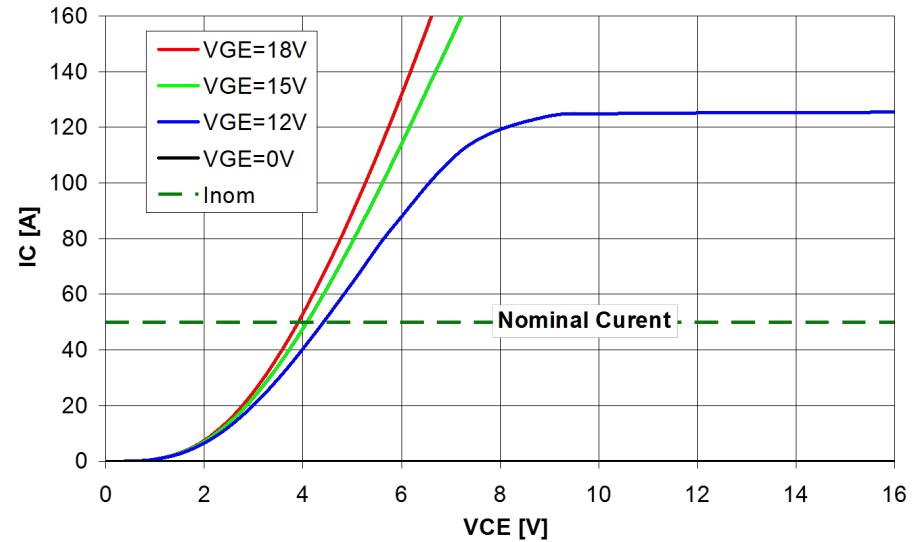
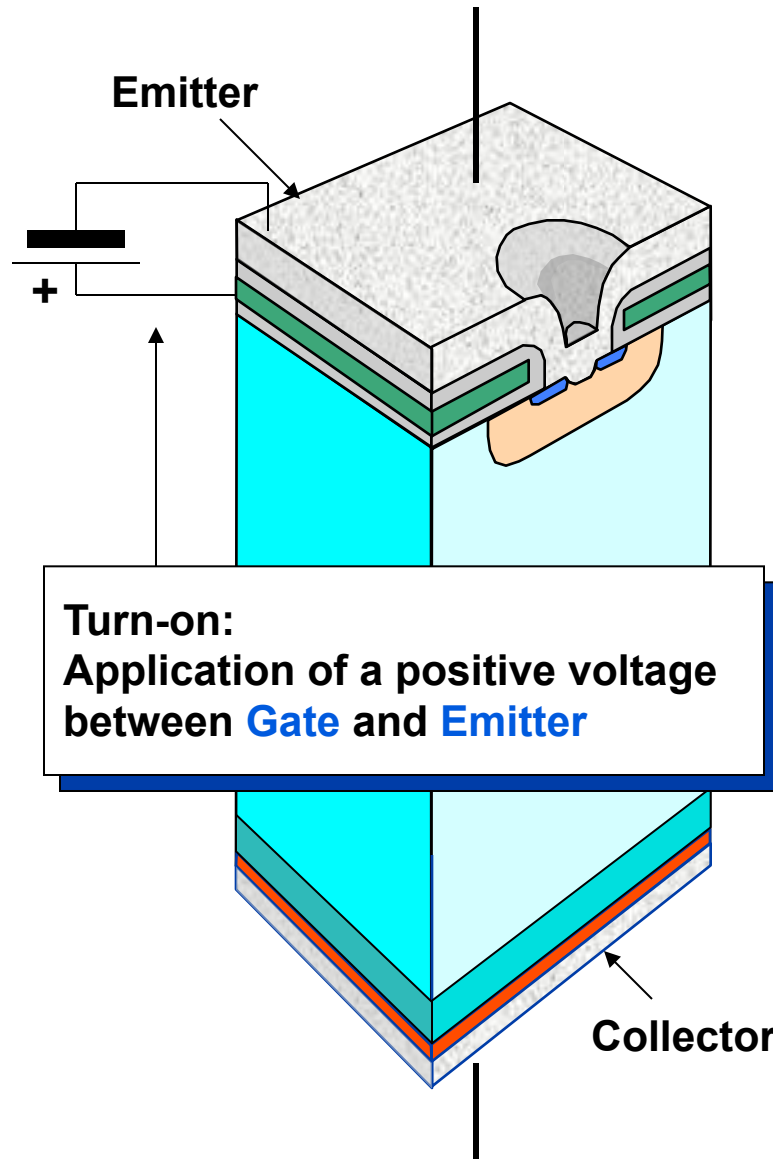


How an IGBT Conducts (1/5)



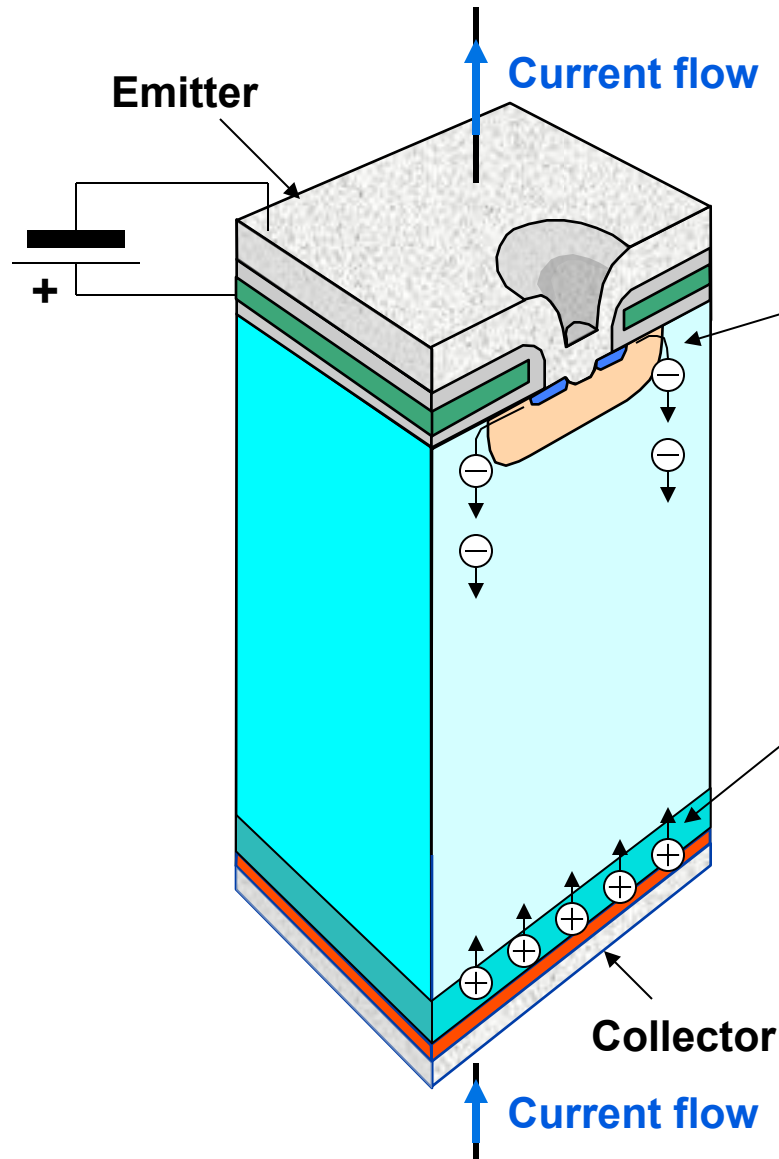
Switch „**OFF**“: No mobile carriers (electrons or holes) in substrate.
No current flow.

How an IGBT Conducts (2/5)



3.3kV IGBT output IV curves

How an IGBT Conducts (3/5)

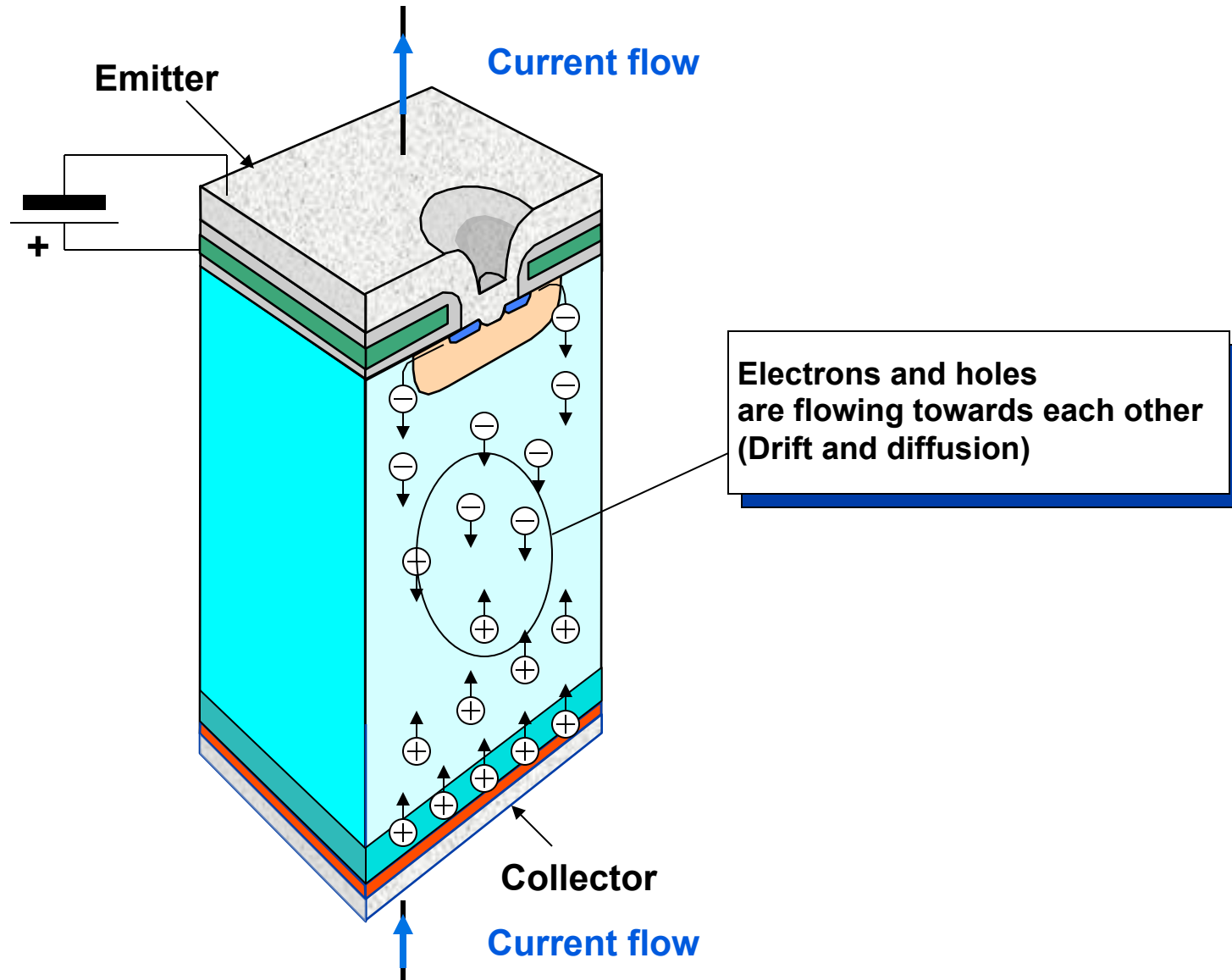


The emitter supplies electrons through the lock into the substrate.

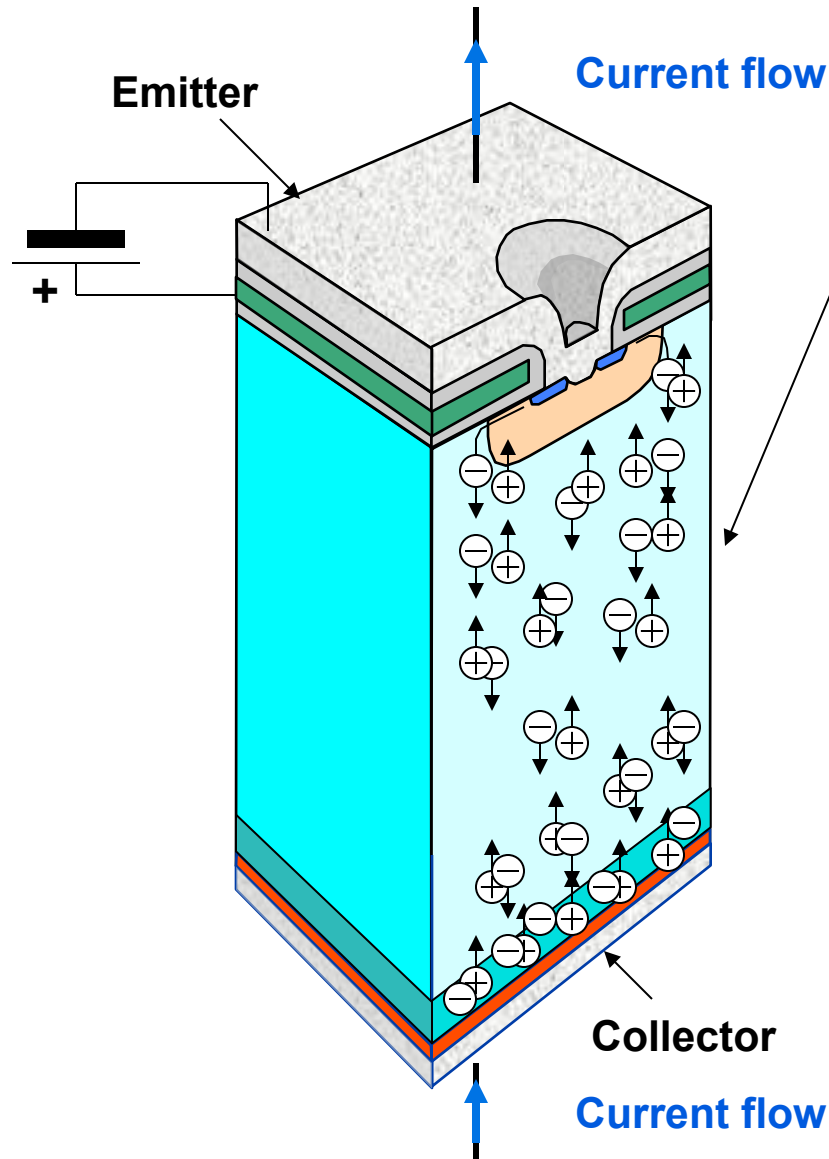
The anode reacts by supplying holes into the substrate

A MOSFET has only N+ region, so no holes are supplied and the device operates in Unipolar mode

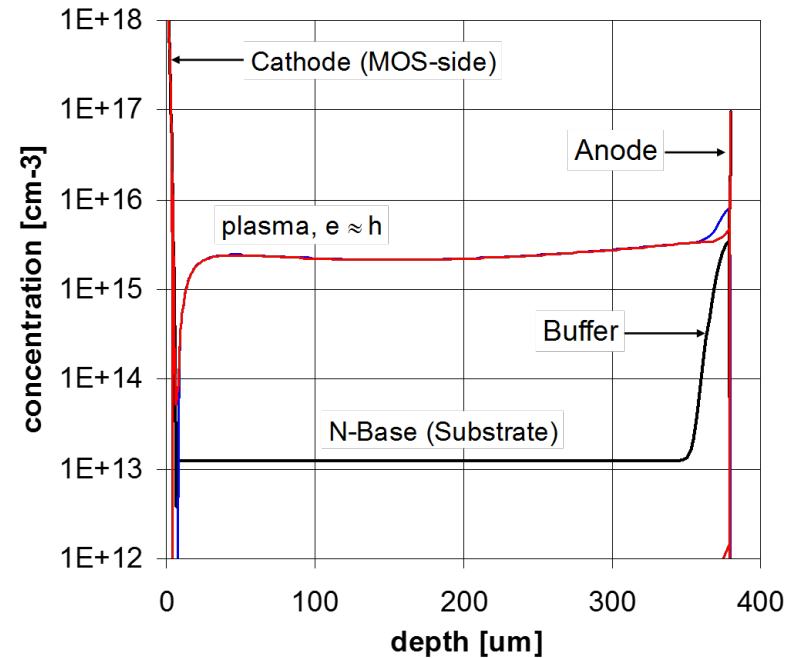
How an IGBT Conducts (4/5)



How an IGBT Conducts (5/5)

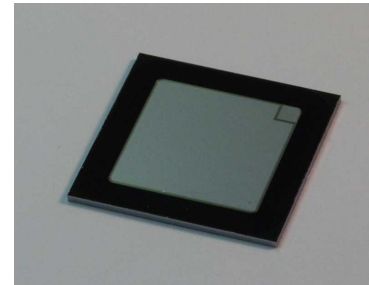
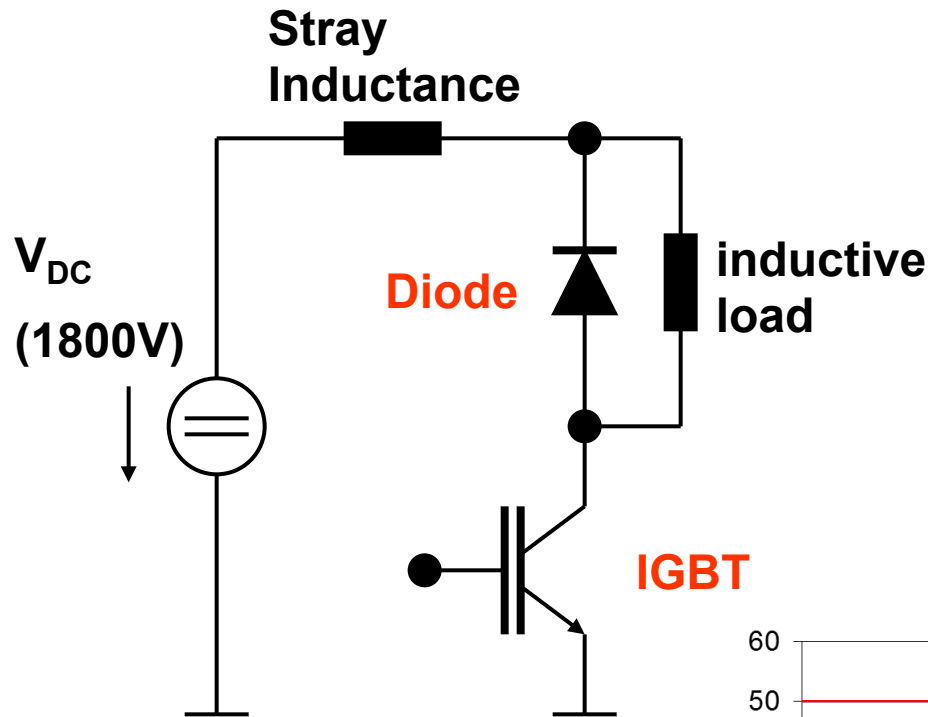


Electrons and holes are mixing to constitute a quasi-neutral plasma. With plenty of mobile carriers, current can flow freely and the device is conducting (switch on)

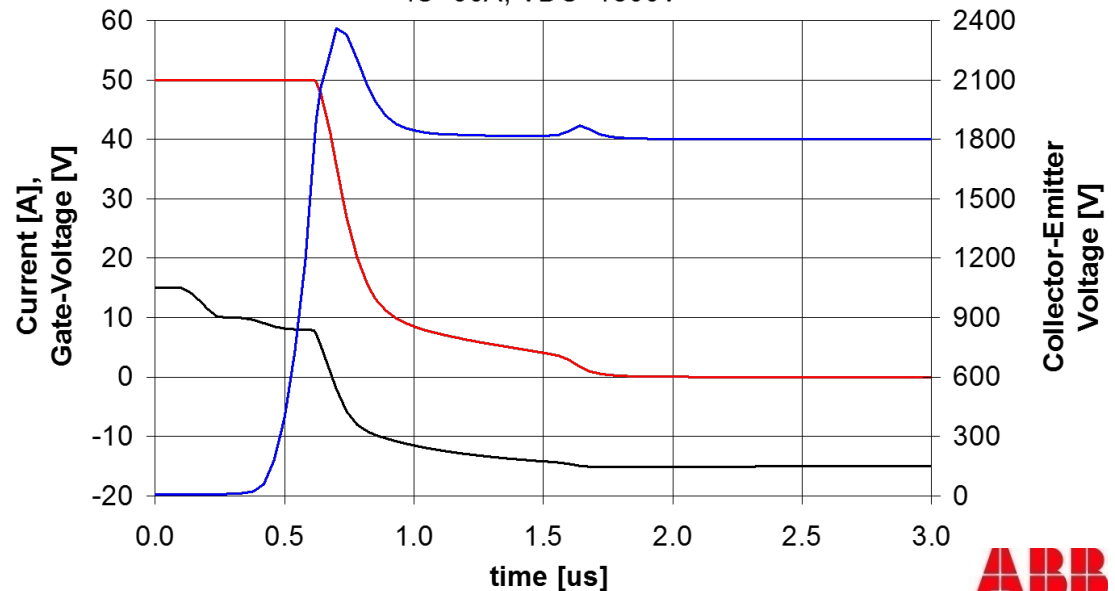


3.3kV IGBT doping/plasma

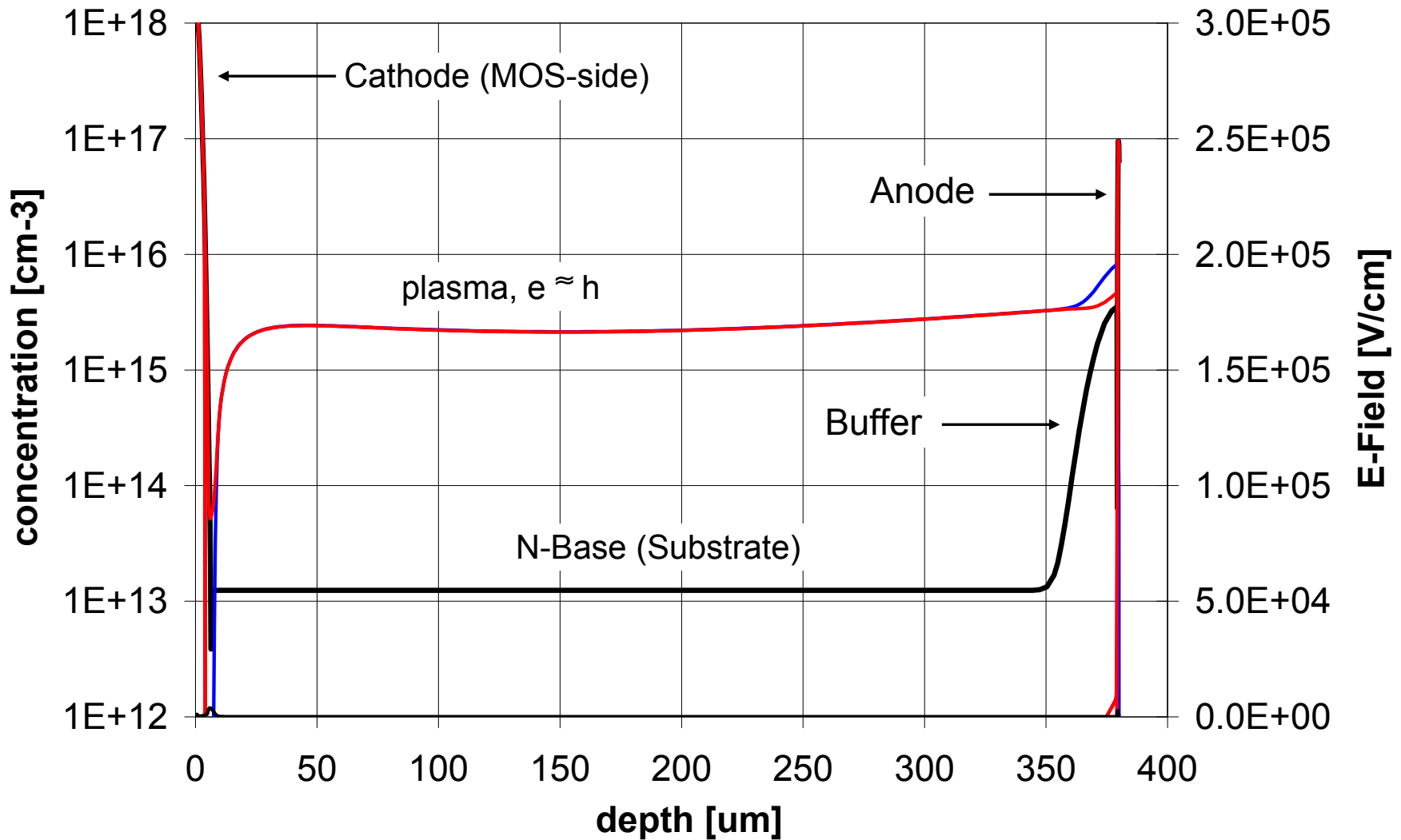
3.3kV IGBT Switching Performance: Test Circuit



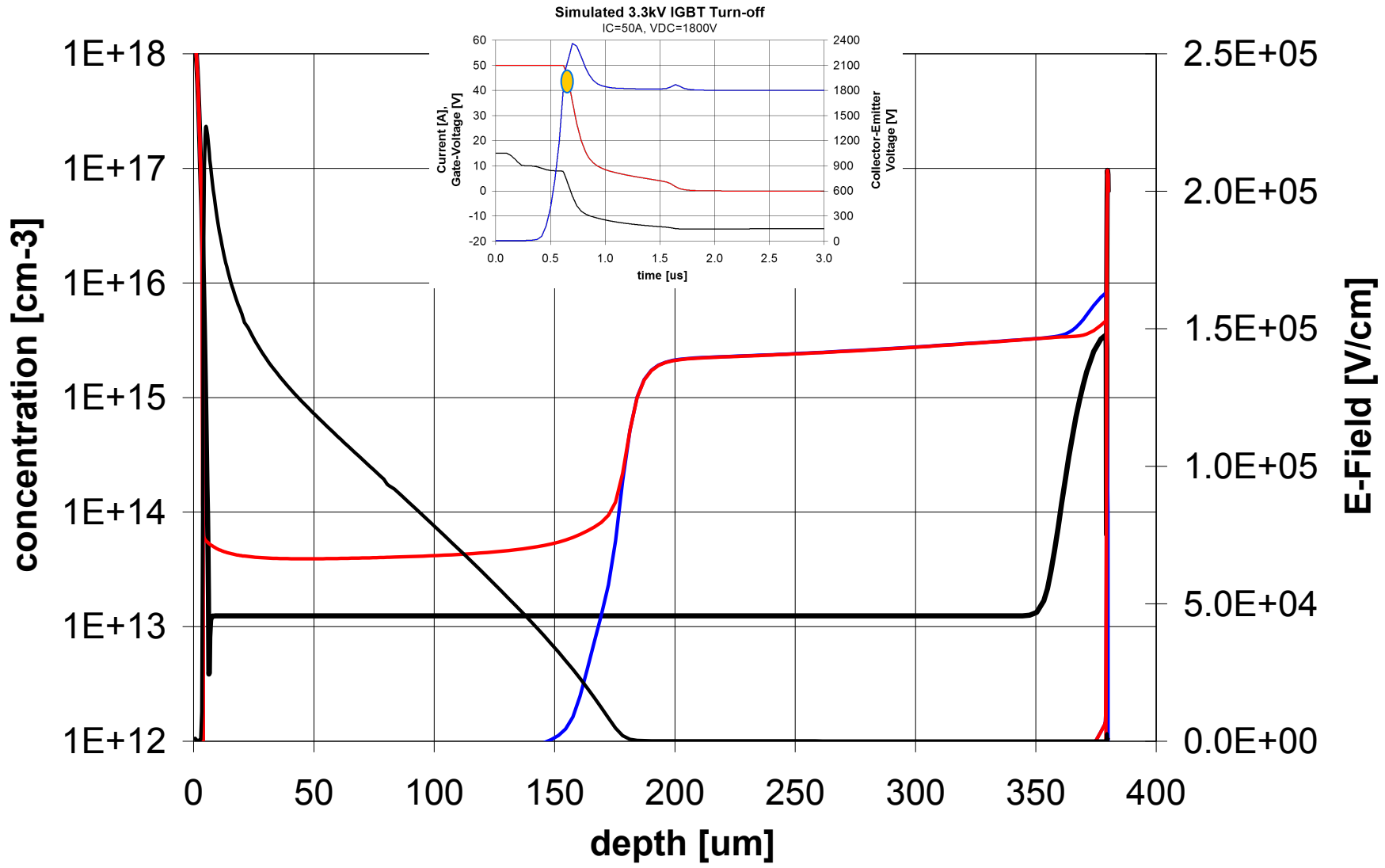
Simulated 3.3kV IGBT Turn-off
 $I_C=50A$, $V_{DC}=1800V$



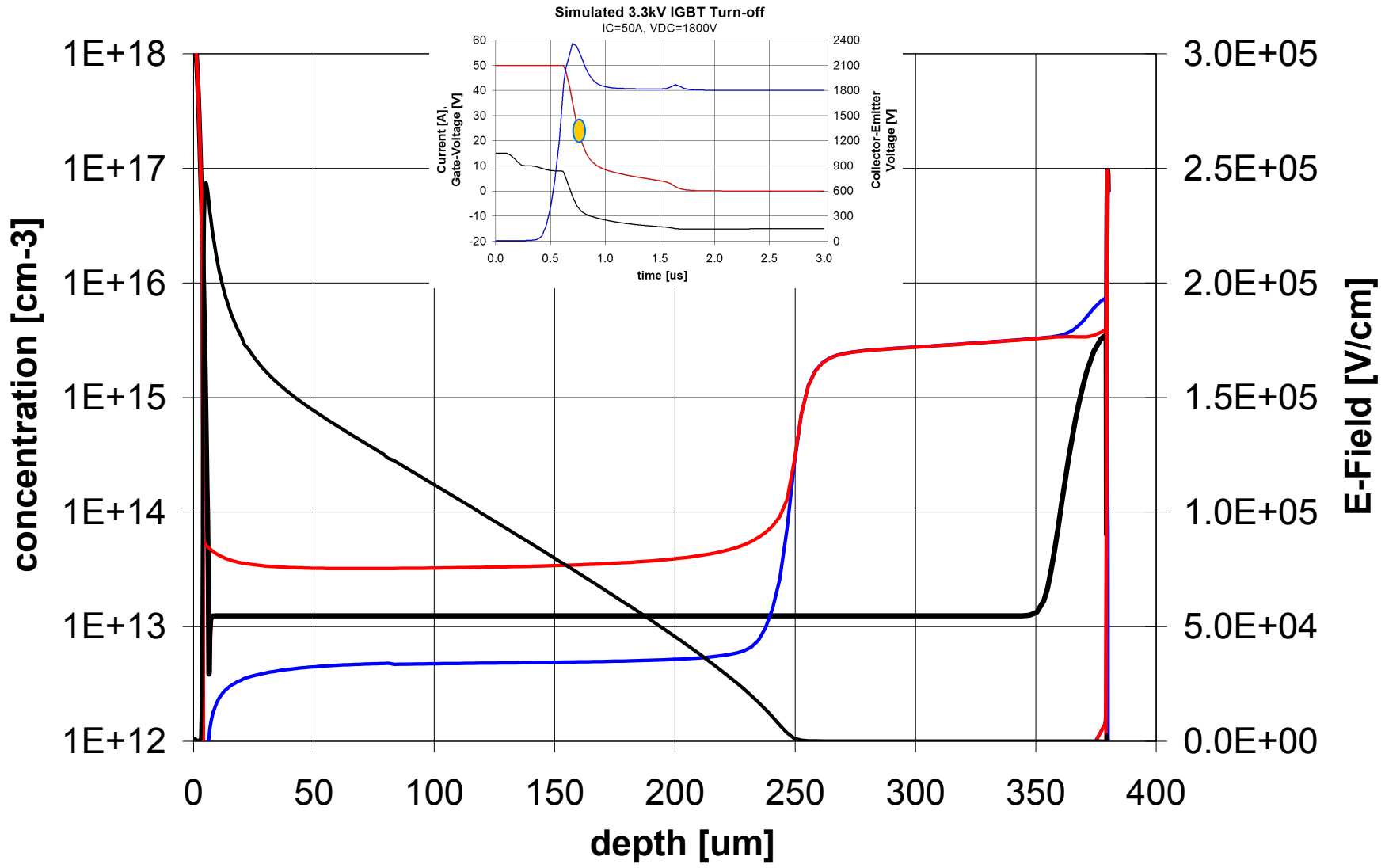
Plasma extraction during turn-off (1/5)



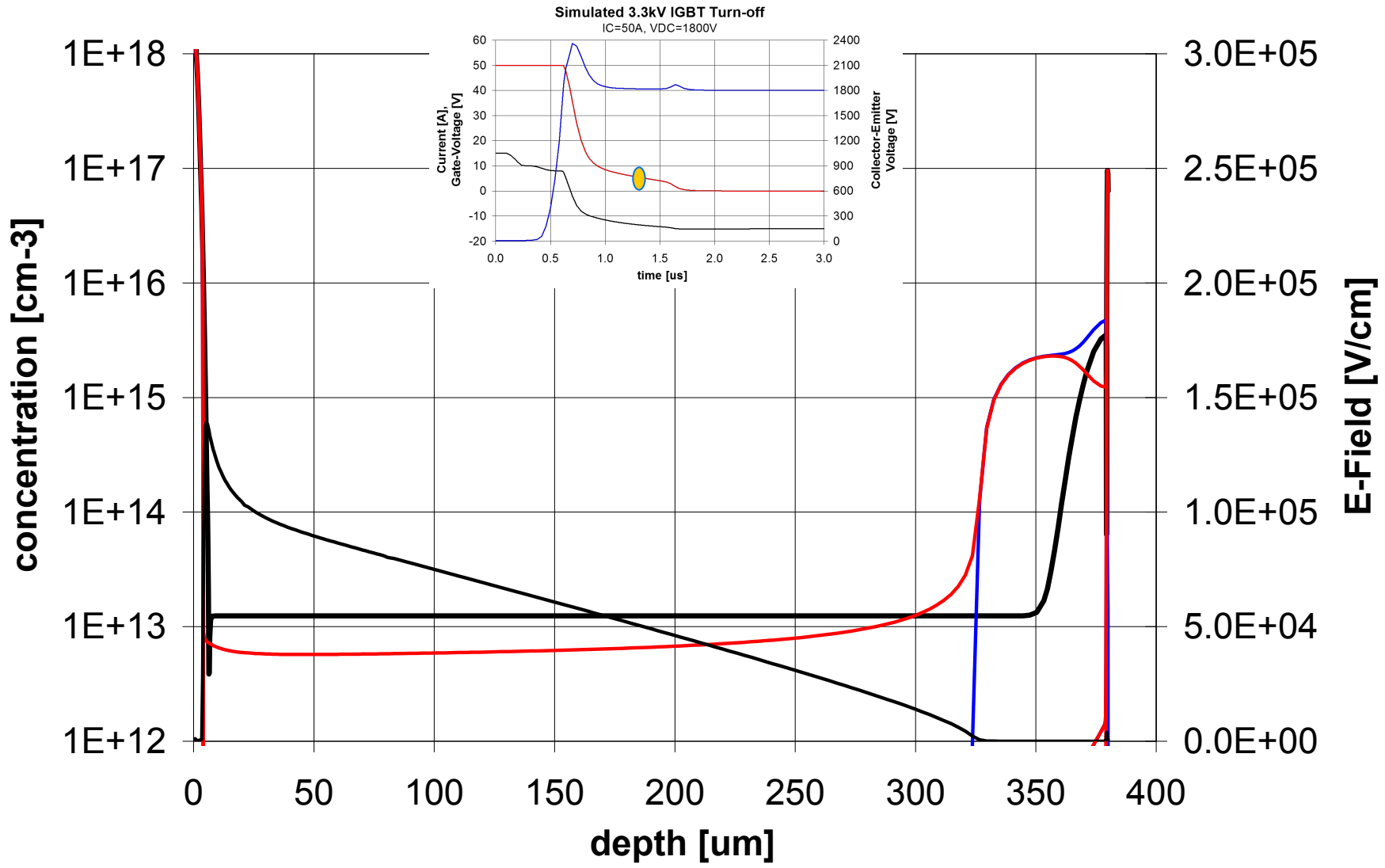
Plasma extraction during turn-off (2/5)



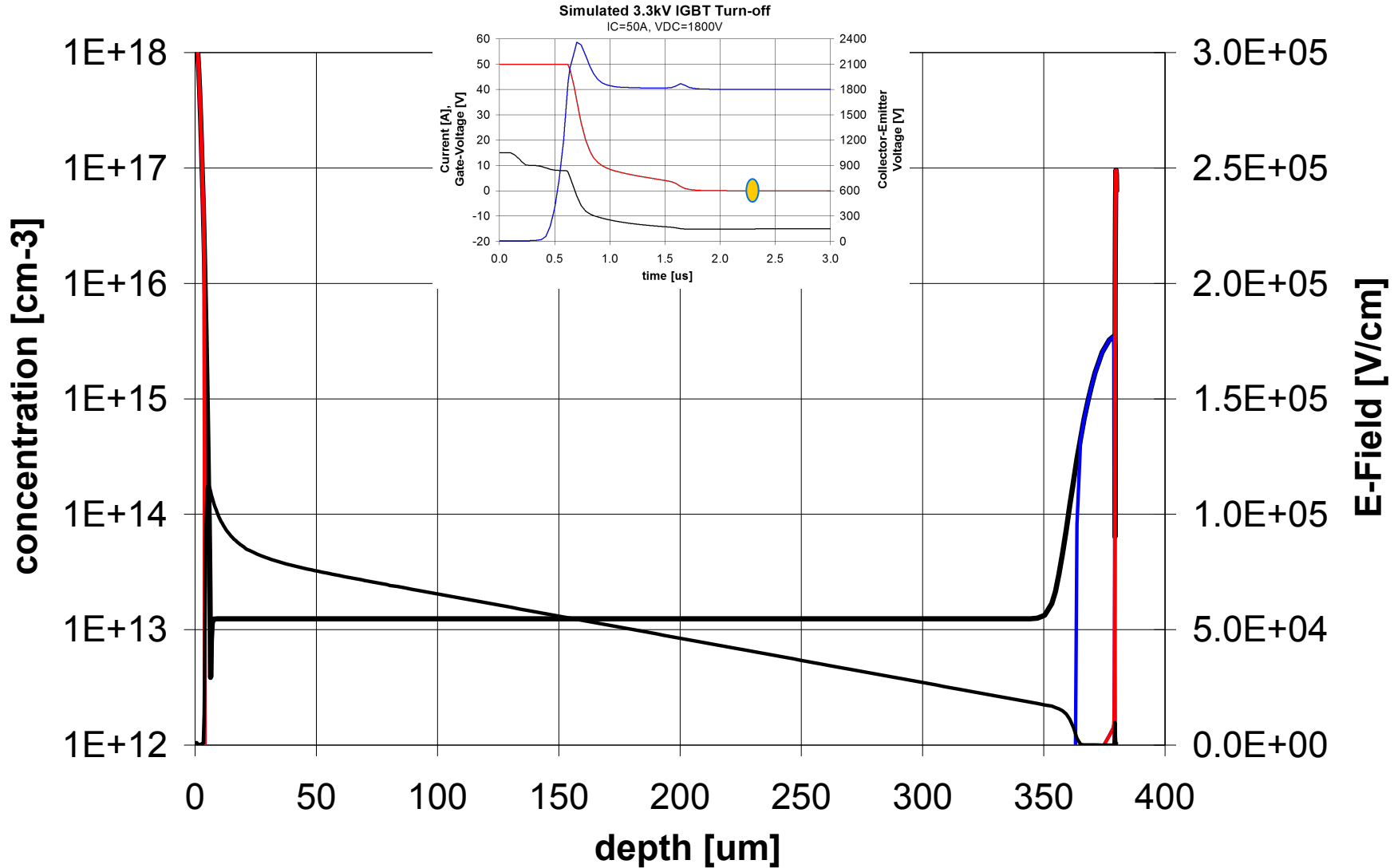
Plasma extraction during turn-off (3/5)



Plasma extraction during turn-off (4/5)

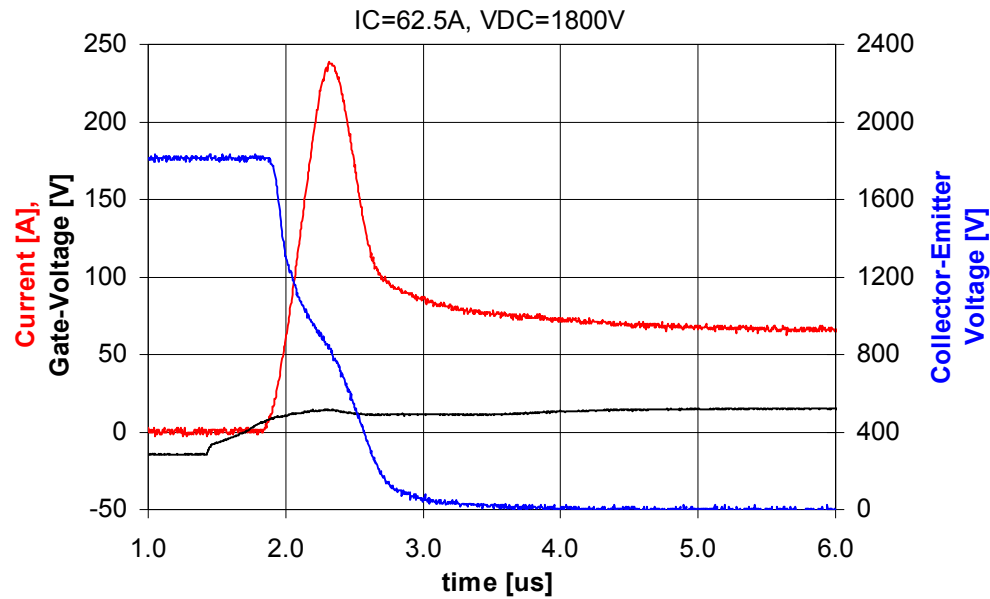


Plasma extraction during turn-off (5/5)

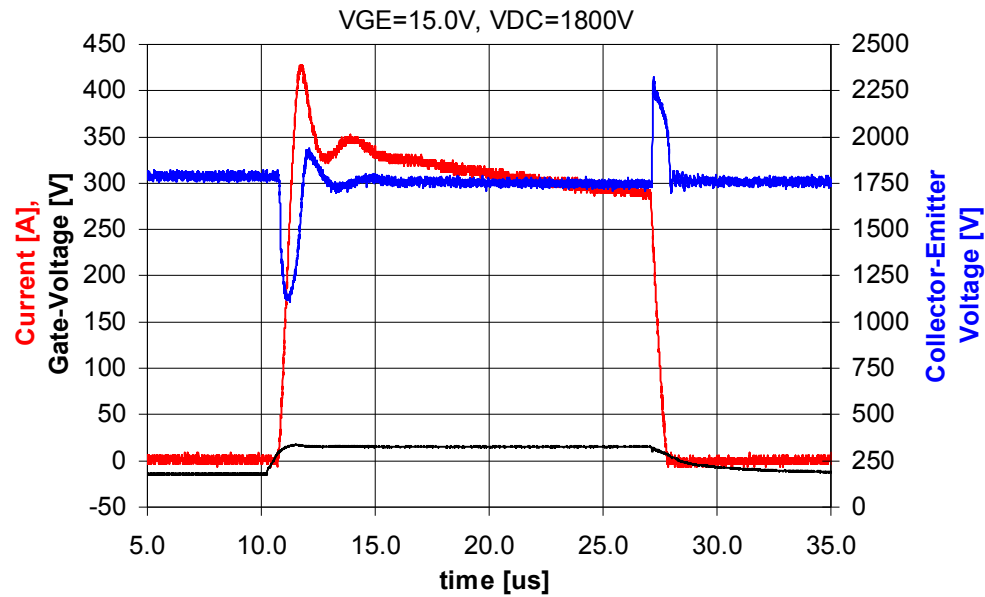


3.3kV IGBT Turn-on and Short Circuit Waveforms

Turn-on
waveforms

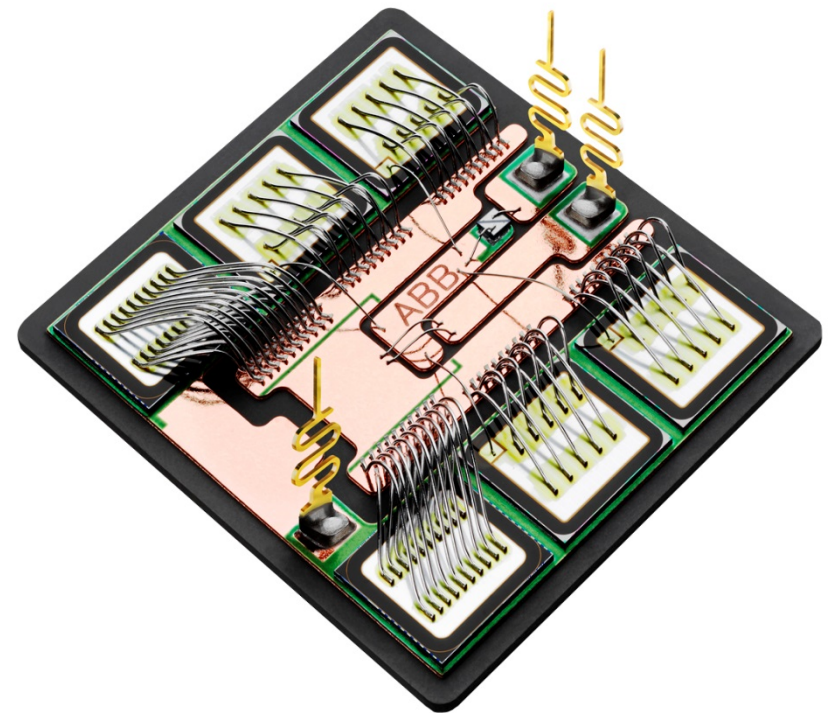


Short
Circuit



Power Semiconductors

Packaging Concepts



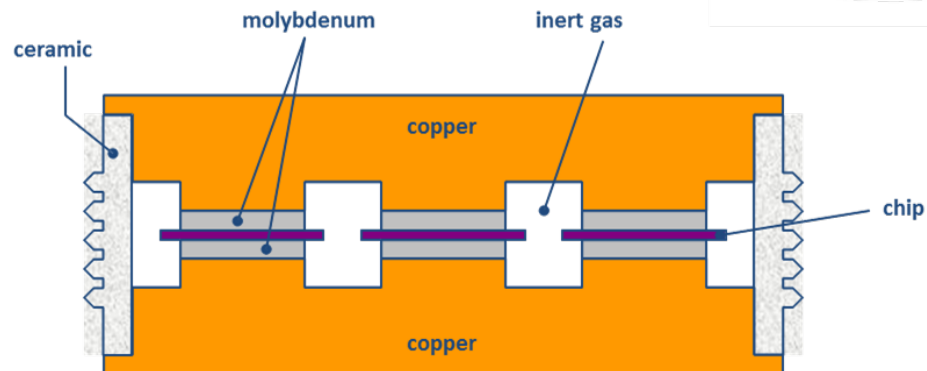
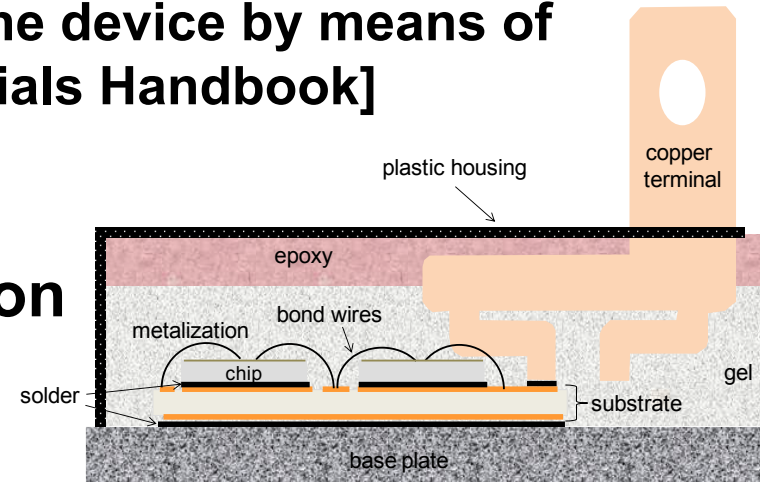
Power Semiconductor Device Packaging

- **What is Packaging ?**

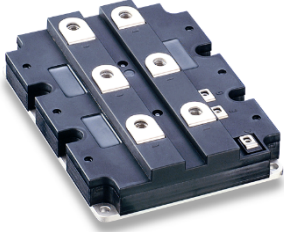

- A package is an enclosure for a single element, an integrated circuit or a hybrid circuit. It provides hermetic or non-hermetic protection, determines the form factor, and serves as the ***first level interconnection externally*** for the device by means of package terminals. [Electronic Materials Handbook]

- **Package functions in PE**

- Power and Signal distribution
- Heat dissipation
- HV insulation
- Protection



Power Semiconductor Device Packaging Concepts

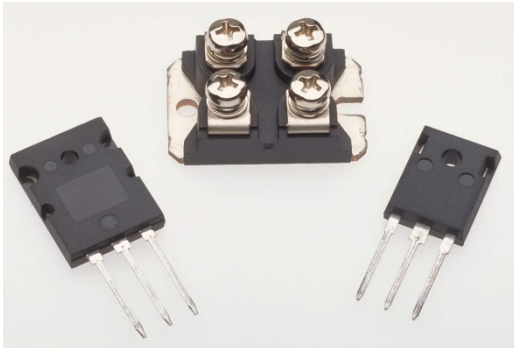
	“Insulated” Devices 	Press-Pack Devices 
Mounting	heat sink galvanically insulated from power terminals <ul style="list-style-type: none"> ■ all devices of a system can be mounted on same heat sink 	heat sinks under high voltage <ul style="list-style-type: none"> ■ every device needs its own heat sink
Failure Mode	open circuit after failure	fails into low impedance state
Markets	Industry Transportation T&D	Industry Transportation T&D
Power range	typically 100 kW - low MW	MW

transportation components have higher reliability demands

Insulated Package for 10s to 100s of KW

Low to Medium Power Semiconductor Packages

Discrete Devices

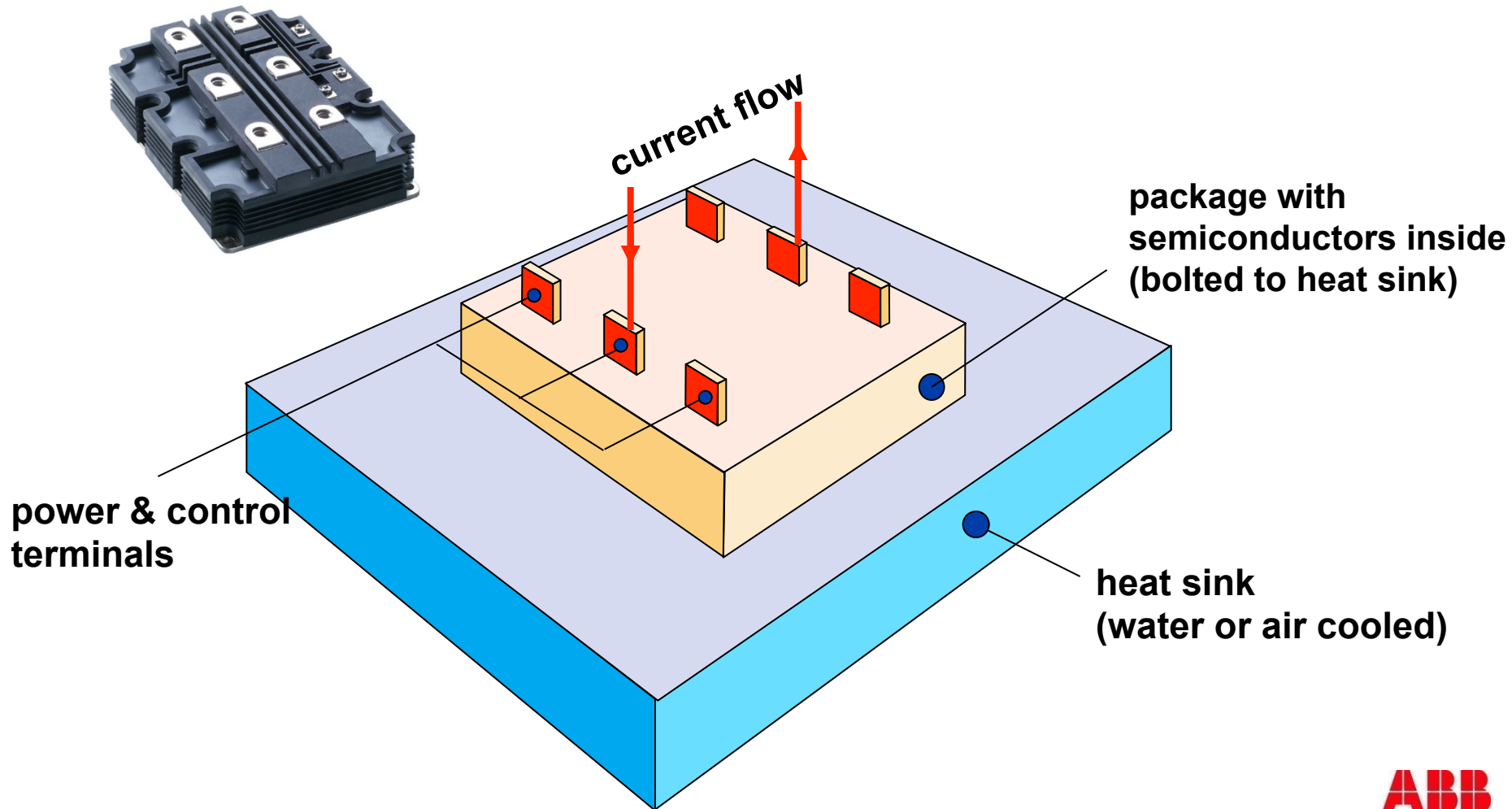


Standard Modules



Insulated Modules

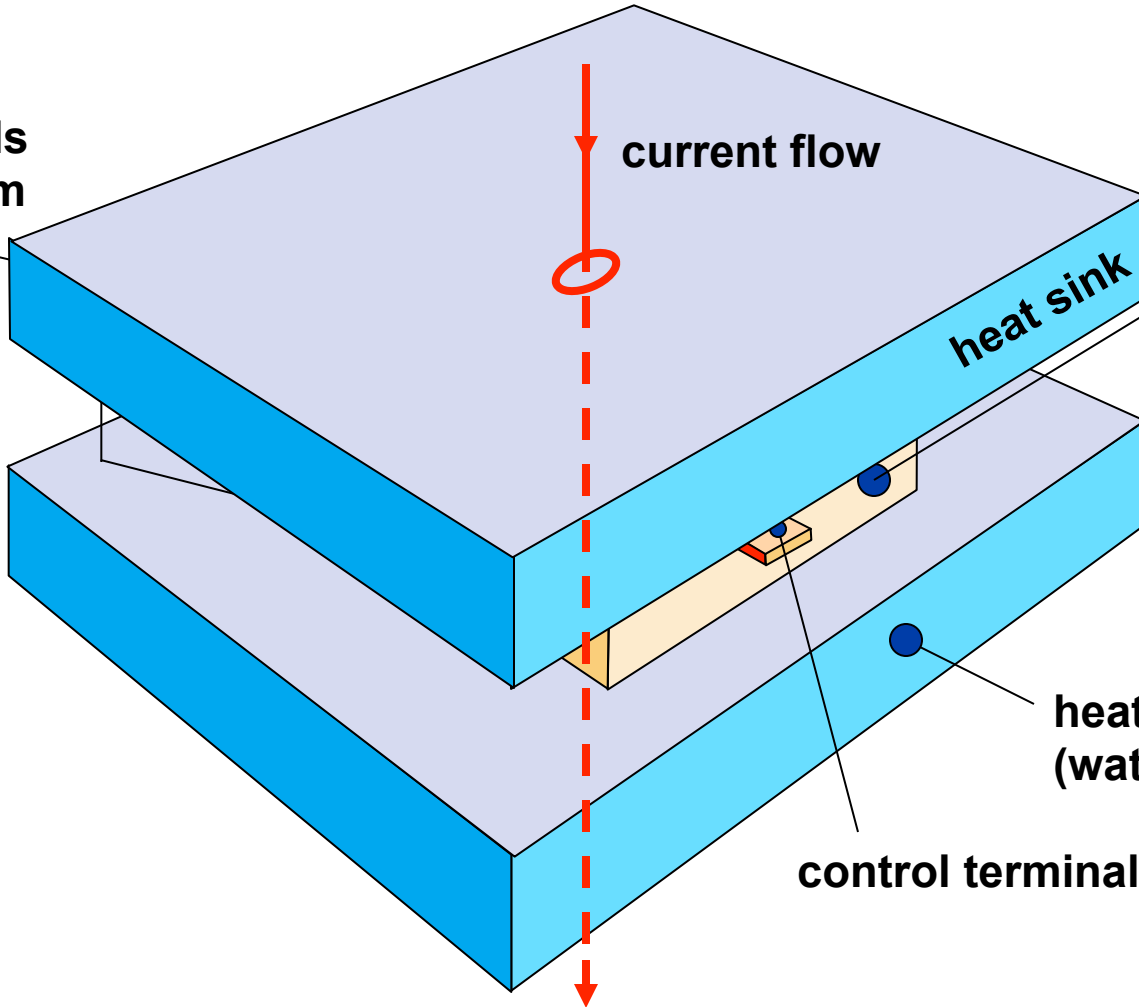
- Used for industrial and transportation applications (typ. 100 kW - 3 MW)
- Insulated packages are suited for Multi Chip packaging IGBTs



Press-Pack Modules



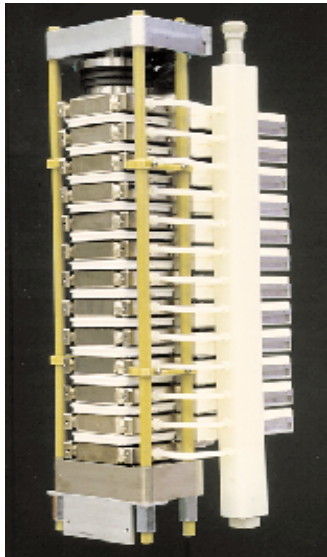
power terminals
(top and bottom
of module)



package with
semiconductors
inside

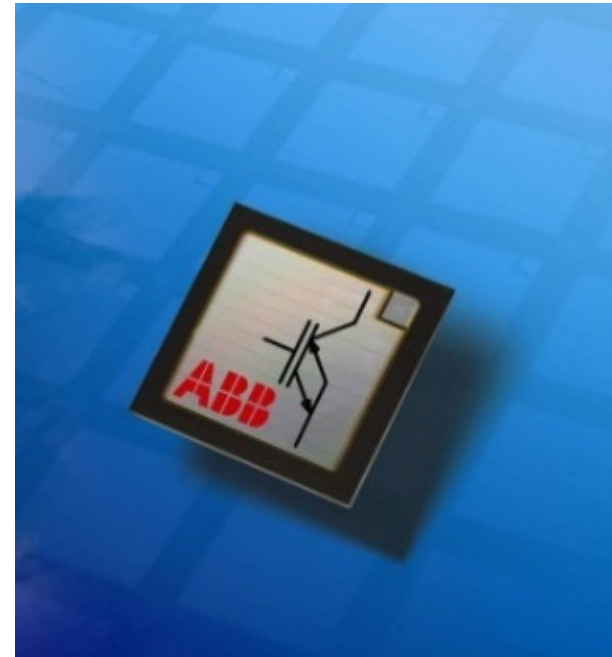
heat sink
(water or air cooled)

control terminal



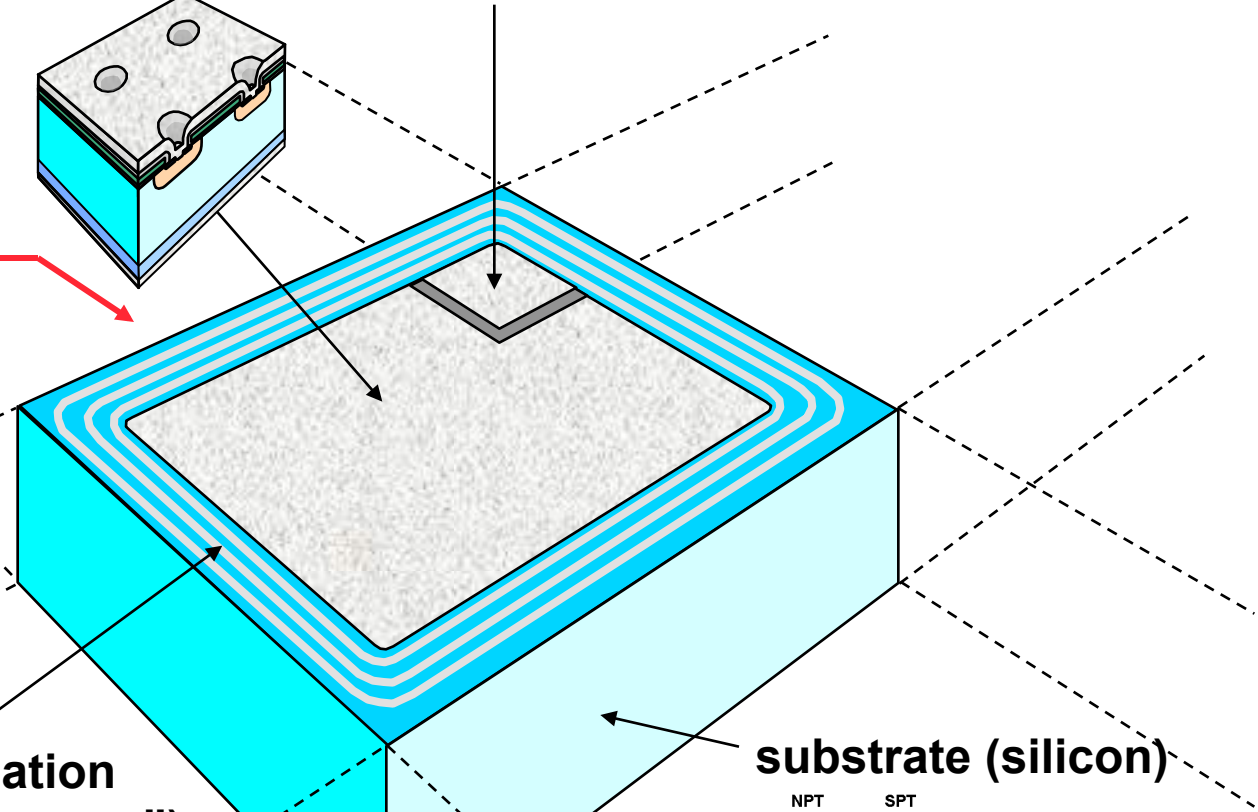
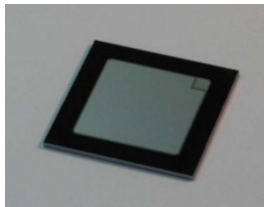
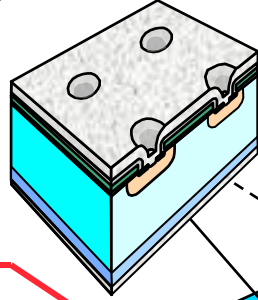
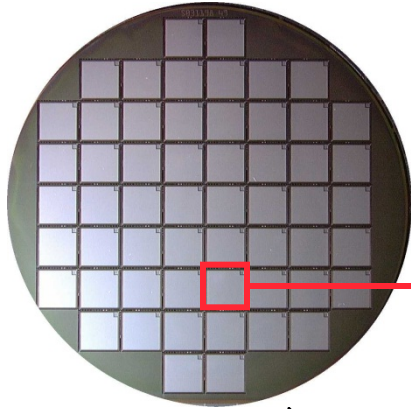
Power Semiconductors

Technology Drivers and Trends

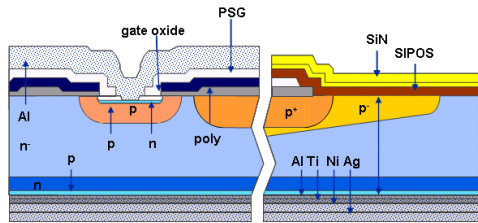


Power Semiconductor Device Technology Platforms

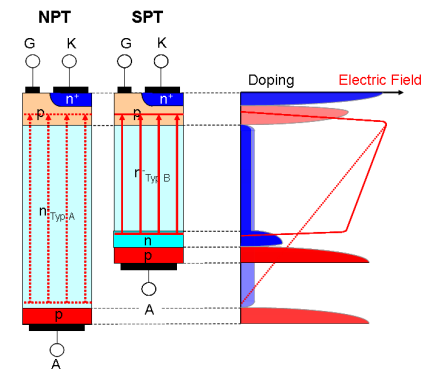
active area
(main electrode) gate pad (control electrode)



junction termination
("isolation of active area")



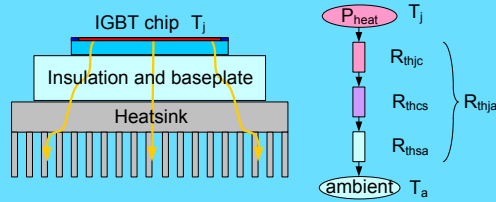
substrate (silicon)



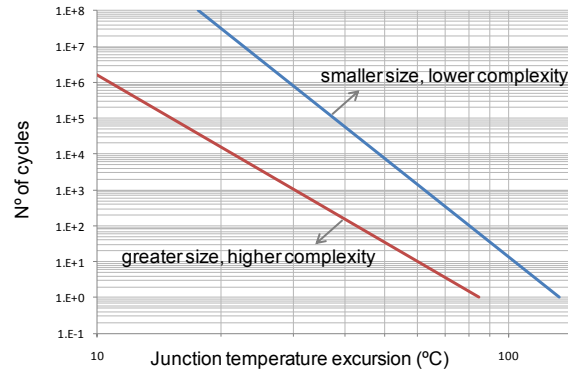
Power Semiconductor Package Technology Platforms

Heat dissipation

- Interconnections
- Advanced cooling concepts



Typical temperature cycling curve



Electrical distribution

- Interconnections
- Power / Signal terminals
- Low electrical parasitics



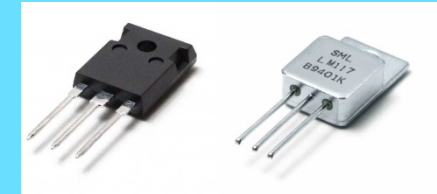
High Voltage Insulation

- Partial Discharges
- HV insulating
- Creepage distances

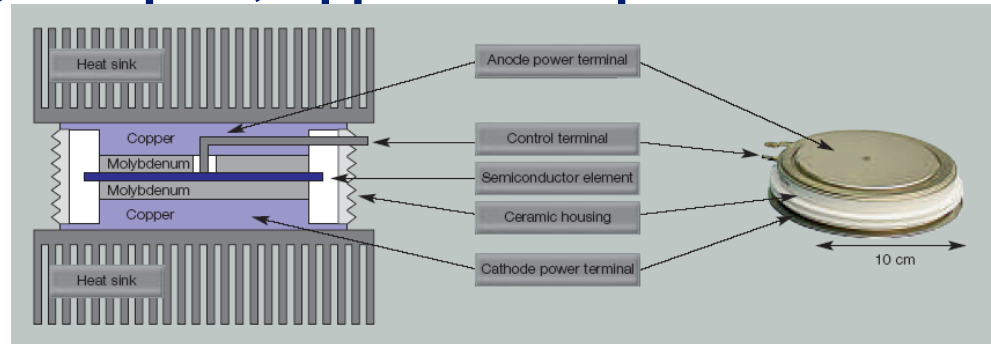
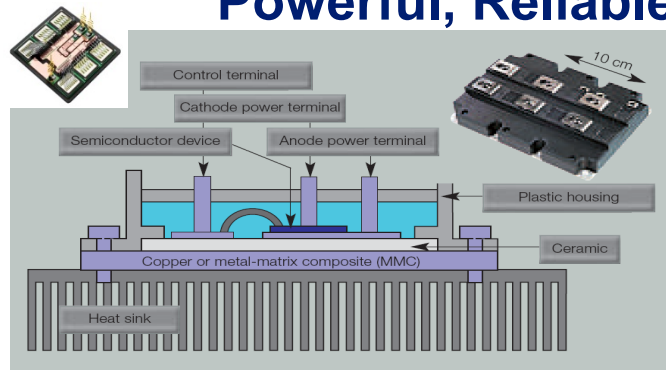


Encapsulation/ protection

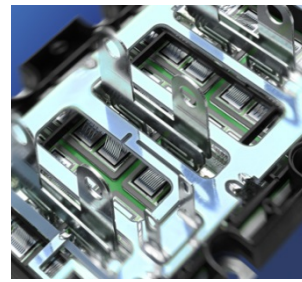
- Hermetic / non-hermetic
- Coating / filling materials



Powerful, Reliable, Compact, Application specific



Overcoming the Limitations (the boundaries)



The Power

$$\text{Power} = V_{\text{on}} \left[I_{\text{c}} \text{ or } \frac{V_{\text{on}}}{R_{\text{on}}} \right] = \frac{T_{\text{j,max}} - T_{\text{j,amb}}}{R_{\text{th}}}$$

The Margins

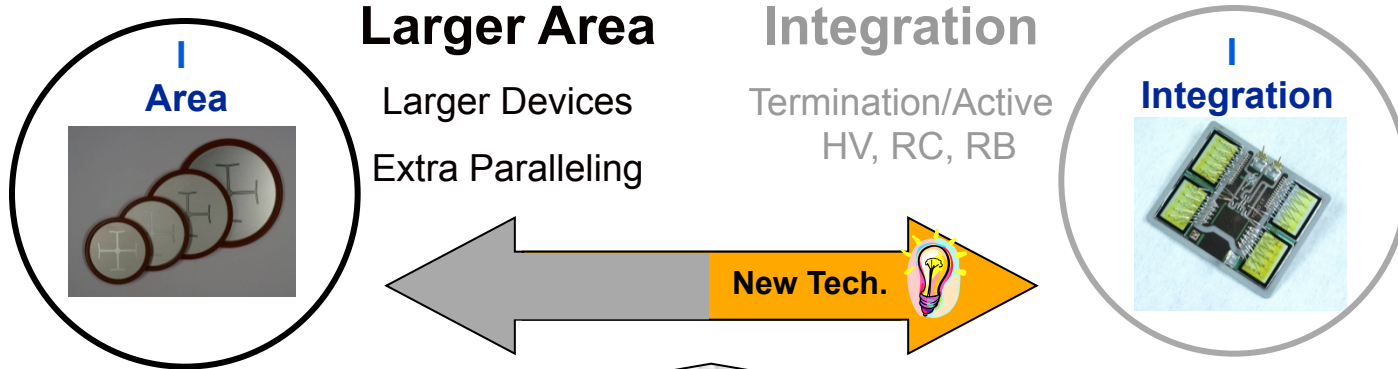
$$P_{\text{max}} = V_{\text{max}} \cdot I_{\text{max}}, \text{ Controllability, Reliability}$$

The Application

Topology, Frequency, Control, Cooling

The Cost of Performance

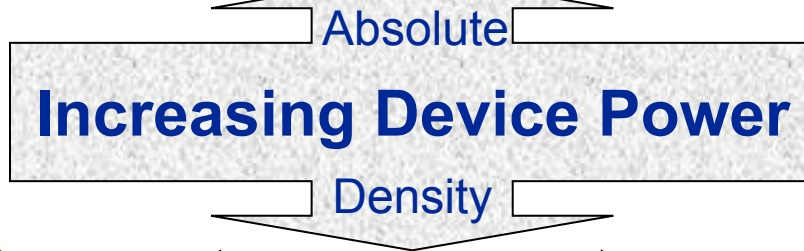
Technology Drivers for Higher Power (the boundaries)



Reduced Losses

Carrier Enhancement

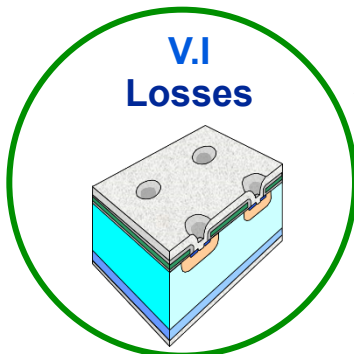
Thickness Reduction (Blocking)



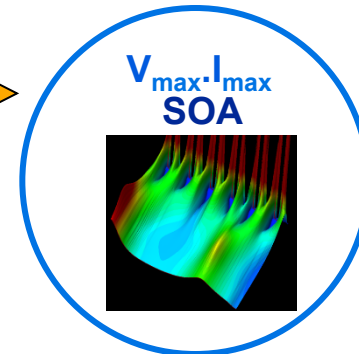
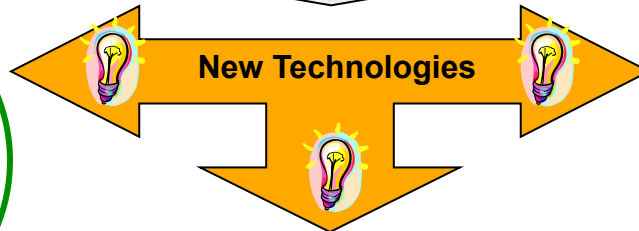
Increased Margins

Latch-up / Filament Protection

Controllability, Softness & Scale



Traditional Focus



$\Delta T/R_{th}$ Temperature



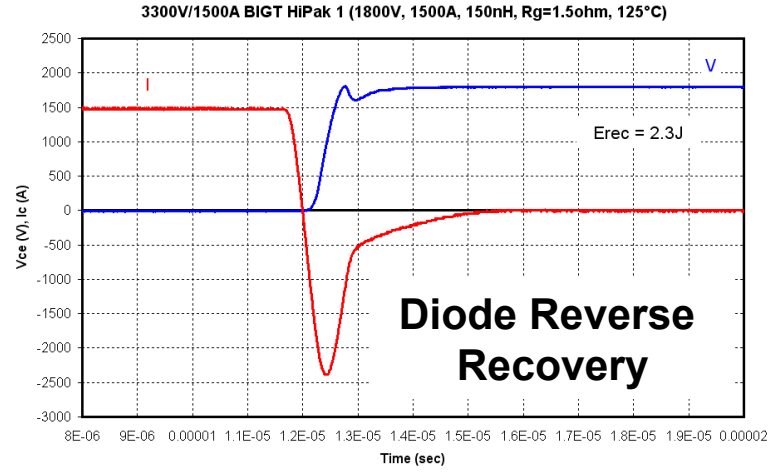
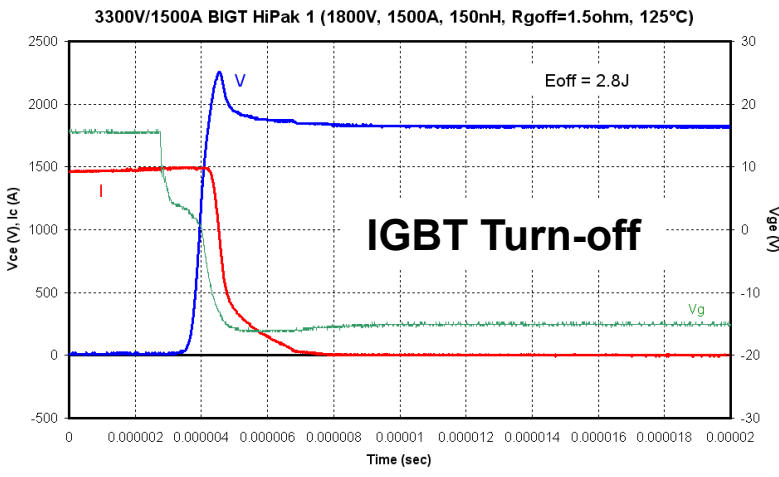
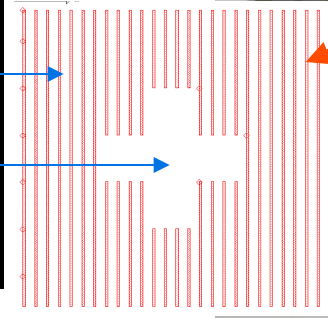
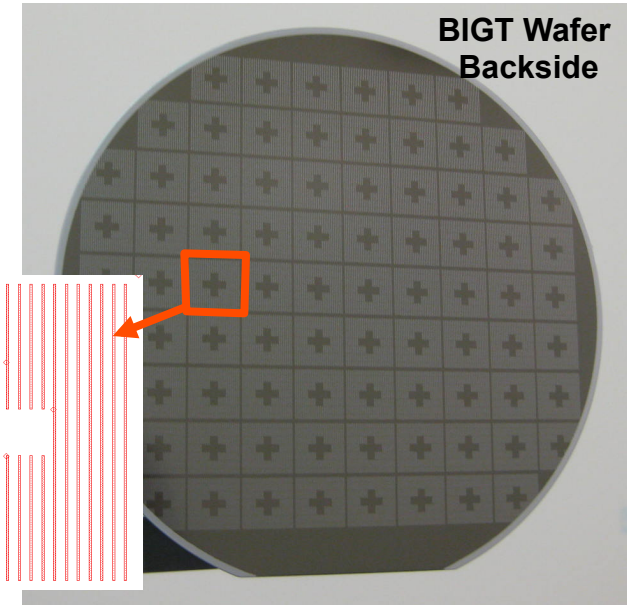
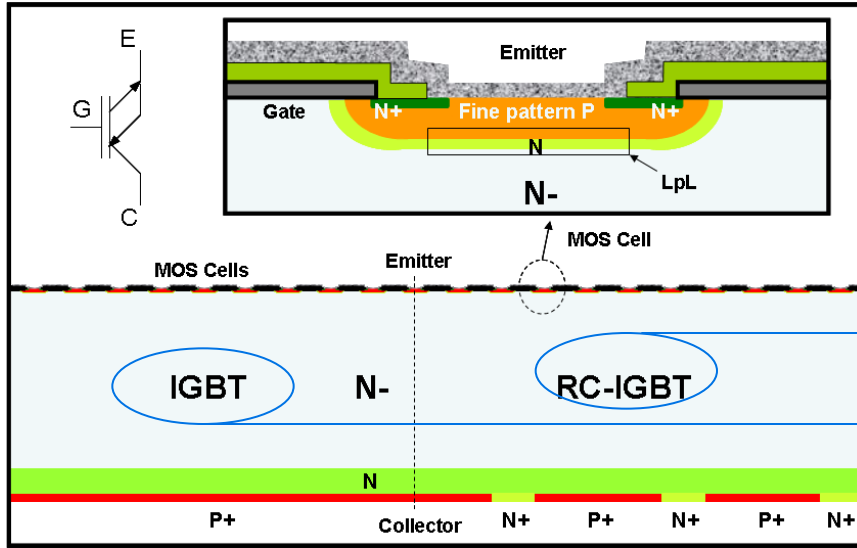
Improved Thermal

High Temp. Operation

Lower Package R_{th}

The Bimode Insulated Gate Transistor (BIGT)

integrates an IGBT & RC-IGBT in one structure to eliminate snap-back effect



Wide Bandgap Technologies

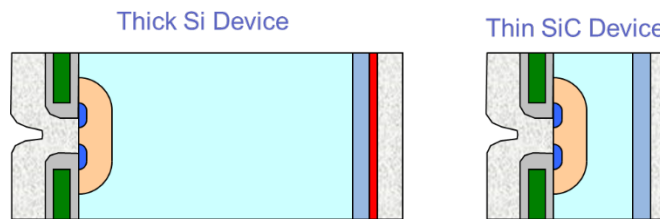
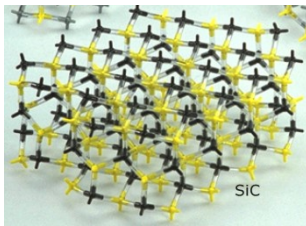


Wide Bandgap Semiconductors: Long Term Potentials

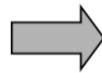
Parameter		Silicon	4H-SiC	GaN	Diamond
Band-gap E_g	eV	1.12	3.26	3.39	5.47
Critical Field E_{crit}	MV/cm	0.23	2.2	3.3	5.6
Permittivity ϵ_r	–	11.8	9.7	9.0	5.7
Electron Mobility μ_n	$cm^2/V\cdot s$	1400	950	800/1700*	1800
BFoM: $\epsilon_r \cdot \mu_n \cdot E_{crit}^3$	rel. to Si	1	500	1300/2700*	9000
Intrinsic Conc. n_i	cm^{-3}	$1.4 \cdot 10^{10}$	$8.2 \cdot 10^{-9}$	$1.9 \cdot 10^{-10}$	$1 \cdot 10^{-22}$
Thermal Cond. λ	W/cm·K	1.5	3.8	1.3/3**	20

* significant difference between bulk and 2DEG

** difference between epi and bulk

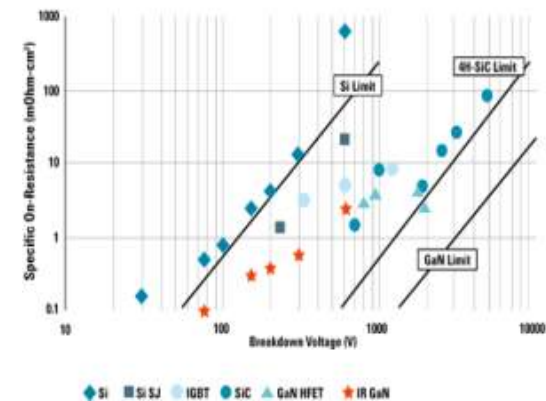


- Higher Blocking
- Lower Losses
- Lower Leakage
- **But higher built-in voltage**

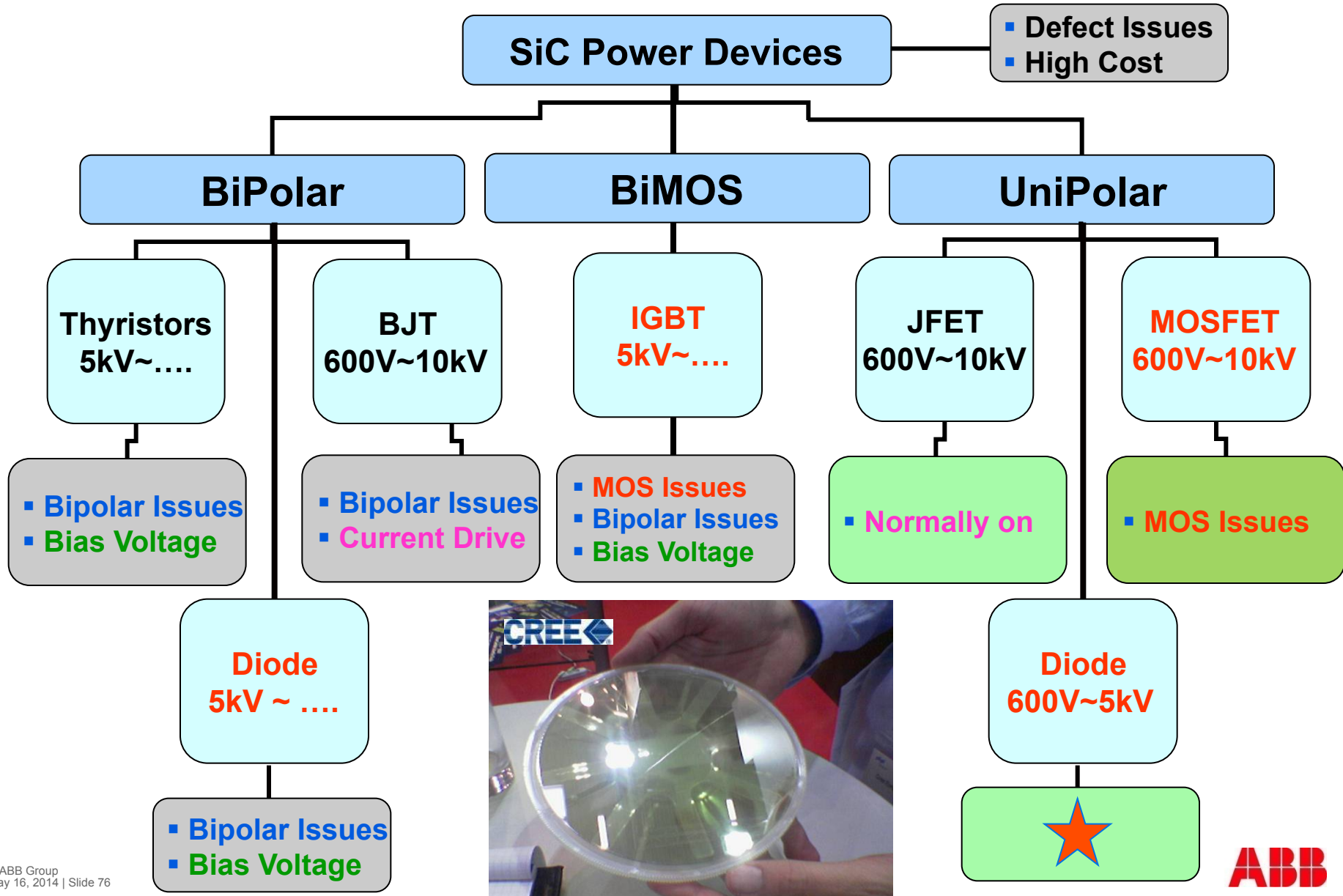


- Higher Power
- Wider Frequency Range
- Very High Voltages
- Higher Temperature

Comparison of R_{on} for Si, SiC, and GaN based FETs



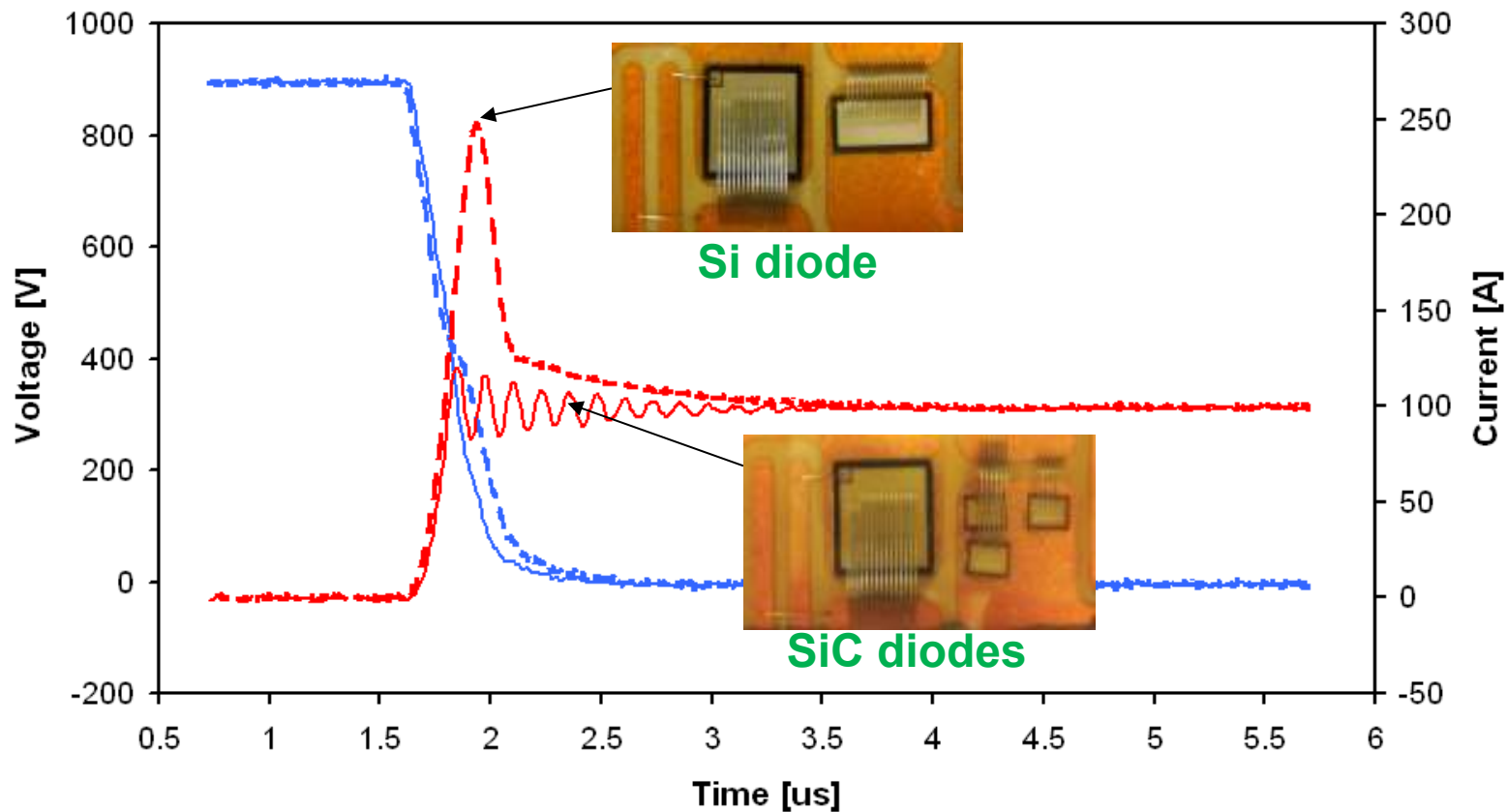
SiC Switch/Diode Classification and Issues



SiC Unipolar Diodes vs. Si Bipolar Diode

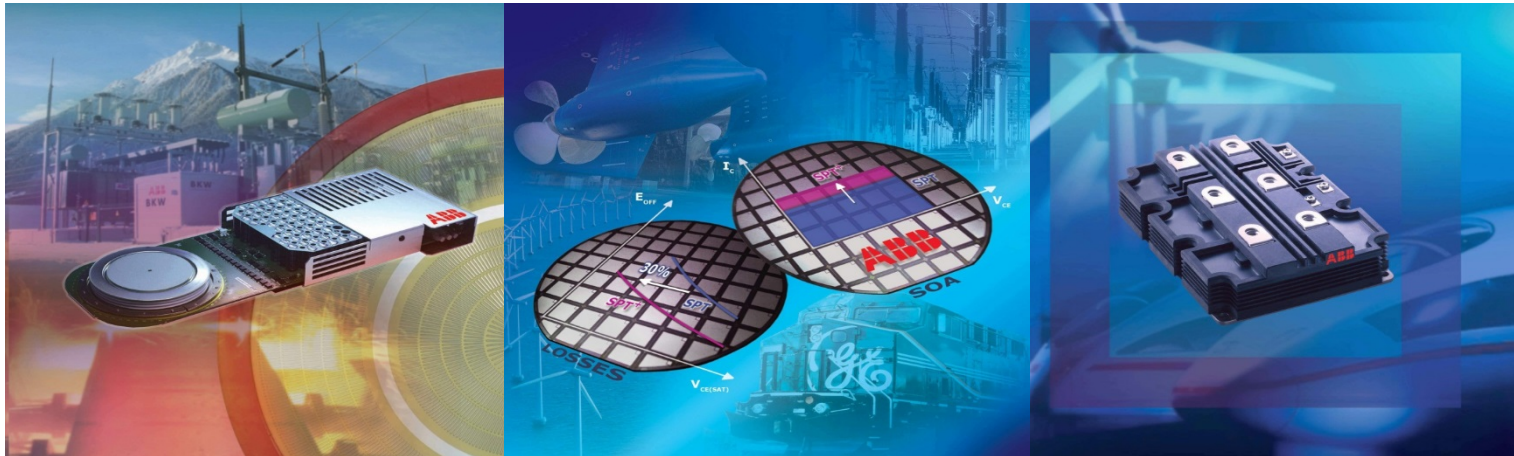
1700V Fast IGBTs with SiC Diodes during turn-on

Turn-On Fast IGBT + Si & SiC Diodes, 900V/100A, 175°C, Ls=400nH Rg=100hm



Conclusions

- **Si Based Power semiconductors** are a key enabler for modern and future power electronics systems including grid systems
- **High power semiconductor devices and new system topologies** are continuously improving for achieving higher power, improved efficiency and reliability and better controllability
- **The Diode, PCT, IGCT, IGBT and MOSFET** continue to evolve for achieving future system targets with the potential for improved power/performance through further losses reductions, higher operating temperatures and integration solutions
- **Wide Band Gap Based Power Devices** offer many performance advantages with strong potential for very high voltage applications



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